

**TOTAL DOSE STEADY-STATE IRRADIATION
Of
0.18 μm G12 process SRAM Test Vehicle
from LSI-Logic**

Test Report

NASA-GSFC, Radiation Effects and Analysis Group (REAG), Code 561

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1 Documentation

1.1 Reference Document

MIL STD 883D, Method 1019.6

Steady State Irradiation Procedure

2 Test Plan

2.1 Tested devices

The LSI-Logic LXA0387 memory test chip is a 512Kbit SRAM organized externally as 64K words of 8 bits. The minimum cycle time is about 50 ns, and the power supply voltage is 1.8V. The memory test chip is packaged in a 64 pin ceramic PGA package.

LSI-Logic provided memory test chips on both bulk and SOI 0.18 μ m processes. Table 2 gives the information on the test samples.

Table 2: Test samples information

Process	Test vehicle	Package	Package Marking	Sample Size
G12 (0.18 μ m)	Bulk	SRAM	FA28 (ceramic PGA 64)	11 SN5to15
	SOI	SRAM	FA28 (ceramic PGA 64)	12 SN4 (delidded), SN5to7, SN9to16

2.2 Electrical Measurements

The electrical parameters measured before irradiation and after each irradiation step are defined in Table 3.

2.3 Experimental Conditions

2.3.1 Irradiation conditions

The parts were irradiated at the NASA-GSFC Co-60 irradiation facility. Parts were irradiated up to a dose level of ranging from 100 to 500 krad(Si). ITAR restrictions begin at 500 krad(Si). In this report , only test results up to a dose level of 300 krad(Si) are presented. Irradiations were followed by a one-week annealing at room temperature.

2.3.2 Bias Conditions

8 SOI devices and 7 bulk devices were irradiated. During irradiation, 6 SOI devices and 5 bulk devices were biased with a static bias as defined in Appendix 1. 2 SOI parts and 2 bulk parts were unbiased with all pins connected to ground. A static bias, compared to a dynamic bias, is a worst-case bias for total dose degradation of CMOS devices.

Table 3: Electrical parameters measured on the SRAM test vehicle (1/2)

Parameter name	Description	Typical value	Max value	Unit
Functional test_s0	All 0 pattern, 1us cycle			
Sidd_s0	I/O power supply staticIdd, all 0 pattern			
Sidd2_s0	Periphery power supply static Idd, all 0 pattern	<2	90	µA
Siddcore_s0	Memory core power supply static Idd, all 0 pattern	<20	90	µA
Didd_w_s0	I/O power supply dynamic Idd (write cycle @ 1 MHz, all 0 pattern)			
Didd2_w_s0	Periphery power supply dynamic Idd (write cycle @ 1 MHz, all 0 pattern)			
Diddcore_w_s0	Memory core power supply dynamic Idd (write cycle @ 1 MHz, all 0 pattern)			
Didd_r_s0	I/O power supply dynamic Idd (read cycle @ 1 MHz, all 0 pattern)			
Didd2_r_s0	Periphery power supply dynamic Idd (read cycle @ 1 MHz, all 0 pattern)			
Diddcore_r_s0	Memory core power supply dynamic Idd (read cycle @ 1 MHz, all 0 pattern)			
Functional test_c0	Checkerboard pattern, 1us cycle			
Sidd_c0	I/O power supply staticIdd, Checkerboard pattern			
Sidd2_c0	Periphery power supply static Idd, Checkerboard pattern	<2	90	µA
Siddcore_c0	Memory core power supply static Idd, Checkerboard pattern	<20	90	µA
Didd_w_c0	I/O power supply dynamic Idd (write cycle @ 1 MHz, Checkerboard pattern)			
Didd2_w_c0	Periphery power supply dynamic Idd (write cycle @ 1 MHz, Checkerboard pattern)			
Diddcore_w_c0	Memory core power supply dynamic Idd (write cycle @ 1 MHz, Checkerboard pattern)			
Didd_r_c0	I/O power supply dynamic Idd (read cycle @ 1 MHz, Checkerboard pattern)			
Didd2_r_c0	Periphery power supply dynamic Idd (read cycle @ 1 MHz, Checkerboard pattern)			
Diddcore_r_c0	Memory core power supply dynamic Idd (read cycle @ 1 MHz, Checkerboard pattern)			

Table 3: Electrical parameters measured on the SRAM test vehicle (2/2)

Parameter name	Description	Typical value	Max value	Unit
Functional test_c1	Reverse Checkerboard pattern, 1us cycle			
Sidd_c1	I/O power supply staticIdd, Reverse Checkerboard pattern			
Sidd2_c1	Periphery power supply static Idd, Reverse Checkerboard pattern	<2	90	µA
Siddcore_c1	Memory core power supply static Idd, Reverse Checkerboard pattern	<20	90	µA
Didd_w_c1	I/O power supply dynamic Idd (write cycle @ 1 MHz, Reverse Checkerboard pattern)			
Didd2_w_c1	Periphery power supply dynamic Idd (write cycle @ 1 MHz, Reverse Checkerboard pattern)			
Diddcore_w_c1	Memory core power supply dynamic Idd (write cycle @ 1 MHz, Reverse Checkerboard pattern)			
Didd_r_c1	I/O power supply dynamic Idd (read cycle @ 1 MHz, Reverse Checkerboard pattern)			
Didd2_r_c1	Periphery power supply dynamic Idd (read cycle @ 1 MHz, Reverse Checkerboard pattern)			
Diddcore_r_c1	Memory core power supply dynamic Idd (read cycle @ 1 MHz, Reverse Checkerboard pattern)			
Functional test_s1	All 1 pattern, 1us cycle			
Sidd_s1	I/O power supply staticIdd, all 1 pattern			
Sidd2_s1	Periphery power supply static Idd, all 1 pattern	<2	90	µA
Siddcore_s1	Memory core power supply static Idd, all 1 pattern	<20	90	µA
Didd_w_s1	I/O power supply dynamic Idd (write cycle @ 1 MHz, all 1 pattern)			
Didd2_w_s1	Periphery power supply dynamic Idd (write cycle @ 1 MHz, all 1 pattern)			
Diddcore_w_s1	Memory core power supply dynamic Idd (write cycle @ 1 MHz, all 1 pattern)			
Didd_r_s1	I/O power supply dynamic Idd (read cycle @ 1 MHz, all 1 pattern)			
Didd2_r_s1	Periphery power supply dynamic Idd (read cycle @ 1 MHz, all 1 pattern)			
Diddcore_r_s1	Memory core power supply dynamic Idd (read cycle @ 1 MHz, all 1 pattern)			

3 Test Report

3.1 Experimental Conditions

3.1.1 Parts Identification

Bulk devices	Irradiated Devices							Control device
Serial Number	5 / 13*	6 / 14*	7 / 15*	8*	9*	10	11	12
Bias condition	on	on	on	on	on	off	off	

SOI devices	Irradiated Devices							Control device
Serial Number	5 / 14*	6 / 15*	7 / 16*	9*	10*	11*	12	13
Bias condition	on	on	on	on	on	on	off	off

* note: None of the parts were biased up to irradiation step 6. On bulk devices, SN5, SN6, and SN7 have been replaced by SN13, SN14, and SN15 after irradiation step 6. On SOI devices, SN5, SN6, and SN7 have been replaced by SN14, SN15, and SN16 after irradiation step 6 and the new control part is SN4. See paragraph 3.2.3 for more details.

3.1.2 Irradiation Test Sequence

Step #	Date and Time in		Date and Time out		Description	Exposure Time	dose rate rad[Si]/mn	step dose krad [Si]	Total dose krad [Si] 1st set*	Total dose krad [Si] 2nd set*
0					Initial Elect. Measurements					
1 1a	6/28/04 6/29/04	16h55 9h39	6/29/04 6/29/04	9h39 10h58	Irradiation Electrical Meas.	16h44'	10.6	10.64	10.64	
2 2a	6/29/04 6/29/04	10h58 12h30	6/29/04 6/29/04	12h30 13h28	Irradiation Electrical Meas.	1.5	82	7.38	18.02	
3 3a	6/29/04 6/29/04	13h28 15h28	6/29/04 6/29/04	15h28 16h44	Irradiation Electrical Meas.	2	82	9.84	27.86	
4 4a	6/29/04 6/30/04	16h44 10h00	6/30/04 6/30/04	10h00 11h04	Irradiation Electrical Meas.	17h16'	18.3	18.96	46.82	
5 5a	6/30/04 6/30/04	11h04 15h00	6/30/04 6/30/04	15h00 15h56	Irradiation Electrical Meas.	3h56'	83.5	19.71	66.53	
6 6a	6/30/04 7/1/04	15h56 10h00	7/1/04 7/1/04	10h00 15h05	Irradiation Electrical Meas.	18h4'	30.1	32.63	99.16	
7 7a	7/1/04 7/2/04	15h05 9h30	7/1/04 7/2/04	18h33 10h40	Irradiation Electrical Meas.	3h28	56.5	11.75	110.91	11.75
8 8a	7/2/04 7/2/04	10h40 15h55	7/2/04 7/2/04	15h55 17h02	Irradiation Electrical Meas.	5h15	156	49.14	160.05	60.89
9 9a	7/2/04 7/6/04	17h02 10h30	7/4/04 7/6/04	14h40 11h24	Irradiation Electrical Meas.	45h38'	10.6	29.02	189.07	89.91
10 10a	7/6/04 7/6/04	11h24 15h24	7/6/04 7/6/04	15h24 16h30	Irradiation Electrical Meas.	4	152	36.48	225.55	126.39
11 11a	7/6/04 7/7/04	16h30 9h25	7/7/04 7/7/04	9h25 10h41	Irradiation Electrical Meas.	16h55	40.2	40.80	266.35	167.20
12 12a	7/7/04 7/7/04	10h41 15h34	7/7/04 7/7/04	15h34 17h08	Irradiation Electrical Meas.	4h53'	151	44.24	310.60	211.44
13 13a	7/7/04 7/8/04	17h08 10h31	7/8/04 7/8/04	10h31 12h42	Irradiation Electrical Meas.	17h23'	59	61.54	372.13	272.98
14 14a	7/8/04 7/8/04	12h42 15h52	7/8/04 7/8/04	15h52 16h52	Irradiation Electrical Meas.	3h10'	150	28.5	400.63	301.48
15 15a	7/8/04 7/9/04	16h52 10h09	7/9/04 7/9/04	10h09 11h00	Irradiation Electrical Meas.	17h17'	92	95.404	496.04	396.88
16 16a	7/9/04 7/16/04	11h00 11h00	7/16/04 7/16/04	11h00 12h00	Annealing room temp. Electrical Meas.	168h				

* note: On bulk devices the first set is made of SN5 to SN12, and the second set is made of SN13 to SN15.

On SOI devices the first set is made of SN5 to SN7 and SN10 to SN13, and the second set is made of SN14 to SN16. See paragraph 3.2.3 for more details.

3.2 Experimental Results

3.2.1 Bulk devices

3.2.1.1 Functional tests

After the irradiation step 12, one part, SN8, showed a failure in one memory cell during the reverse checkerboard pattern functional test. The expected stored value in this cell for the reverse checkerboard pattern was 1. No failure was observed for the following functional test with the all1 test pattern. The accumulated dose level on SN8 after the irradiation step 12 is 311 krad(Si). The part showed no other functional failure at the subsequent irradiation steps.

It is possible that this failure is due to a measurement glitch. However, we cannot rule out a radiation-induced failure that recovered quickly.

No other functional failure was observed on all parts after all irradiation steps.

3.2.1.2 Parametric tests

The electrical measurements results are presented in appendix 2. Fig 1 to 3 show the degradation of the three different static currents for the all1 test pattern. The dynamic currents during read and write cycle show the same trend.

The most significant degradation is observed on the memory core static current that increases of about three orders of magnitude during the irradiation. We can see a significant degradation starting at a total dose level of about 90 krad-Si. The degradation of the two other static current is visible but much less important, within one order of magnitude. The parts that were not biased during irradiation, SN10 and SN11, do not show any degradation.

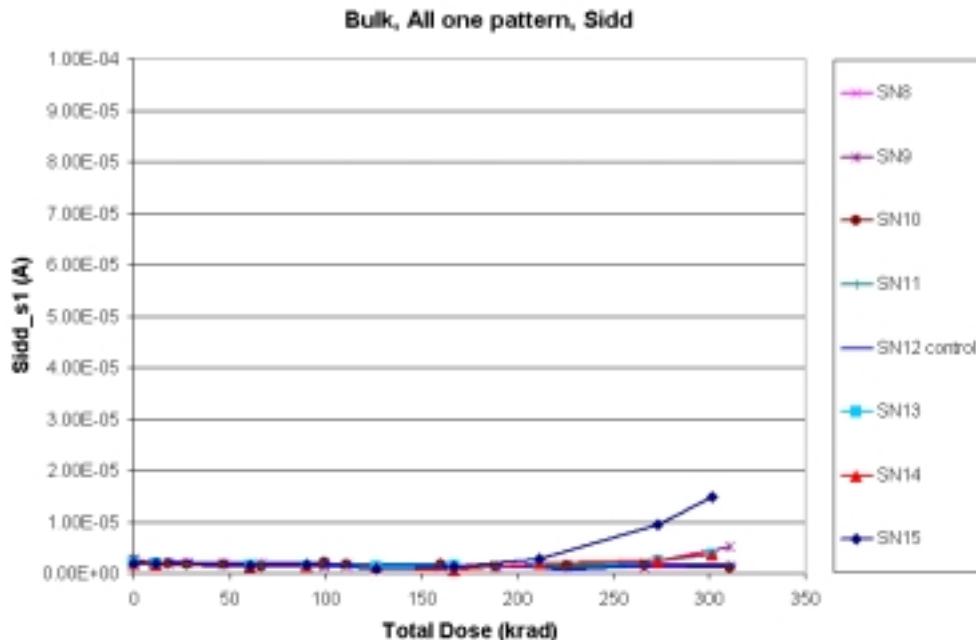


Fig 1: Degradation versus total dose of I/O power supply static Idd, all 1 pattern.

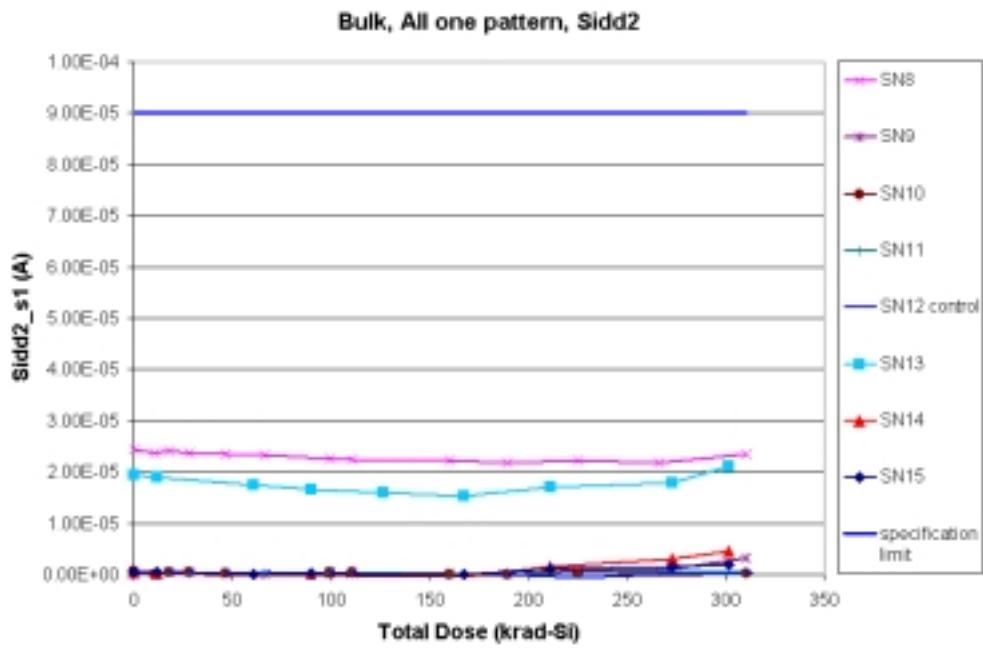


Fig 2: Degradation versus total dose of periphery power supply static Idd, all 1 pattern.

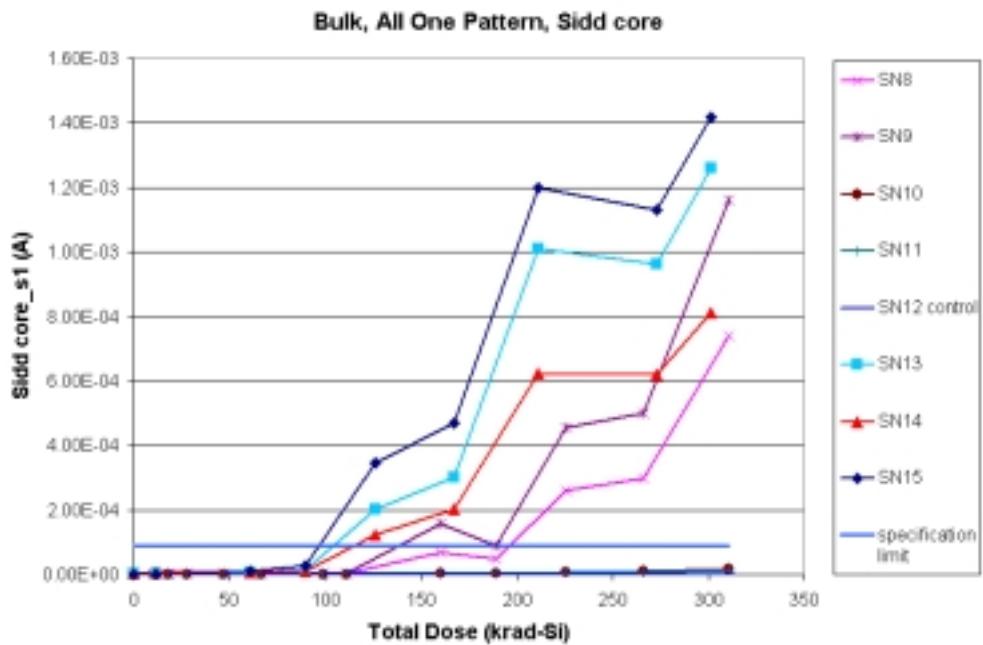


Fig 3: Degradation versus total dose of memory core power supply static Idd, all 1 pattern.

Fig 3 to 6 show the memory core power supply static Idd for the four different pattern s. All 0 pattern is the test pattern for which the smallest TID degradation is observed. All 1 pattern is the test pattern for which the largest TID degradation is observed. Checkerboard and reverse checkerboard test patterns give intermediate degradation between these two extremes. It should be noted that the difference is small. The same pattern effect is observed on Idd and Idd2 as well.

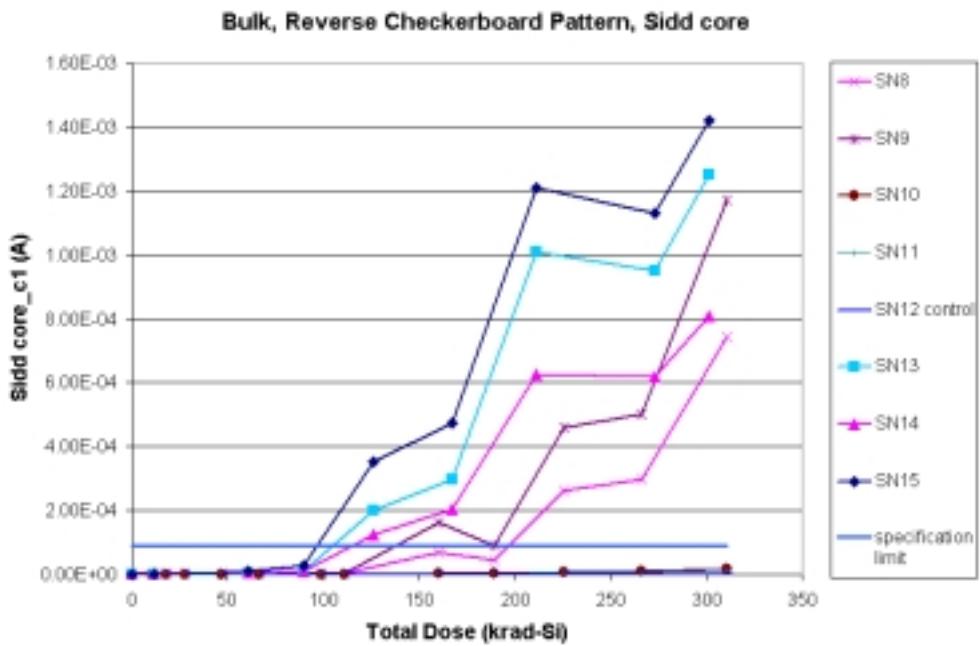


Fig 4: Degradation versus total dose of memory core power supply static Idd, reverse checkerboard pattern.

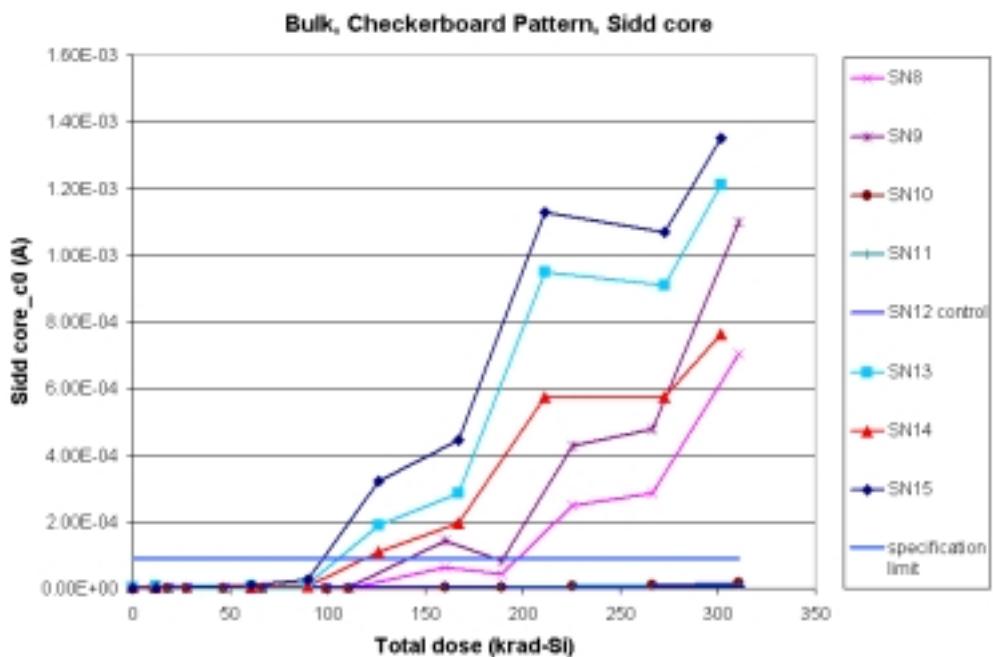


Fig 5: Degradation versus total dose of memory core power supply static Idd, checkerboard pattern.

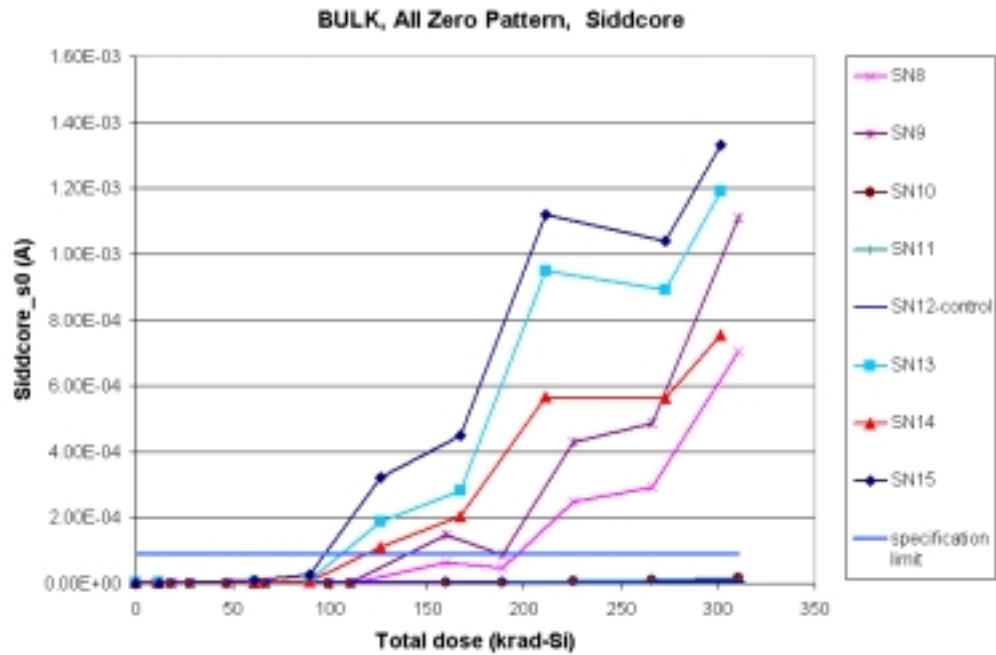


Fig 6: Degradation versus total dose of memory core power supply static Idd, all 0 pattern.

3.2.1.3 Post Irradiation effects

The measurements performed after the one week room temperature annealing show a significant but not complete recovery. Fig 7 shows the annealing data for the memory core static current with the all 1 test pattern.

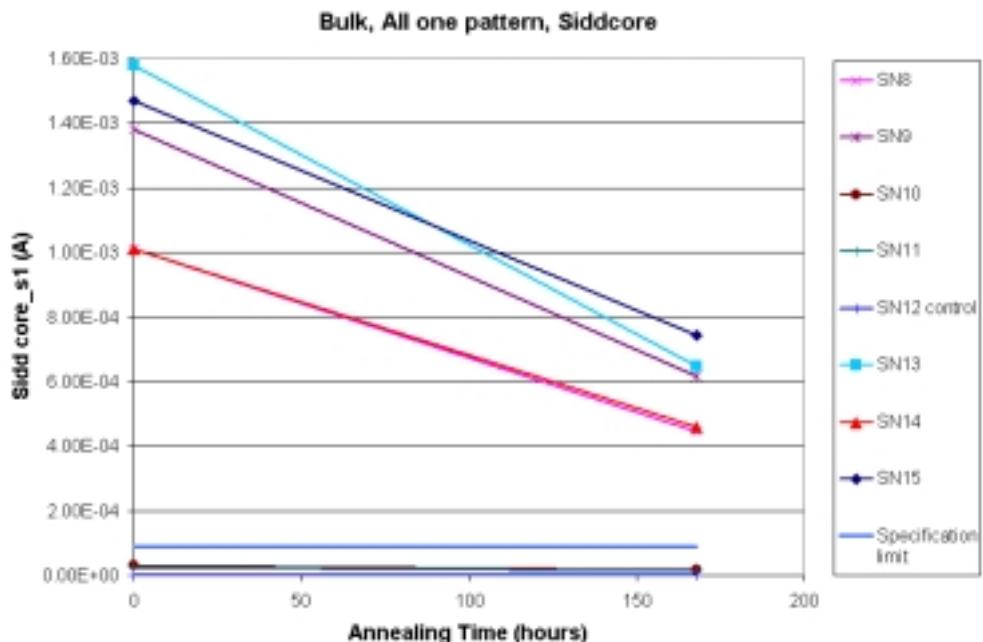


Fig 7: Recovery versus room temperature annealing time of memory core static current.
(the corresponding TID degradation curve is in Fig 3)

3.2.2 SOI devices

3.2.2.1 Functional tests

No functional failure was observed after all irradiation steps.

3.2.2.2 Parametric tests

The electrical measurements results are presented in appendix 3. Fig 8 to 10 show the degradation of the three different static currents for the all 1 test pattern. The dynamic currents during read and write cycle show the same trend.

One difference with the bulk devices is that the SOI devices show significant degradations, from two to three orders of magnitude, on all three static currents. We can see a significant degradation starting at a total dose level of about 90 krad-Si. Another difference with the bulk devices is that the unbiased SOI devices, SN12 and SN13, show degradation with total dose. However, this degradation is small compared to the one of biased parts.

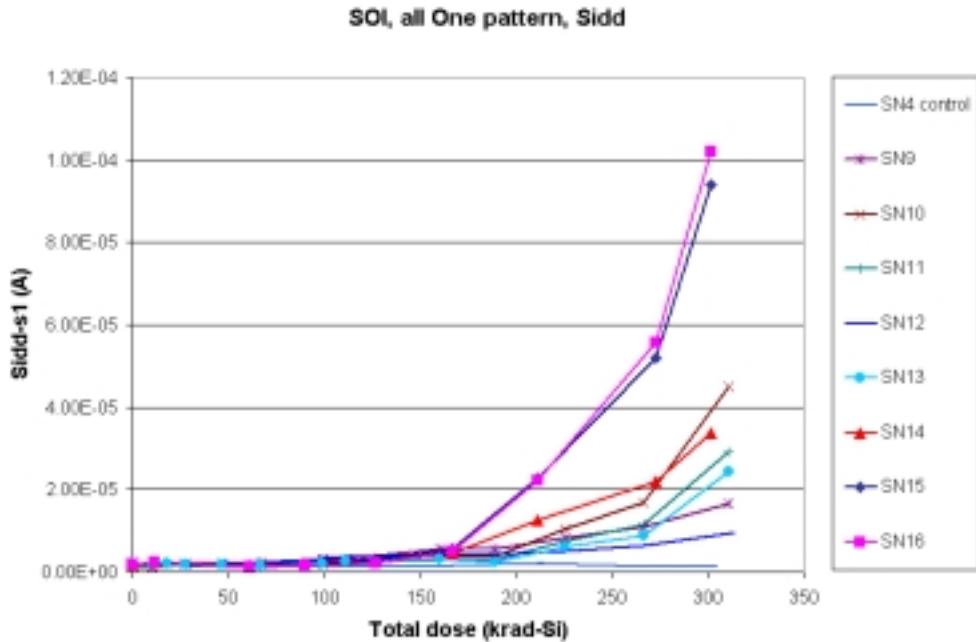


Fig 8: Degradation versus total dose of I/O power supply static Idd, all 1 pattern

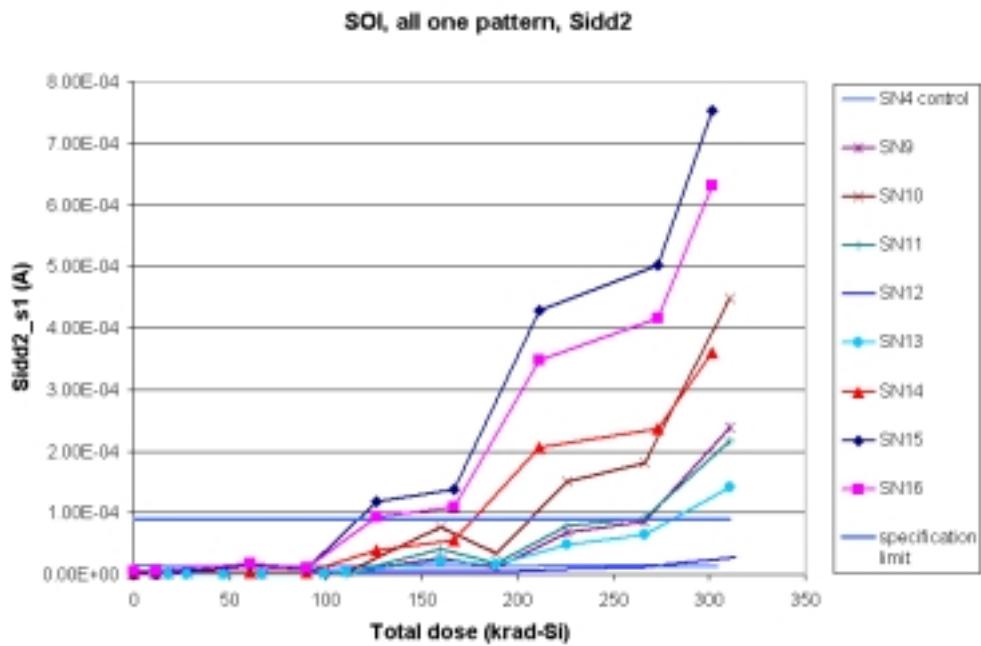


Fig 9: Degradation versus total dose of periphery power supply static Idd, all 1 pattern.

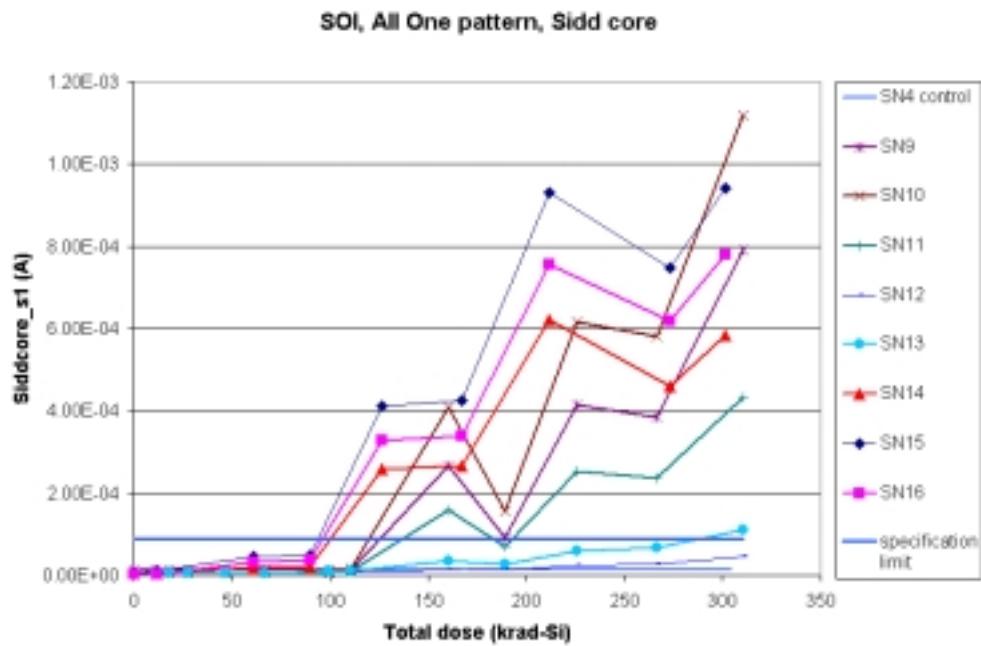


Fig 10: Degradation versus total dose of memory core power supply static Idd, all 1 pattern.

Fig 10 to 13 show the memory core power supply static Idd for the four different patterns. The effect of the test pattern is much more important on SOI devices than on bulk devices. All 0 pattern is the test pattern for which the smallest TID degradation is observed. All 1 pattern is the test pattern for which the largest TID degradation is observed. Checkerboard and reverse checkerboard test patterns give intermediate degradation between these two extremes. The same pattern effect is observed on Idd and Idd2 as well.

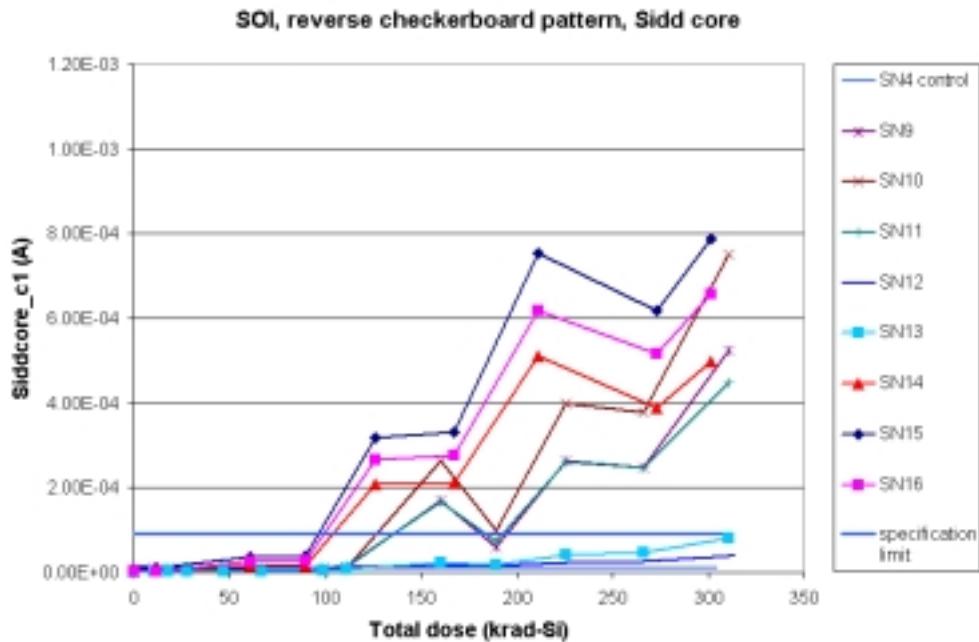


Fig 11: Degradation versus total dose of memory core power supply static Idd, reverse checkerboard pattern.

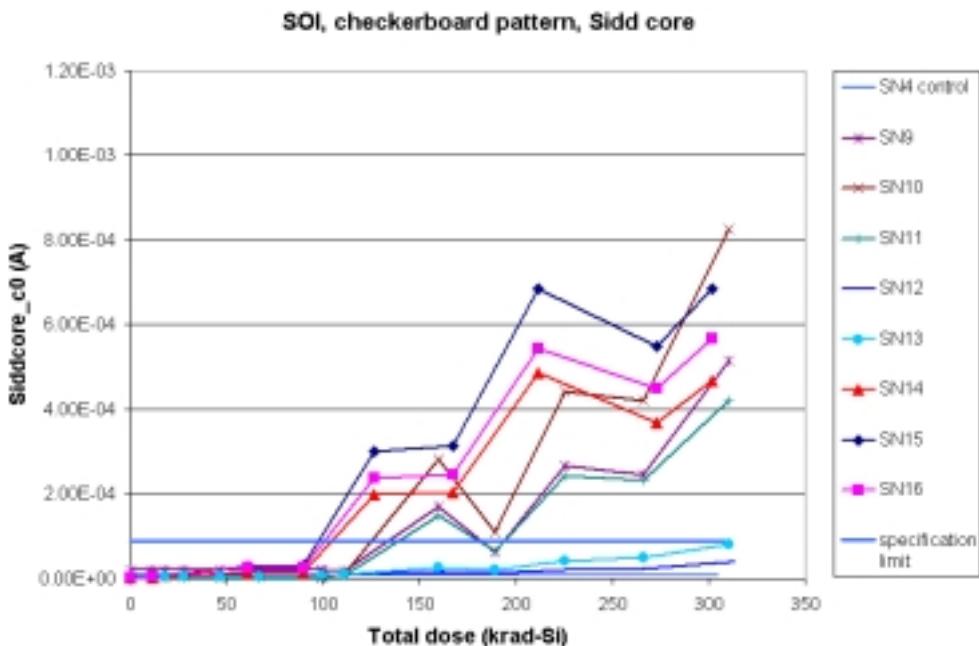


Fig 12: Degradation versus total dose of memory core power supply static Idd, checkerboard pattern.

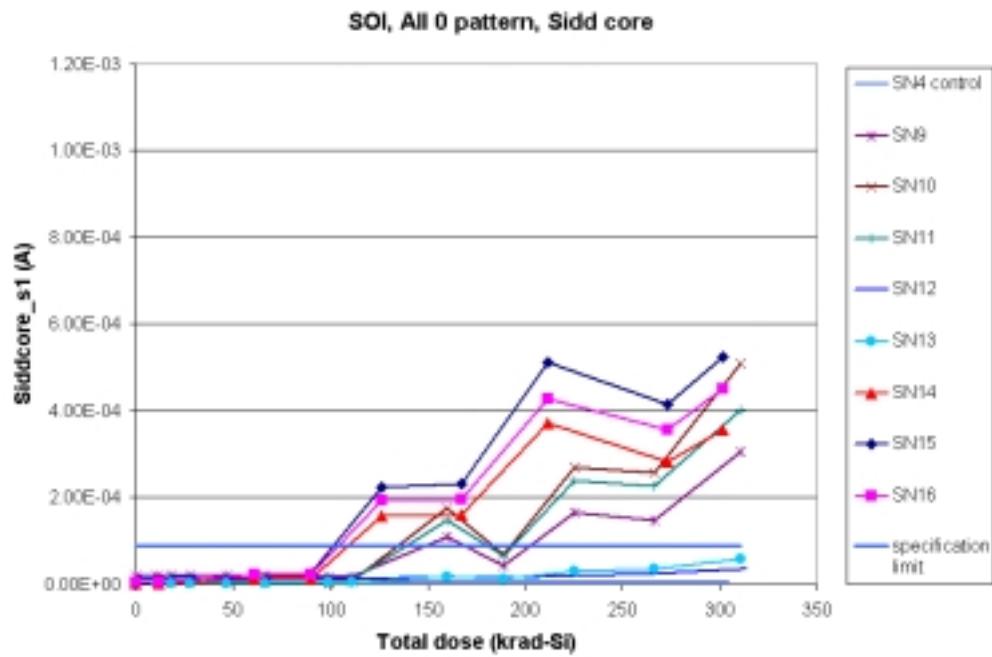


Fig 13: Degradation versus total dose of memory core power supply static Idd, all 0 pattern.

3.2.2.3 Post Irradiation effects

As for the bulk devices, the measurements performed after the one-week room temperature annealing show a significant but not complete recovery. Fig 14 shows the annealing data for the memory core static current with the all 1 test pattern.

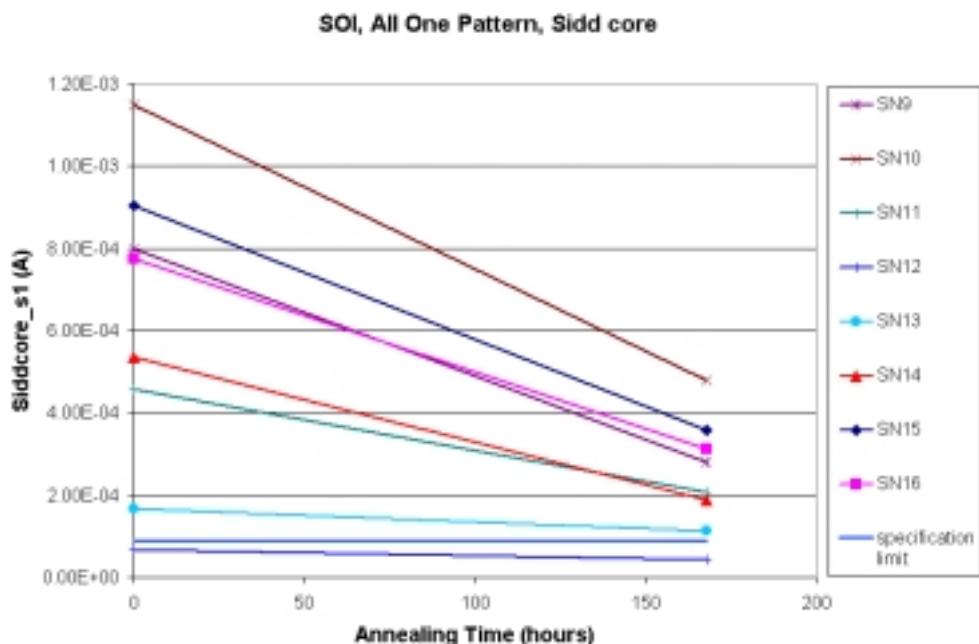


Fig 14: Recovery versus room temperature annealing time of memory core static current
(corresponding TID degradation curve is in Figure 10)

3.2.3 Problems encountered / Discussion

Due to a defective cable, all parts have been irradiated unbiased up to irradiation step 6. On bulk devices SN5, SN6, and SN7 have been replaced by new parts: SN13, SN14, and SN15. On SOI devices SN5, SN6, and SN7 have been replaced by new parts: SN14, SN15, and SN16. SN14 was the control part. It has been replaced by SN4 as the new control part. Between irradiation steps 6 and 7, the parts have been kept unbiased for 5 hours. This is a deviation from the standard procedure that requires that the time between two irradiation steps shall not exceed one hour. The parts irradiated up to step 6 have been measured just at the end of the irradiation step. They have been measured again, with the new parts, just before the irradiation step 7.

Because of a storm, the irradiation step 7 stopped prematurely. The parts have been kept biased without irradiation for about 14 hours before the electrical measurements and the next irradiation step.

For the same reason, the irradiation step 9 stopped prematurely. The parts have been kept biased without irradiation for about 44 hours before the electrical measurements and the next irradiation step.

4 Conclusion

Test results on the bulk SRAM test vehicles indicate that:

- all the parts stay functional up to at least a dose level of 270 krad-Si.
- No significant degradation of the measured electrical parameters was observed up to a dose level of 90 krad-Si.
- The I/O and periphery power supply current show a little degradation after 300 krad-Si.
- The memory core supply current is extremely degraded after 300 krad-Si.

Test results on the SOI SRAM test vehicles indicate that:

- all the parts stay functional up to at least a dose level of 300 krad-Si..
- No significant degradation of the measured electrical parameters was observed up to a dose level of 90 krad-Si.
- All three power-supply currents are extremely degraded after 300 krad-Si.

5 Appendices

5.1 Appendix 1: Static on bias conditions during irradiation

Signal name	package side	Signal type	FA28 SocketPin	Bias
adr0	left	Input signal	G2	0
adr1	right	Input signal	C10	1
adr2	right	Input signal	F10	0
adr3	left	Input signal	F2	1
adr4	left	Input signal	G1	0
adr5	right	Input signal	B10	1
adr6	right	Input signal	C9	0
adr7	top	Input signal	A9	1
adr8	top	Input signal	A8	0
adr9	top	Input signal	A10	1
adr10	top	Input signal	B8	0
adr11	top	Input signal	B2	1
adr12	top	Input signal	A2	0
adr13	top	Input signal	B3	1
adr14	right	Input signal	J10	0
adr15	right	Input signal	H10	1
clk	right	Input signal	H9	0
di0	left	Input signal	C2	0
di1	left	Input signal	B1	1
di2	left	Input signal	C1	0
di3	left	Input signal	H1	1
di4	left	Input signal	H2	0
di5	left	Input signal	J1	1
di6	right	Input signal	G9	0
di7	right	Input signal	G10	1
do0	bottom	Output signal	K1	NC
do1	bottom	Output signal	J3	NC
do2	bottom	Output signal	K2	NC
do3	bottom	Output signal	K3	NC
do4	bottom	Output signal	J7	NC
do5	bottom	Output signal	K8	NC
do6	bottom	Output signal	J8	NC
do7	bottom	Output signal	K9	NC

Signal name	package side	Signal type	FA28 SocketPin	Bias
vdd	left	power	D2	1.8V
vdd	bottom	power	K7	1.8V
vdd	right	power	D9	1.8V
vdd	top	power	B7	1.8V
vdd2	left	power	F1	1.8V
vdd2	bottom	power	J4	1.8V
vdd2	right	power	F9	1.8V
vdd2	top	power	A3	1.8V
vddcore	left	power	E1	1.8V
vddcore	right	power	E9	1.8V
vddcore	top	power	A5	1.8V
vss	left	power	D1	GND
vss	bottom	power	J6	GND
vss	right	power	D10	GND
vss	top	power	A7	GND
vss2	left	power	E2	GND
vss2	bottom	power	K4	GND
vss2	right	power	E10	GND
vss2	top	power	B4	GND
we	bottom	Input signal	J9	0

5.2 Appendix 2: Electrical measurements on bulk devices

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK05	0	all 0	P	-2.04E-07	-3.13E-07	-8.30E-07	3.25E-05	1.05E-02	-4.79E-07	3.15E-05	1.11E-02	-2.53E-07
1	BULK05	11	all 0	P	-1.51E-06	-1.19E-06	-1.19E-06	3.07E-05	1.04E-02	-9.76E-07	2.99E-05	1.11E-02	-9.23E-07
2	BULK05	18	all 0	P	-1.13E-06	-8.17E-07	-8.52E-07	3.14E-05	1.04E-02	-7.91E-07	3.03E-05	1.11E-02	-7.14E-07
3	BULK05	28	all 0	P	-1.14E-06	-8.71E-07	-8.27E-07	3.13E-05	1.04E-02	-6.25E-07	3.03E-05	1.11E-02	-3.99E-07
4	BULK05	47	all 0	P	-9.67E-07	-8.76E-07	-9.28E-07	3.09E-05	1.04E-02	-9.81E-07	2.97E-05	1.11E-02	-7.99E-07
5	BULK05	67	all 0	P	-1.05E-06	-7.23E-07	-9.86E-07	3.14E-05	1.04E-02	-7.31E-07	3.01E-05	1.11E-02	-6.96E-07
6	BULK05	99	all 0	P	-1.08E-06	-8.65E-07	-3.09E-07	3.06E-05	1.04E-02	-3.79E-07	2.93E-05	1.11E-02	-2.09E-07

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK05	0	checkerboard	P	5.86E-07	1.40E-08	-2.24E-07	7.70E-04	1.29E-02	9.00E-09	8.03E-04	1.31E-02	8.50E-08
1	BULK05	11	checkerboard	P	-2.60E-07	-7.56E-07	-6.31E-07	7.67E-04	1.29E-02	-3.94E-07	8.01E-04	1.31E-02	-2.98E-07
2	BULK05	18	checkerboard	P	-3.34E-07	-5.94E-07	-4.88E-07	7.67E-04	1.29E-02	-3.58E-07	8.01E-04	1.31E-02	-2.10E-08
3	BULK05	28	checkerboard	P	-2.11E-07	-3.44E-07	-2.00E-07	7.67E-04	1.29E-02	2.50E-07	8.01E-04	1.31E-02	3.29E-07
4	BULK05	47	checkerboard	P	-6.42E-07	-8.62E-07	-7.23E-07	7.65E-04	1.28E-02	-4.52E-07	8.00E-04	1.31E-02	-2.56E-07
5	BULK05	67	checkerboard	P	-5.37E-07	-6.07E-07	-5.08E-07	7.67E-04	1.29E-02	-1.30E-07	8.01E-04	1.31E-02	-4.60E-08
6	BULK05	99	checkerboard	P	-2.31E-07	-6.34E-07	1.90E-08	7.66E-04	1.28E-02	4.30E-07	8.00E-04	1.30E-02	4.95E-07

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK05	0	rev checkerboard	P	1.46E-06	3.47E-07	4.28E-07	7.71E-04	1.29E-02	7.74E-07	8.05E-04	1.31E-02	8.79E-07
1	BULK05	11	rev checkerboard	P	6.69E-07	-3.31E-07	2.68E-07	7.68E-04	1.29E-02	3.70E-07	8.02E-04	1.31E-02	4.92E-07
2	BULK05	18	rev checkerboard	P	5.84E-07	-1.84E-07	4.28E-07	7.68E-04	1.29E-02	4.85E-07	8.02E-04	1.31E-02	6.29E-07
3	BULK05	28	rev checkerboard	P	1.06E-06	2.24E-07	8.14E-07	7.69E-04	1.29E-02	9.51E-07	8.02E-04	1.31E-02	1.06E-06
4	BULK05	47	rev checkerboard	P	3.13E-07	-2.77E-07	2.81E-07	7.67E-04	1.28E-02	4.50E-07	8.01E-04	1.31E-02	5.36E-07
5	BULK05	67	rev checkerboard	P	4.81E-07	-2.69E-07	4.02E-07	7.68E-04	1.28E-02	5.86E-07	8.02E-04	1.31E-02	5.86E-07
6	BULK05	99	rev checkerboard	P	7.59E-07	-1.28E-07	9.06E-07	7.67E-04	1.28E-02	1.21E-06	8.01E-04	1.30E-02	1.22E-06

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK05	0	all 1	P	2.03E-06	5.52E-07	8.27E-07	2.07E-06	1.38E-02	9.05E-07	2.04E-06	1.55E-02	1.04E-06
1	BULK05	11	all 1	P	1.35E-06	1.26E-07	5.73E-07	1.32E-06	1.38E-02	8.23E-07	1.39E-06	1.55E-02	8.85E-07
2	BULK05	18	all 1	P	1.26E-06	1.53E-07	7.27E-07	1.35E-06	1.38E-02	7.80E-07	1.52E-06	1.55E-02	8.27E-07
3	BULK05	28	all 1	P	1.50E-06	4.45E-07	9.09E-07	1.44E-06	1.38E-02	1.10E-06	1.49E-06	1.55E-02	1.16E-06
4	BULK05	47	all 1	P	1.05E-06	-8.00E-08	6.52E-07	1.16E-06	1.37E-02	6.24E-07	1.11E-06	1.54E-02	8.44E-07
5	BULK05	67	all 1	P	1.06E-06	8.60E-08	6.21E-07	1.08E-06	1.38E-02	8.88E-07	1.28E-06	1.54E-02	9.09E-07
6	BULK05	99	all 1	P	1.35E-06	2.38E-07	1.28E-06	1.43E-06	1.37E-02	1.55E-06	1.30E-06	1.54E-02	1.37E-06

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK06	0	all 0	P	1.12E-06	2.02E-07	2.84E-06	3.04E-05	1.02E-02	2.77E-06	2.93E-05	1.09E-02	2.69E-06
1	BULK06	11	all 0	P	1.73E-06	3.60E-07	4.21E-06	3.07E-05	1.02E-02	4.03E-06	2.92E-05	1.09E-02	4.04E-06
2	BULK06	18	all 0	P	1.72E-06	5.58E-07	4.38E-06	3.04E-05	1.02E-02	4.23E-06	2.89E-05	1.09E-02	4.21E-06
3	BULK06	28	all 0	P	1.94E-06	7.19E-07	5.11E-06	3.03E-05	1.02E-02	4.78E-06	2.92E-05	1.09E-02	4.85E-06
4	BULK06	47	all 0	P	1.47E-06	3.67E-07	4.61E-06	3.00E-05	1.02E-02	4.65E-06	2.85E-05	1.09E-02	4.65E-06
5	BULK06	67	all 0	P	1.49E-06	2.74E-07	5.12E-06	3.04E-05	1.02E-02	4.79E-06	2.88E-05	1.09E-02	4.81E-06
6	BULK06	99	all 0	P	1.73E-06	5.36E-07	5.01E-06	2.98E-05	1.02E-02	4.80E-06	2.85E-05	1.09E-02	4.67E-06

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK06	0	checkerboard	P	9.88E-07	1.82E-07	1.70E-06	7.72E-04	1.27E-02	1.93E-06	8.01E-04	1.30E-02	2.04E-06
1	BULK06	11	checkerboard	P	1.01E-06	1.38E-07	2.04E-06	7.70E-04	1.27E-02	2.21E-06	8.00E-04	1.30E-02	2.38E-06
2	BULK06	18	checkerboard	P	1.34E-06	3.26E-07	2.47E-06	7.71E-04	1.27E-02	2.59E-06	8.01E-04	1.30E-02	2.82E-06
3	BULK06	28	checkerboard	P	1.71E-06	4.21E-07	2.88E-06	7.71E-04	1.27E-02	3.01E-06	8.01E-04	1.30E-02	3.18E-06
4	BULK06	47	checkerboard	P	1.42E-06	1.80E-08	2.84E-06	7.70E-04	1.27E-02	2.79E-06	7.99E-04	1.30E-02	2.96E-06
5	BULK06	67	checkerboard	P	1.22E-06	1.08E-07	2.84E-06	7.71E-04	1.27E-02	3.00E-06	8.01E-04	1.30E-02	3.17E-06
6	BULK06	99	checkerboard	P	1.40E-06	1.35E-07	3.06E-06	7.70E-04	1.26E-02	3.21E-06	8.00E-04	1.29E-02	3.35E-06

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK06	0	rev checkerboard	P	1.68E-06	5.94E-07	2.88E-06	7.73E-04	1.27E-02	3.08E-06	8.02E-04	1.30E-02	3.10E-06
1	BULK06	11	rev checkerboard	P	1.43E-06	2.49E-07	3.46E-06	7.71E-04	1.27E-02	3.65E-06	8.00E-04	1.30E-02	3.76E-06
2	BULK06	18	rev checkerboard	P	2.05E-06	4.41E-07	4.16E-06	7.72E-04	1.27E-02	4.39E-06	8.01E-04	1.30E-02	4.31E-06
3	BULK06	28	rev checkerboard	P	1.91E-06	6.01E-07	4.57E-06	7.72E-04	1.27E-02	4.63E-06	8.01E-04	1.30E-02	4.73E-06
4	BULK06	47	rev checkerboard	P	1.66E-06	1.33E-07	4.38E-06	7.70E-04	1.26E-02	4.47E-06	8.00E-04	1.29E-02	4.46E-06
5	BULK06	67	rev checkerboard	P	1.54E-06	2.18E-07	4.42E-06	7.71E-04	1.27E-02	4.46E-06	8.01E-04	1.30E-02	4.44E-06
6	BULK06	99	rev checkerboard	P	1.56E-06	2.42E-07	4.28E-06	7.71E-04	1.26E-02	4.36E-06	8.00E-04	1.29E-02	4.44E-06

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK06	0	all 1	P	2.17E-06	6.12E-07	2.02E-06	2.12E-06	1.38E-02	1.83E-06	2.04E-06	1.56E-02	1.93E-06
1	BULK06	11	all 1	P	1.63E-06	2.38E-07	1.93E-06	1.67E-06	1.38E-02	2.24E-06	1.94E-06	1.55E-02	2.01E-06
2	BULK06	18	all 1	P	1.90E-06	4.05E-07	2.44E-06	1.79E-06	1.38E-02	2.54E-06	2.11E-06	1.55E-02	2.48E-06
3	BULK06	28	all 1	P	2.15E-06	7.93E-07	2.71E-06	2.07E-06	1.38E-02	2.82E-06	2.11E-06	1.55E-02	2.75E-06
4	BULK06	47	all 1	P	1.93E-06	1.84E-07	2.48E-06	1.90E-06	1.37E-02	2.43E-06	1.66E-06	1.55E-02	2.44E-06
5	BULK06	67	all 1	P	1.65E-06	4.50E-07	2.58E-06	1.81E-06	1.37E-02	2.75E-06	1.90E-06	1.55E-02	2.93E-06
6	BULK06	99	all 1	P	1.79E-06	3.27E-07	2.70E-06	1.81E-06	1.37E-02	2.66E-06	1.79E-06	1.54E-02	2.89E-06

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK07	0	all 0	P	2.21E-06	5.68E-07	5.35E-07	3.34E-05	1.05E-02	2.90E-07	3.20E-05	1.12E-02	5.32E-07
1	BULK07	11	all 0	P	1.57E-06	2.64E-07	3.71E-07	3.29E-05	1.05E-02	-1.21E-07	3.11E-05	1.12E-02	-2.23E-07
2	BULK07	18	all 0	P	2.18E-06	7.06E-07	6.38E-07	3.34E-05	1.05E-02	6.55E-07	3.20E-05	1.12E-02	4.33E-07
3	BULK07	28	all 0	P	1.69E-06	6.08E-07	4.18E-07	3.26E-05	1.05E-02	7.10E-08	3.14E-05	1.12E-02	1.90E-08
4	BULK07	47	all 0	P	1.91E-06	3.83E-07	4.29E-07	3.28E-05	1.05E-02	1.87E-07	3.11E-05	1.11E-02	8.80E-08
5	BULK07	67	all 0	P	1.80E-06	5.64E-07	6.96E-07	3.28E-05	1.05E-02	6.10E-08	3.15E-05	1.11E-02	2.29E-07
6	BULK07	99	all 0	P	1.88E-06	4.82E-07	1.05E-06	3.29E-05	1.04E-02	8.20E-07	3.12E-05	1.11E-02	6.01E-07

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK07	0	checkerboard	P	1.94E-06	3.17E-07	2.89E-07	7.74E-04	1.30E-02	4.81E-07	8.04E-04	1.32E-02	5.44E-07
1	BULK07	11	checkerboard	P	1.02E-06	-1.74E-07	-3.39E-07	7.72E-04	1.30E-02	-1.38E-07	8.02E-04	1.32E-02	-2.20E-07
2	BULK07	18	checkerboard	P	1.59E-06	3.29E-07	4.48E-07	7.73E-04	1.30E-02	4.68E-07	8.03E-04	1.32E-02	5.24E-07
3	BULK07	28	checkerboard	P	1.11E-06	2.00E-07	3.27E-07	7.72E-04	1.30E-02	3.62E-07	8.03E-04	1.32E-02	3.90E-07
4	BULK07	47	checkerboard	P	1.37E-06	4.40E-08	1.30E-07	7.71E-04	1.29E-02	1.96E-07	8.02E-04	1.32E-02	2.16E-07
5	BULK07	67	checkerboard	P	1.21E-06	-3.50E-08	2.22E-07	7.73E-04	1.29E-02	2.85E-07	8.03E-04	1.32E-02	3.20E-07
6	BULK07	99	checkerboard	P	1.30E-06	2.23E-07	5.99E-07	7.72E-04	1.29E-02	6.80E-07	8.02E-04	1.31E-02	6.31E-07

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK07	0	rev checkerboard	P	2.25E-06	4.63E-07	4.60E-07	7.75E-04	1.30E-02	6.38E-07	8.05E-04	1.32E-02	8.56E-07
1	BULK07	11	rev checkerboard	P	1.42E-06	-5.30E-08	-2.31E-07	7.72E-04	1.30E-02	-3.00E-09	8.03E-04	1.32E-02	1.39E-07
2	BULK07	18	rev checkerboard	P	1.92E-06	4.46E-07	5.30E-07	7.74E-04	1.30E-02	5.44E-07	8.03E-04	1.32E-02	6.65E-07
3	BULK07	28	rev checkerboard	P	1.55E-06	4.11E-07	3.34E-07	7.73E-04	1.29E-02	3.35E-07	8.03E-04	1.32E-02	4.96E-07
4	BULK07	47	rev checkerboard	P	1.58E-06	9.90E-08	2.20E-07	7.72E-04	1.29E-02	3.99E-07	8.02E-04	1.32E-02	3.44E-07
5	BULK07	67	rev checkerboard	P	1.36E-06	1.40E-08	2.91E-07	7.73E-04	1.29E-02	3.40E-07	8.03E-04	1.32E-02	3.53E-07
6	BULK07	99	rev checkerboard	P	1.52E-06	2.74E-07	5.66E-07	7.72E-04	1.29E-02	6.15E-07	8.02E-04	1.31E-02	7.44E-07

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK07	0	all 1	P	2.40E-06	6.48E-07	5.98E-07	2.20E-06	1.40E-02	7.84E-07	2.29E-06	1.57E-02	7.58E-07
1	BULK07	11	all 1	P	1.56E-06	1.24E-07	4.00E-08	1.53E-06	1.39E-02	9.80E-08	1.46E-06	1.57E-02	1.51E-07
2	BULK07	18	all 1	P	2.11E-06	5.90E-07	7.14E-07	2.15E-06	1.39E-02	6.37E-07	2.12E-06	1.57E-02	6.30E-07
3	BULK07	28	all 1	P	1.81E-06	3.45E-07	5.63E-07	1.88E-06	1.39E-02	8.04E-07	2.07E-06	1.57E-02	1.22E-06
4	BULK07	47	all 1	P	1.81E-06	2.50E-07	3.97E-07	1.95E-06	1.39E-02	4.32E-07	1.69E-06	1.56E-02	3.66E-07
5	BULK07	67	all 1	P	1.75E-06	1.35E-07	3.80E-07	1.52E-06	1.39E-02	5.32E-07	1.68E-06	1.56E-02	6.57E-07
6	BULK07	99	all 1	P	1.55E-06	2.85E-07	7.91E-07	1.60E-06	1.39E-02	9.23E-07	1.79E-06	1.56E-02	7.90E-07

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK08	0	all 0	P	2.34E-06	2.43E-05	1.98E-06	3.69E-05	1.03E-02	2.65E-06	3.56E-05	1.10E-02	2.69E-06
1	BULK08	11	all 0	P	1.83E-06	2.42E-05	1.79E-06	3.62E-05	1.03E-02	2.21E-06	3.44E-05	1.10E-02	1.98E-06
2	BULK08	18	all 0	P	2.17E-06	2.41E-05	1.99E-06	3.65E-05	1.03E-02	2.76E-06	3.50E-05	1.10E-02	2.72E-06
3	BULK08	28	all 0	P	2.10E-06	2.39E-05	2.22E-06	3.63E-05	1.03E-02	3.04E-06	3.49E-05	1.10E-02	2.68E-06
4	BULK08	47	all 0	P	1.94E-06	2.32E-05	2.03E-06	3.60E-05	1.03E-02	2.87E-06	3.45E-05	1.10E-02	2.71E-06
5	BULK08	67	all 0	P	2.00E-06	2.33E-05	2.18E-06	3.60E-05	1.03E-02	3.01E-06	3.45E-05	1.10E-02	2.78E-06
6	BULK08	99	all 0	P	1.90E-06	2.29E-05	2.31E-06	3.57E-05	1.02E-02	3.08E-06	3.42E-05	1.09E-02	3.06E-06
6bis	BULK08	99	all 0	P	-1.21E-06	2.15E-05	7.04E-07	3.26E-05	1.02E-02	1.55E-06	3.19E-05	1.09E-02	1.66E-06
7	BULK08	111	all 0	P	-1.29E-06	2.13E-05	9.01E-07	3.26E-05	1.02E-02	1.94E-06	3.17E-05	1.09E-02	1.93E-06
8	BULK08	160	all 0	P	-1.10E-06	2.13E-05	6.37E-05	3.29E-05	1.02E-02	6.37E-05	3.17E-05	1.09E-02	6.32E-05
9	BULK08	189	all 0	P	-1.04E-06	2.10E-05	4.56E-05	3.18E-05	1.02E-02	4.51E-05	3.07E-05	1.09E-02	4.47E-05
10	BULK08	226	all 0	P	-1.26E-06	2.09E-05	2.49E-04	3.24E-05	1.02E-02	2.48E-04	3.12E-05	1.09E-02	2.46E-04
11	BULK08	266	all 0	P	-1.48E-06	2.09E-05	2.92E-04	3.18E-05	1.02E-02	2.89E-04	3.07E-05	1.09E-02	2.87E-04
12	BULK08	311	all 0	P	-1.35E-06	2.20E-05	7.05E-04	3.21E-05	1.02E-02	6.99E-04	3.12E-05	1.09E-02	6.97E-04
ann	BULK08	annealing*	all 0	P	-1.35E-06	2.08E-05	4.21E-04	3.19E-05	1.02E-02	4.20E-04	3.09E-05	1.09E-02	4.19E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK08	0	checkerboard	P	2.11E-06	2.44E-05	1.90E-06	7.76E-04	1.28E-02	1.90E-06	8.04E-04	1.31E-02	1.75E-06
1	BULK08	11	checkerboard	P	1.31E-06	2.37E-05	1.34E-06	7.74E-04	1.28E-02	1.44E-06	8.02E-04	1.31E-02	1.53E-06
2	BULK08	18	checkerboard	P	1.85E-06	2.38E-05	1.97E-06	7.75E-04	1.28E-02	2.26E-06	8.03E-04	1.31E-02	1.93E-06
3	BULK08	28	checkerboard	P	1.39E-06	2.35E-05	2.03E-06	7.75E-04	1.28E-02	2.25E-06	8.02E-04	1.31E-02	2.15E-06
4	BULK08	47	checkerboard	P	1.50E-06	2.32E-05	1.94E-06	7.73E-04	1.27E-02	1.91E-06	8.01E-04	1.30E-02	1.91E-06
5	BULK08	67	checkerboard	P	1.23E-06	2.30E-05	2.00E-06	7.74E-04	1.27E-02	2.09E-06	8.02E-04	1.30E-02	2.19E-06
6	BULK08	99	checkerboard	P	1.66E-06	2.27E-05	2.43E-06	7.74E-04	1.27E-02	2.38E-06	8.02E-04	1.30E-02	2.42E-06
6bis	BULK08	99	checkerboard	P	-3.13E-07	2.18E-05	1.14E-06	7.71E-04	1.27E-02	1.53E-06	8.00E-04	1.30E-02	1.71E-06
7	BULK08	111	checkerboard	P	-4.06E-07	2.16E-05	1.39E-06	7.72E-04	1.27E-02	1.73E-06	8.00E-04	1.30E-02	1.95E-06
8	BULK08	160	checkerboard	P	-4.20E-07	2.14E-05	6.34E-05	7.70E-04	1.27E-02	6.26E-05	7.99E-04	1.30E-02	6.23E-05
9	BULK08	189	checkerboard	P	-4.81E-07	2.10E-05	4.41E-05	7.68E-04	1.26E-02	4.38E-05	7.97E-04	1.29E-02	4.36E-05
10	BULK08	226	checkerboard	P	-6.83E-07	2.10E-05	2.48E-04	7.69E-04	1.27E-02	2.46E-04	7.98E-04	1.29E-02	2.45E-04
11	BULK08	266	checkerboard	P	-7.98E-07	2.08E-05	2.87E-04	7.67E-04	1.26E-02	2.85E-04	7.96E-04	1.29E-02	2.83E-04
12	BULK08	311	checkerboard	P	-2.78E-07	2.24E-05	7.04E-04	7.69E-04	1.26E-02	6.99E-04	7.98E-04	1.29E-02	6.97E-04
ann	BULK08	annealing*	checkerboard	P	1.70E-06	2.13E-05	4.27E-04	7.70E-04	1.26E-02	4.24E-04	7.99E-04	1.29E-02	4.22E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK08	0	rev checkerboard	P	2.13E-06	2.41E-05	1.65E-06	7.77E-04	1.28E-02	2.57E-06	8.04E-04	1.31E-02	2.65E-06
1	BULK08	11	rev checkerboard	P	1.40E-06	2.37E-05	1.43E-06	7.75E-04	1.28E-02	2.50E-06	8.02E-04	1.31E-02	2.52E-06
2	BULK08	18	rev checkerboard	P	1.93E-06	2.39E-05	2.00E-06	7.76E-04	1.28E-02	3.01E-06	8.03E-04	1.31E-02	3.24E-06
3	BULK08	28	rev checkerboard	P	1.89E-06	2.38E-05	2.21E-06	7.76E-04	1.28E-02	3.20E-06	8.03E-04	1.30E-02	3.06E-06
4	BULK08	47	rev checkerboard	P	1.85E-06	2.31E-05	2.03E-06	7.74E-04	1.27E-02	2.97E-06	8.02E-04	1.30E-02	3.12E-06
5	BULK08	67	rev checkerboard	P	1.60E-06	2.31E-05	2.24E-06	7.75E-04	1.27E-02	3.42E-06	8.03E-04	1.30E-02	3.39E-06
6	BULK08	99	rev checkerboard	P	1.69E-06	2.27E-05	2.41E-06	7.74E-04	1.27E-02	3.42E-06	8.02E-04	1.30E-02	3.47E-06
6bis	BULK08	99	rev checkerboard	P	6.51E-07	2.22E-05	1.96E-06	7.73E-04	1.27E-02	2.96E-06	8.01E-04	1.30E-02	3.22E-06
7	BULK08	111	rev checkerboard	P	6.59E-07	2.21E-05	2.18E-06	7.73E-04	1.27E-02	3.19E-06	8.02E-04	1.30E-02	3.61E-06
8	BULK08	160	rev checkerboard	P	7.04E-07	2.19E-05	6.89E-05	7.71E-04	1.27E-02	6.84E-05	8.00E-04	1.30E-02	6.79E-05
9	BULK08	189	rev checkerboard	P	6.35E-07	2.14E-05	4.61E-05	7.70E-04	1.26E-02	4.64E-05	7.98E-04	1.29E-02	4.62E-05
10	BULK08	226	rev checkerboard	P	3.78E-07	2.15E-05	2.62E-04	7.71E-04	1.26E-02	2.58E-04	7.99E-04	1.29E-02	2.56E-04
11	BULK08	266	rev checkerboard	P	4.52E-07	2.13E-05	2.98E-04	7.69E-04	1.26E-02	2.94E-04	7.98E-04	1.29E-02	2.93E-04
12	BULK08	311	rev checkerboard	F	8.56E-07	2.29E-05	7.42E-04	7.71E-04	1.26E-02	7.30E-04	8.00E-04	1.29E-02	7.25E-04
ann	BULK08	annealing*	rev checkerboard	P	2.37E-06	2.17E-05	4.49E-04	7.72E-04	1.26E-02	4.43E-04	8.01E-04	1.29E-02	4.38E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK08	0	all 1	P	2.51E-06	2.44E-05	1.95E-06	2.41E-06	1.38E-02	1.88E-06	2.45E-06	1.56E-02	2.02E-06
1	BULK08	11	all 1	P	1.70E-06	2.38E-05	1.71E-06	1.69E-06	1.38E-02	1.60E-06	1.65E-06	1.56E-02	1.62E-06
2	BULK08	18	all 1	P	2.05E-06	2.41E-05	2.03E-06	1.89E-06	1.38E-02	2.11E-06	2.03E-06	1.56E-02	2.04E-06
3	BULK08	28	all 1	P	2.09E-06	2.38E-05	2.30E-06	1.99E-06	1.38E-02	2.49E-06	2.01E-06	1.56E-02	2.33E-06
4	BULK08	47	all 1	P	1.90E-06	2.35E-05	2.11E-06	1.75E-06	1.38E-02	2.11E-06	1.91E-06	1.55E-02	2.19E-06
5	BULK08	67	all 1	P	1.93E-06	2.33E-05	2.51E-06	1.83E-06	1.38E-02	2.47E-06	1.94E-06	1.55E-02	2.52E-06
6	BULK08	99	all 1	P	1.84E-06	2.27E-05	2.52E-06	1.91E-06	1.37E-02	2.57E-06	1.84E-06	1.55E-02	2.38E-06
6bis	BULK08	99	all 1	P	1.31E-06	2.27E-05	2.36E-06	1.57E-06	1.37E-02	2.40E-06	1.62E-06	1.55E-02	2.34E-06
7	BULK08	111	all 1	P	1.19E-06	2.25E-05	2.78E-06	1.53E-06	1.37E-02	2.75E-06	1.35E-06	1.55E-02	2.69E-06
8	BULK08	160	all 1	P	1.26E-06	2.22E-05	6.82E-05	1.38E-06	1.37E-02	6.70E-05	1.26E-06	1.54E-02	6.68E-05
9	BULK08	189	all 1	P	1.08E-06	2.17E-05	4.64E-05	1.28E-06	1.37E-02	4.59E-05	1.35E-06	1.54E-02	4.58E-05
10	BULK08	226	all 1	P	1.20E-06	2.21E-05	2.62E-04	1.14E-06	1.37E-02	2.59E-04	1.25E-06	1.54E-02	2.58E-04
11	BULK08	266	all 1	P	9.77E-07	2.17E-05	2.99E-04	1.18E-06	1.36E-02	2.96E-04	1.30E-06	1.54E-02	2.96E-04
12	BULK08	311	all 1	P	1.55E-06	2.34E-05	7.40E-04	1.63E-06	1.37E-02	7.34E-04	1.77E-06	1.54E-02	7.32E-04
ann	BULK08	annealing*	all 1	P	5.21E-06	2.26E-05	4.45E-04	5.31E-06	1.36E-02	4.40E-04	5.54E-06	1.54E-02	4.38E-04

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK09	0	all 0	P	2.09E-06	7.13E-07	9.14E-07	3.43E-05	1.04E-02	8.08E-07	3.31E-05	1.11E-02	8.27E-07
1	BULK09	11	all 0	P	1.89E-06	5.27E-07	3.62E-07	3.30E-05	1.04E-02	2.11E-07	3.18E-05	1.11E-02	1.11E-07
2	BULK09	18	all 0	P	2.20E-06	6.88E-07	7.98E-07	3.36E-05	1.04E-02	6.64E-07	3.24E-05	1.11E-02	6.46E-07
3	BULK09	28	all 0	P	2.03E-06	6.82E-07	8.52E-07	3.36E-05	1.04E-02	7.46E-07	3.22E-05	1.11E-02	6.30E-07
4	BULK09	47	all 0	P	1.95E-06	3.80E-07	6.43E-07	3.31E-05	1.04E-02	6.55E-07	3.15E-05	1.11E-02	4.82E-07
5	BULK09	67	all 0	P	1.82E-06	3.96E-07	8.75E-07	3.32E-05	1.04E-02	4.99E-07	3.17E-05	1.10E-02	5.58E-07
6	BULK09	99	all 0	P	1.80E-06	5.63E-07	1.03E-06	3.29E-05	1.04E-02	8.90E-07	3.15E-05	1.10E-02	7.67E-07
6bis	BULK09	99	all 0	P	1.58E-06	4.42E-07	1.23E-06	3.24E-05	1.04E-02	9.61E-07	3.11E-05	1.10E-02	8.72E-07
7	BULK09	111	all 0	P	1.79E-06	1.83E-07	2.24E-06	3.28E-05	1.04E-02	2.42E-06	3.14E-05	1.10E-02	2.04E-06
8	BULK09	160	all 0	P	1.73E-06	4.06E-07	1.46E-04	3.25E-05	1.03E-02	1.43E-04	3.10E-05	1.10E-02	1.42E-04
9	BULK09	189	all 0	P	5.75E-07	-2.40E-07	8.66E-05	3.09E-05	1.03E-02	8.48E-05	2.96E-05	1.10E-02	8.43E-05
10	BULK09	226	all 0	P	8.63E-07	4.79E-07	4.31E-04	3.16E-05	1.03E-02	4.26E-04	3.00E-05	1.10E-02	4.24E-04
11	BULK09	266	all 0	P	7.93E-07	7.41E-07	4.87E-04	3.10E-05	1.03E-02	4.80E-04	2.97E-05	1.10E-02	4.77E-04
12	BULK09	311	all 0	P	9.36E-07	2.45E-06	1.11E-03	3.15E-05	1.03E-02	1.10E-03	3.01E-05	1.10E-02	1.10E-03
ann	BULK09	annealing*	all 0	P	1.48E-06	1.71E-06	5.97E-04	3.18E-05	1.03E-02	5.91E-04	3.05E-05	1.10E-02	5.87E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK09	0	checkerboard	P	2.12E-06	5.36E-07	6.08E-07	7.72E-04	1.28E-02	8.48E-07	7.98E-04	1.30E-02	8.81E-07
1	BULK09	11	checkerboard	P	1.02E-06	-2.94E-07	-1.42E-07	7.70E-04	1.28E-02	-6.10E-08	7.96E-04	1.30E-02	-1.98E-07
2	BULK09	18	checkerboard	P	1.96E-06	5.08E-07	4.70E-07	7.70E-04	1.28E-02	5.04E-07	7.97E-04	1.30E-02	7.85E-07
3	BULK09	28	checkerboard	P	1.88E-06	4.18E-07	6.37E-07	7.71E-04	1.28E-02	5.66E-07	7.97E-04	1.30E-02	6.87E-07
4	BULK09	47	checkerboard	P	1.58E-06	7.60E-08	2.76E-07	7.69E-04	1.28E-02	4.24E-07	7.96E-04	1.30E-02	2.72E-07
5	BULK09	67	checkerboard	P	1.24E-06	5.00E-09	2.35E-07	7.70E-04	1.28E-02	4.82E-07	7.96E-04	1.30E-02	4.83E-07
6	BULK09	99	checkerboard	P	1.59E-06	2.90E-07	7.90E-07	7.69E-04	1.27E-02	8.00E-07	7.96E-04	1.29E-02	8.52E-07
6bis	BULK09	99	checkerboard	P	1.41E-06	2.20E-07	6.66E-07	7.69E-04	1.27E-02	6.77E-07	7.95E-04	1.29E-02	6.88E-07
7	BULK09	111	checkerboard	P	1.34E-06	1.52E-07	1.92E-06	7.69E-04	1.27E-02	2.03E-06	7.96E-04	1.29E-02	1.99E-06
8	BULK09	160	checkerboard	P	1.13E-06	2.24E-07	1.43E-04	7.67E-04	1.27E-02	1.41E-04	7.94E-04	1.29E-02	1.40E-04
9	BULK09	189	checkerboard	P	3.14E-07	-4.63E-07	8.44E-05	7.65E-04	1.27E-02	8.37E-05	7.92E-04	1.29E-02	8.32E-05
10	BULK09	226	checkerboard	P	6.28E-07	1.47E-07	4.29E-04	7.66E-04	1.27E-02	4.25E-04	7.93E-04	1.29E-02	4.23E-04
11	BULK09	266	checkerboard	P	9.69E-07	3.30E-07	4.79E-04	7.65E-04	1.27E-02	4.74E-04	7.92E-04	1.29E-02	4.71E-04
12	BULK09	311	checkerboard	P	2.31E-06	2.31E-06	1.10E-03	7.68E-04	1.27E-02	1.09E-03	7.95E-04	1.29E-02	1.09E-03
ann	BULK09	annealing*	checkerboard	P	1.18E-05	2.04E-06	5.98E-04	7.76E-04	1.27E-02	5.92E-04	8.03E-04	1.29E-02	5.87E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK09	0	rev checkerboard	P	2.29E-06	4.11E-07	1.64E-06	7.73E-04	1.28E-02	1.96E-06	7.98E-04	1.30E-02	2.15E-06
1	BULK09	11	rev checkerboard	P	1.19E-06	-1.35E-07	1.03E-06	7.70E-04	1.28E-02	1.17E-06	7.96E-04	1.30E-02	1.30E-06
2	BULK09	18	rev checkerboard	P	2.21E-06	4.47E-07	1.78E-06	7.71E-04	1.28E-02	1.92E-06	7.97E-04	1.30E-02	1.64E-06
3	BULK09	28	rev checkerboard	P	2.01E-06	3.92E-07	2.07E-06	7.71E-04	1.28E-02	2.19E-06	7.98E-04	1.30E-02	2.06E-06
4	BULK09	47	rev checkerboard	P	1.63E-06	2.10E-07	1.75E-06	7.70E-04	1.28E-02	1.96E-06	7.96E-04	1.30E-02	1.89E-06
5	BULK09	67	rev checkerboard	P	1.61E-06	2.27E-07	1.97E-06	7.71E-04	1.28E-02	2.17E-06	7.97E-04	1.30E-02	2.09E-06
6	BULK09	99	rev checkerboard	P	1.79E-06	2.77E-07	2.44E-06	7.70E-04	1.27E-02	2.37E-06	7.96E-04	1.29E-02	2.47E-06
6bis	BULK09	99	rev checkerboard	P	1.52E-06	1.73E-07	2.13E-06	7.70E-04	1.27E-02	2.28E-06	7.96E-04	1.29E-02	2.26E-06
7	BULK09	111	rev checkerboard	P	1.64E-06	9.00E-08	3.46E-06	7.70E-04	1.27E-02	3.52E-06	7.96E-04	1.29E-02	3.69E-06
8	BULK09	160	rev checkerboard	P	1.57E-06	1.83E-07	1.61E-04	7.69E-04	1.27E-02	1.56E-04	7.95E-04	1.29E-02	1.54E-04
9	BULK09	189	rev checkerboard	P	9.77E-07	-1.60E-07	9.04E-05	7.66E-04	1.27E-02	8.87E-05	7.93E-04	1.29E-02	8.79E-05
10	BULK09	226	rev checkerboard	P	1.22E-06	2.00E-07	4.58E-04	7.68E-04	1.27E-02	4.49E-04	7.94E-04	1.29E-02	4.45E-04
11	BULK09	266	rev checkerboard	P	1.44E-06	6.42E-07	5.02E-04	7.66E-04	1.27E-02	4.94E-04	7.93E-04	1.29E-02	4.90E-04
12	BULK09	311	rev checkerboard	P	3.01E-06	2.91E-06	1.17E-03	7.69E-04	1.27E-02	1.15E-03	7.96E-04	1.29E-02	1.14E-03
ann	BULK09	annealing*	rev checkerboard	P	1.22E-05	2.64E-06	6.30E-04	7.77E-04	1.27E-02	6.19E-04	8.04E-04	1.29E-02	6.13E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK09	0	all 1	P	2.70E-06	6.80E-07	1.59E-06	2.30E-06	1.37E-02	1.89E-06	2.62E-06	1.54E-02	1.86E-06
1	BULK09	11	all 1	P	1.89E-06	-4.30E-08	1.23E-06	1.69E-06	1.37E-02	1.18E-06	1.81E-06	1.53E-02	1.12E-06
2	BULK09	18	all 1	P	1.78E-06	4.34E-07	1.68E-06	1.94E-06	1.37E-02	1.65E-06	2.09E-06	1.53E-02	1.78E-06
3	BULK09	28	all 1	P	2.04E-06	3.92E-07	1.99E-06	2.10E-06	1.37E-02	1.64E-06	2.01E-06	1.53E-02	1.90E-06
4	BULK09	47	all 1	P	1.78E-06	1.79E-07	1.75E-06	1.92E-06	1.36E-02	1.90E-06	2.17E-06	1.53E-02	1.77E-06
5	BULK09	67	all 1	P	1.88E-06	9.50E-08	2.11E-06	1.68E-06	1.36E-02	2.05E-06	1.75E-06	1.53E-02	2.03E-06
6	BULK09	99	all 1	P	1.96E-06	3.47E-07	2.38E-06	2.05E-06	1.36E-02	2.23E-06	1.91E-06	1.53E-02	2.15E-06
6bis	BULK09	99	all 1	P	1.50E-06	2.63E-07	2.12E-06	1.77E-06	1.36E-02	2.30E-06	1.98E-06	1.53E-02	2.46E-06
7	BULK09	111	all 1	P	1.68E-06	2.63E-07	3.45E-06	1.65E-06	1.36E-02	3.49E-06	1.80E-06	1.53E-02	3.22E-06
8	BULK09	160	all 1	P	1.44E-06	1.91E-07	1.56E-04	1.59E-06	1.36E-02	1.53E-04	1.59E-06	1.52E-02	1.52E-04
9	BULK09	189	all 1	P	1.45E-06	1.40E-08	9.01E-05	1.36E-06	1.35E-02	8.92E-05	1.67E-06	1.52E-02	8.87E-05
10	BULK09	226	all 1	P	1.67E-06	8.42E-07	4.56E-04	1.64E-06	1.36E-02	4.51E-04	1.39E-06	1.52E-02	4.47E-04
11	BULK09	266	all 1	P	1.91E-06	7.26E-07	5.00E-04	1.78E-06	1.35E-02	4.94E-04	2.27E-06	1.52E-02	4.93E-04
12	BULK09	311	all 1	P	5.25E-06	3.31E-06	1.16E-03	5.27E-06	1.35E-02	1.15E-03	5.52E-06	1.52E-02	1.14E-03
ann	BULK09	annealing*	all 1	P	2.27E-05	3.23E-06	6.18E-04	2.31E-05	1.35E-02	6.13E-04	2.33E-05	1.52E-02	6.08E-04

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK10	0	all 0	P	2.11E-06	4.51E-07	4.03E-07	3.39E-05	1.05E-02	4.78E-07	3.27E-05	1.12E-02	3.07E-07
1	BULK10	11	all 0	P	2.01E-06	2.47E-07	1.00E-09	3.26E-05	1.05E-02	-2.80E-07	3.09E-05	1.11E-02	-3.66E-07
2	BULK10	18	all 0	P	2.11E-06	6.17E-07	2.62E-07	3.27E-05	1.05E-02	1.04E-07	3.12E-05	1.11E-02	3.40E-08
3	BULK10	28	all 0	P	2.10E-06	5.81E-07	3.52E-07	3.31E-05	1.05E-02	3.97E-07	3.14E-05	1.11E-02	-1.90E-08
4	BULK10	47	all 0	P	1.95E-06	3.39E-07	3.05E-07	3.21E-05	1.04E-02	6.00E-09	3.09E-05	1.11E-02	-1.79E-07
5	BULK10	67	all 0	P	1.20E-06	1.60E-07	-1.22E-07	3.21E-05	1.04E-02	-4.66E-07	3.05E-05	1.11E-02	-6.40E-07
6	BULK10	99	all 0	P	2.18E-06	6.46E-07	6.92E-07	3.25E-05	1.04E-02	4.38E-07	3.09E-05	1.11E-02	4.18E-07
6bis	BULK10	99	all 0	P	1.94E-06	4.52E-07	7.38E-07	3.24E-05	1.04E-02	5.30E-07	3.07E-05	1.11E-02	4.90E-07
7	BULK10	111	all 0	P	1.90E-06	4.25E-07	7.54E-07	3.24E-05	1.04E-02	5.15E-07	3.11E-05	1.11E-02	7.10E-07
8	BULK10	160	all 0	P	1.81E-06	2.86E-07	3.26E-06	3.19E-05	1.04E-02	2.89E-06	3.06E-05	1.11E-02	3.10E-06
9	BULK10	189	all 0	P	5.61E-07	-1.92E-07	2.29E-06	3.05E-05	1.04E-02	1.96E-06	2.92E-05	1.11E-02	1.94E-06
10	BULK10	226	all 0	P	6.75E-07	-3.60E-08	7.31E-06	3.10E-05	1.04E-02	7.10E-06	2.95E-05	1.11E-02	6.86E-06
11	BULK10	266	all 0	P	7.65E-07	-3.00E-07	9.62E-06	3.03E-05	1.04E-02	9.43E-06	2.89E-05	1.11E-02	9.20E-06
12	BULK10	311	all 0	P	-4.87E-07	-4.45E-07	1.66E-05	3.00E-05	1.04E-02	1.64E-05	2.89E-05	1.11E-02	1.64E-05
ann	BULK10	annealing*	all 0	P	1.95E-06	4.83E-07	1.67E-05	3.15E-05	1.04E-02	1.64E-05	3.07E-05	1.11E-02	1.64E-05

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK10	0	checkerboard	P	2.04E-06	3.70E-07	7.31E-07	7.74E-04	1.29E-02	7.47E-07	7.99E-04	1.32E-02	6.47E-07
1	BULK10	11	checkerboard	P	1.55E-06	9.00E-08	-1.37E-07	7.72E-04	1.29E-02	1.25E-07	7.97E-04	1.32E-02	-3.00E-09
2	BULK10	18	checkerboard	P	1.50E-06	2.40E-07	3.36E-07	7.72E-04	1.29E-02	3.29E-07	7.98E-04	1.32E-02	3.61E-07
3	BULK10	28	checkerboard	P	1.55E-06	2.10E-07	4.19E-07	7.72E-04	1.29E-02	3.11E-07	7.98E-04	1.32E-02	4.70E-07
4	BULK10	47	checkerboard	P	1.39E-06	1.96E-07	3.11E-07	7.71E-04	1.29E-02	3.30E-07	7.97E-04	1.31E-02	3.56E-07
5	BULK10	67	checkerboard	P	5.44E-07	-5.18E-07	-2.54E-07	7.71E-04	1.29E-02	-2.41E-07	7.97E-04	1.31E-02	2.30E-08
6	BULK10	99	checkerboard	P	1.70E-06	2.51E-07	9.82E-07	7.72E-04	1.29E-02	9.09E-07	7.98E-04	1.31E-02	8.96E-07
6bis	BULK10	99	checkerboard	P	1.65E-06	3.45E-07	8.30E-07	7.72E-04	1.29E-02	8.29E-07	7.98E-04	1.31E-02	8.02E-07
7	BULK10	111	checkerboard	P	1.65E-06	1.68E-07	9.64E-07	7.72E-04	1.29E-02	9.50E-07	7.98E-04	1.31E-02	1.09E-06
8	BULK10	160	checkerboard	P	1.70E-06	1.60E-07	3.60E-06	7.70E-04	1.29E-02	3.46E-06	7.97E-04	1.31E-02	3.56E-06
9	BULK10	189	checkerboard	P	1.91E-07	-3.79E-07	2.17E-06	7.68E-04	1.28E-02	2.58E-06	7.94E-04	1.31E-02	2.65E-06
10	BULK10	226	checkerboard	P	5.61E-07	-3.26E-07	7.22E-06	7.69E-04	1.28E-02	7.35E-06	7.96E-04	1.31E-02	7.55E-06
11	BULK10	266	checkerboard	P	7.32E-07	-3.66E-07	9.47E-06	7.67E-04	1.28E-02	9.42E-06	7.94E-04	1.30E-02	9.45E-06
12	BULK10	311	checkerboard	P	-1.48E-07	-3.99E-07	1.68E-05	7.68E-04	1.28E-02	1.69E-05	7.95E-04	1.30E-02	1.71E-05
ann	BULK10	annealing*	checkerboard	P	1.60E-06	2.26E-07	1.64E-05	7.69E-04	1.28E-02	1.63E-05	7.95E-04	1.30E-02	1.61E-05

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK10	0	rev checkerboard	P	2.25E-06	5.85E-07	6.10E-07	7.75E-04	1.29E-02	5.91E-07	8.00E-04	1.32E-02	6.77E-07
1	BULK10	11	rev checkerboard	P	1.48E-06	-4.10E-08	6.00E-09	7.73E-04	1.29E-02	1.70E-08	7.98E-04	1.32E-02	-4.30E-08
2	BULK10	18	rev checkerboard	P	1.59E-06	2.86E-07	6.20E-08	7.73E-04	1.29E-02	2.00E-07	7.98E-04	1.32E-02	9.40E-08
3	BULK10	28	rev checkerboard	P	1.98E-06	2.51E-07	2.62E-07	7.73E-04	1.29E-02	1.59E-07	7.99E-04	1.32E-02	3.13E-07
4	BULK10	47	rev checkerboard	P	1.62E-06	1.26E-07	1.70E-07	7.72E-04	1.29E-02	1.79E-07	7.97E-04	1.31E-02	1.97E-07
5	BULK10	67	rev checkerboard	P	8.21E-07	-2.73E-07	-3.87E-07	7.72E-04	1.29E-02	-3.12E-07	7.98E-04	1.31E-02	-1.84E-07
6	BULK10	99	rev checkerboard	P	1.83E-06	3.11E-07	6.44E-07	7.72E-04	1.29E-02	7.65E-07	7.98E-04	1.31E-02	6.79E-07
6bis	BULK10	99	rev checkerboard	P	1.77E-06	3.02E-07	6.64E-07	7.72E-04	1.29E-02	6.28E-07	7.98E-04	1.31E-02	6.02E-07
7	BULK10	111	rev checkerboard	P	1.64E-06	2.74E-07	6.73E-07	7.73E-04	1.29E-02	7.33E-07	7.99E-04	1.31E-02	8.11E-07
8	BULK10	160	rev checkerboard	P	1.48E-06	9.80E-08	3.10E-06	7.71E-04	1.28E-02	3.34E-06	7.97E-04	1.31E-02	3.23E-06
9	BULK10	189	rev checkerboard	P	1.07E-06	-1.59E-07	2.41E-06	7.69E-04	1.28E-02	2.67E-06	7.95E-04	1.30E-02	2.77E-06
10	BULK10	226	rev checkerboard	P	1.17E-06	1.25E-07	7.73E-06	7.70E-04	1.28E-02	7.80E-06	7.96E-04	1.31E-02	7.66E-06
11	BULK10	266	rev checkerboard	P	8.74E-07	-3.40E-07	9.33E-06	7.68E-04	1.28E-02	9.57E-06	7.94E-04	1.30E-02	9.47E-06
12	BULK10	311	rev checkerboard	P	5.23E-07	5.70E-08	1.73E-05	7.70E-04	1.28E-02	1.76E-05	7.96E-04	1.30E-02	1.73E-05
ann	BULK10	annealing*	rev checkerboard	P	1.37E-06	1.06E-07	1.66E-05	7.70E-04	1.28E-02	1.65E-05	7.96E-04	1.30E-02	1.67E-05

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK10	0	all 1	P	2.61E-06	5.84E-07	8.40E-07	2.16E-06	1.39E-02	8.23E-07	2.38E-06	1.56E-02	1.14E-06
1	BULK10	11	all 1	P	1.79E-06	-1.20E-08	3.78E-07	1.57E-06	1.39E-02	2.99E-07	1.62E-06	1.56E-02	5.21E-07
2	BULK10	18	all 1	P	1.89E-06	3.57E-07	6.46E-07	1.92E-06	1.39E-02	5.14E-07	1.85E-06	1.56E-02	5.44E-07
3	BULK10	28	all 1	P	1.67E-06	3.53E-07	6.16E-07	1.77E-06	1.39E-02	6.34E-07	1.99E-06	1.56E-02	7.02E-07
4	BULK10	47	all 1	P	1.75E-06	2.24E-07	5.21E-07	1.75E-06	1.38E-02	6.82E-07	1.85E-06	1.55E-02	6.64E-07
5	BULK10	67	all 1	P	1.37E-06	-2.80E-07	1.74E-07	1.20E-06	1.38E-02	5.82E-07	1.54E-06	1.55E-02	5.64E-07
6	BULK10	99	all 1	P	2.18E-06	5.23E-07	1.26E-06	1.98E-06	1.38E-02	1.55E-06	2.14E-06	1.55E-02	1.29E-06
6bis	BULK10	99	all 1	P	1.81E-06	2.32E-07	1.04E-06	1.86E-06	1.38E-02	9.47E-07	1.98E-06	1.55E-02	1.18E-06
7	BULK10	111	all 1	P	1.79E-06	3.98E-07	1.32E-06	1.85E-06	1.38E-02	1.20E-06	1.87E-06	1.55E-02	1.41E-06
8	BULK10	160	all 1	P	1.79E-06	3.00E-08	3.75E-06	1.88E-06	1.38E-02	3.92E-06	1.78E-06	1.55E-02	3.58E-06
9	BULK10	189	all 1	P	1.35E-06	3.10E-08	3.08E-06	1.42E-06	1.37E-02	3.33E-06	1.58E-06	1.54E-02	3.22E-06
10	BULK10	226	all 1	P	1.57E-06	1.28E-07	8.21E-06	1.09E-06	1.37E-02	7.80E-06	1.33E-06	1.54E-02	8.20E-06
11	BULK10	266	all 1	P	1.52E-06	-2.06E-07	1.03E-05	1.30E-06	1.37E-02	1.01E-05	1.59E-06	1.54E-02	1.02E-05
12	BULK10	311	all 1	P	1.12E-06	1.22E-07	1.81E-05	1.57E-06	1.37E-02	1.81E-05	1.49E-06	1.54E-02	1.83E-05
ann	BULK10	annealing*	all 1	P	1.92E-06	4.39E-07	1.70E-05	1.88E-06	1.37E-02	1.72E-05	2.05E-06	1.54E-02	1.71E-05

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK11	0	all 0	P	2.13E-06	5.32E-07	2.58E-06	3.35E-05	1.03E-02	2.43E-06	3.21E-05	1.10E-02	2.34E-06
1	BULK11	11	all 0	P	1.55E-06	3.10E-08	2.40E-06	3.25E-05	1.03E-02	1.77E-06	3.07E-05	1.10E-02	1.61E-06
2	BULK11	18	all 0	P	1.61E-06	6.33E-07	2.67E-06	3.27E-05	1.03E-02	2.55E-06	3.13E-05	1.10E-02	2.39E-06
3	BULK11	28	all 0	P	1.93E-06	4.32E-07	2.83E-06	3.28E-05	1.03E-02	2.83E-06	3.12E-05	1.10E-02	2.78E-06
4	BULK11	47	all 0	P	1.88E-06	2.63E-07	3.00E-06	3.23E-05	1.03E-02	2.77E-06	3.08E-05	1.10E-02	2.49E-06
5	BULK11	67	all 0	P	1.36E-06	1.68E-07	2.74E-06	3.20E-05	1.03E-02	2.46E-06	3.05E-05	1.10E-02	2.56E-06
6	BULK11	99	all 0	P	2.42E-06	5.95E-07	3.72E-06	3.27E-05	1.03E-02	3.25E-06	3.10E-05	1.10E-02	3.29E-06
6bis	BULK11	99	all 0	P	2.04E-06	4.52E-07	3.13E-06	3.22E-05	1.03E-02	3.00E-06	3.08E-05	1.10E-02	2.91E-06
7	BULK11	111	all 0	P	1.89E-06	5.66E-07	3.42E-06	3.21E-05	1.03E-02	3.21E-06	3.09E-05	1.10E-02	3.07E-06
8	BULK11	160	all 0	P	1.77E-06	3.18E-07	4.58E-06	3.20E-05	1.03E-02	4.56E-06	3.06E-05	1.09E-02	4.40E-06
9	BULK11	189	all 0	P	4.65E-07	-1.26E-07	3.76E-06	3.03E-05	1.03E-02	3.43E-06	2.91E-05	1.09E-02	3.42E-06
10	BULK11	226	all 0	P	-9.14E-07	-8.90E-07	5.90E-06	2.92E-05	1.03E-02	6.00E-06	2.82E-05	1.09E-02	6.06E-06
11	BULK11	266	all 0	P	1.44E-06	1.10E-07	8.93E-06	3.02E-05	1.03E-02	8.43E-06	2.90E-05	1.09E-02	8.30E-06
12	BULK11	311	all 0	P	1.31E-06	2.33E-07	1.44E-05	3.08E-05	1.03E-02	1.43E-05	2.96E-05	1.09E-02	1.42E-05
ann	BULK11	annealing*	all 0	P	1.49E-06	3.11E-07	1.41E-05	3.08E-05	1.02E-02	1.39E-05	2.96E-05	1.09E-02	1.39E-05

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK11	0	checkerboard	P	1.92E-06	6.19E-07	1.47E-06	7.71E-04	1.28E-02	1.80E-06	7.98E-04	1.30E-02	1.38E-06
1	BULK11	11	checkerboard	P	7.72E-07	-3.25E-07	4.42E-07	7.69E-04	1.27E-02	6.78E-07	7.97E-04	1.30E-02	6.03E-07
2	BULK11	18	checkerboard	P	1.42E-06	3.81E-07	1.04E-06	7.69E-04	1.27E-02	1.18E-06	7.97E-04	1.30E-02	1.41E-06
3	BULK11	28	checkerboard	P	1.52E-06	3.03E-07	1.74E-06	7.69E-04	1.27E-02	1.68E-06	7.97E-04	1.30E-02	1.61E-06
4	BULK11	47	checkerboard	P	1.47E-06	-3.70E-08	1.61E-06	7.68E-04	1.27E-02	1.78E-06	7.97E-04	1.29E-02	1.95E-06
5	BULK11	67	checkerboard	P	1.01E-06	-5.90E-08	1.64E-06	7.69E-04	1.27E-02	1.32E-06	7.97E-04	1.29E-02	1.36E-06
6	BULK11	99	checkerboard	P	1.95E-06	5.09E-07	2.20E-06	7.68E-04	1.27E-02	1.92E-06	7.97E-04	1.29E-02	2.19E-06
6bis	BULK11	99	checkerboard	P	1.37E-06	1.19E-07	2.04E-06	7.68E-04	1.27E-02	1.96E-06	7.97E-04	1.29E-02	2.01E-06
7	BULK11	111	checkerboard	P	1.66E-06	1.93E-07	2.01E-06	7.69E-04	1.27E-02	2.10E-06	7.97E-04	1.29E-02	2.16E-06
8	BULK11	160	checkerboard	P	1.31E-06	6.30E-08	3.44E-06	7.67E-04	1.27E-02	3.58E-06	7.96E-04	1.29E-02	3.42E-06
9	BULK11	189	checkerboard	P	8.53E-07	-1.89E-07	2.90E-06	7.65E-04	1.26E-02	2.96E-06	7.94E-04	1.29E-02	3.38E-06
10	BULK11	226	checkerboard	P	-4.69E-07	-7.33E-07	5.50E-06	7.64E-04	1.26E-02	5.63E-06	7.94E-04	1.29E-02	5.91E-06
11	BULK11	266	checkerboard	P	9.15E-07	-1.01E-07	7.50E-06	7.64E-04	1.26E-02	7.64E-06	7.93E-04	1.28E-02	7.75E-06
12	BULK11	311	checkerboard	P	7.58E-07	-3.60E-08	1.36E-05	7.66E-04	1.26E-02	1.38E-05	7.95E-04	1.29E-02	1.39E-05
ann	BULK11	annealing*	checkerboard	P	1.08E-06	-1.24E-07	1.31E-05	7.65E-04	1.26E-02	1.34E-05	7.94E-04	1.28E-02	1.32E-05

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK11	0	rev checkerboard	P	2.03E-06	4.27E-07	2.43E-06	7.71E-04	1.28E-02	2.08E-06	7.99E-04	1.30E-02	2.03E-06
1	BULK11	11	rev checkerboard	P	1.12E-06	-2.71E-07	1.47E-06	7.70E-04	1.27E-02	1.62E-06	7.98E-04	1.30E-02	1.86E-06
2	BULK11	18	rev checkerboard	P	1.59E-06	4.36E-07	2.21E-06	7.70E-04	1.27E-02	2.33E-06	7.98E-04	1.30E-02	2.50E-06
3	BULK11	28	rev checkerboard	P	1.66E-06	2.14E-07	2.41E-06	7.70E-04	1.27E-02	2.64E-06	7.98E-04	1.30E-02	2.44E-06
4	BULK11	47	rev checkerboard	P	1.60E-06	2.15E-07	2.38E-06	7.69E-04	1.27E-02	2.38E-06	7.97E-04	1.29E-02	2.58E-06
5	BULK11	67	rev checkerboard	P	1.37E-06	3.40E-08	2.24E-06	7.70E-04	1.27E-02	2.39E-06	7.98E-04	1.29E-02	2.49E-06
6	BULK11	99	rev checkerboard	P	2.04E-06	2.69E-07	2.92E-06	7.69E-04	1.27E-02	2.98E-06	7.98E-04	1.29E-02	2.87E-06
6bis	BULK11	99	rev checkerboard	P	1.75E-06	2.19E-07	2.45E-06	7.69E-04	1.27E-02	2.58E-06	7.97E-04	1.29E-02	2.80E-06
7	BULK11	111	rev checkerboard	P	1.81E-06	3.23E-07	2.79E-06	7.70E-04	1.27E-02	2.92E-06	7.98E-04	1.29E-02	3.02E-06
8	BULK11	160	rev checkerboard	P	1.42E-06	1.71E-07	4.40E-06	7.68E-04	1.27E-02	4.15E-06	7.96E-04	1.29E-02	3.99E-06
9	BULK11	189	rev checkerboard	P	1.36E-06	-4.50E-08	3.58E-06	7.66E-04	1.26E-02	3.84E-06	7.94E-04	1.29E-02	3.75E-06
10	BULK11	226	rev checkerboard	P	5.90E-07	-2.65E-07	6.64E-06	7.66E-04	1.26E-02	6.72E-06	7.95E-04	1.29E-02	6.63E-06
11	BULK11	266	rev checkerboard	P	1.31E-06	-7.00E-08	8.28E-06	7.65E-04	1.26E-02	8.46E-06	7.94E-04	1.28E-02	8.58E-06
12	BULK11	311	rev checkerboard	P	1.26E-06	3.94E-07	1.47E-05	7.67E-04	1.26E-02	1.46E-05	7.96E-04	1.28E-02	1.48E-05
ann	BULK11	annealing*	rev checkerboard	P	1.55E-06	1.24E-07	1.36E-05	7.66E-04	1.26E-02	1.37E-05	7.95E-04	1.28E-02	1.37E-05

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK11	0	all 1	P	2.13E-06	5.40E-07	1.42E-06	2.12E-06	1.37E-02	1.17E-06	2.03E-06	1.54E-02	9.94E-07
1	BULK11	11	all 1	P	1.93E-06	-1.79E-07	7.05E-07	1.30E-06	1.36E-02	5.34E-07	1.56E-06	1.53E-02	6.51E-07
2	BULK11	18	all 1	P	2.11E-06	4.11E-07	1.26E-06	2.13E-06	1.36E-02	1.20E-06	1.79E-06	1.53E-02	1.25E-06
3	BULK11	28	all 1	P	1.80E-06	2.15E-07	1.45E-06	1.91E-06	1.36E-02	1.67E-06	2.14E-06	1.53E-02	1.66E-06
4	BULK11	47	all 1	P	1.86E-06	1.25E-07	1.38E-06	2.00E-06	1.36E-02	1.43E-06	1.87E-06	1.53E-02	1.37E-06
5	BULK11	67	all 1	P	1.57E-06	1.48E-07	1.37E-06	1.36E-06	1.36E-02	1.25E-06	1.71E-06	1.53E-02	1.38E-06
6	BULK11	99	all 1	P	2.08E-06	4.37E-07	1.90E-06	2.00E-06	1.36E-02	1.76E-06	2.04E-06	1.52E-02	1.80E-06
6bis	BULK11	99	all 1	P	1.77E-06	2.56E-07	1.63E-06	1.90E-06	1.36E-02	1.86E-06	1.70E-06	1.53E-02	1.73E-06
7	BULK11	111	all 1	P	2.03E-06	4.36E-07	1.82E-06	1.98E-06	1.36E-02	1.75E-06	1.96E-06	1.53E-02	1.88E-06
8	BULK11	160	all 1	P	1.62E-06	1.70E-08	3.10E-06	1.74E-06	1.36E-02	3.28E-06	1.50E-06	1.52E-02	3.38E-06
9	BULK11	189	all 1	P	1.56E-06	-4.00E-09	3.02E-06	1.63E-06	1.35E-02	3.05E-06	1.57E-06	1.52E-02	3.08E-06
10	BULK11	226	all 1	P	1.12E-06	6.80E-08	6.20E-06	1.28E-06	1.35E-02	6.38E-06	1.51E-06	1.52E-02	6.46E-06
11	BULK11	266	all 1	P	1.83E-06	3.88E-07	7.88E-06	1.52E-06	1.35E-02	7.82E-06	1.73E-06	1.52E-02	7.85E-06
12	BULK11	311	all 1	P	1.81E-06	3.76E-07	1.42E-05	1.70E-06	1.35E-02	1.40E-05	1.88E-06	1.52E-02	1.42E-05
ann	BULK11	annealing*	all 1	P	1.87E-06	1.37E-07	1.35E-05	1.80E-06	1.35E-02	1.35E-05	1.70E-06	1.52E-02	1.34E-05

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK12	0	all 0	P	1.52E-06	2.04E-07	2.53E-06	3.36E-05	1.04E-02	2.39E-06	3.23E-05	1.11E-02	2.40E-06
1	BULK12	11	all 0	P	1.56E-06	-8.50E-08	2.09E-06	3.23E-05	1.04E-02	1.90E-06	3.06E-05	1.11E-02	1.80E-06
2	BULK12	18	all 0	P	1.88E-06	4.57E-07	2.49E-06	3.28E-05	1.04E-02	2.44E-06	3.13E-05	1.11E-02	2.46E-06
3	BULK12	28	all 0	P	1.96E-06	3.17E-07	2.29E-06	3.28E-05	1.04E-02	2.02E-06	3.15E-05	1.11E-02	2.11E-06
4	BULK12	47	all 0	P	2.16E-06	4.05E-07	2.83E-06	3.27E-05	1.04E-02	2.47E-06	3.10E-05	1.11E-02	2.25E-06
5	BULK12	67	all 0	P	1.71E-06	1.62E-07	2.70E-06	3.26E-05	1.04E-02	2.47E-06	3.14E-05	1.11E-02	2.31E-06
6	BULK12	99	all 0	P	2.15E-06	3.56E-07	2.52E-06	3.23E-05	1.04E-02	2.20E-06	3.10E-05	1.11E-02	2.39E-06
6bis	BULK12	99	all 0	P	1.63E-06	2.51E-07	2.73E-06	3.26E-05	1.04E-02	2.26E-06	3.08E-05	1.11E-02	2.29E-06
7	BULK12	111	all 0	P	1.96E-06	2.18E-07	2.57E-06	3.29E-05	1.04E-02	2.57E-06	3.16E-05	1.11E-02	2.54E-06
8	BULK12	160	all 0	P	1.49E-06	-2.93E-07	2.00E-06	3.22E-05	1.04E-02	1.90E-06	3.09E-05	1.11E-02	1.80E-06
9	BULK12	189	all 0	P	8.81E-07	-1.75E-07	1.99E-06	3.10E-05	1.04E-02	1.81E-06	2.99E-05	1.11E-02	1.71E-06
10	BULK12	226	all 0	P	9.96E-07	-5.79E-07	1.54E-06	3.16E-05	1.04E-02	1.69E-06	3.03E-05	1.11E-02	1.50E-06
11	BULK12	266	all 0	P	1.31E-06	-6.30E-08	1.96E-06	3.11E-05	1.04E-02	1.65E-06	2.98E-05	1.11E-02	1.56E-06
12	BULK12	311	all 0	P	1.30E-06	-1.10E-07	2.29E-06	3.20E-05	1.04E-02	2.16E-06	3.05E-05	1.11E-02	1.78E-06
ann	BULK12	annealing*	all 0	P	1.77E-06	2.46E-07	2.53E-06	3.26E-05	1.04E-02	2.36E-06	3.11E-05	1.11E-02	2.39E-06

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK12	0	checkerboard	P	1.98E-06	2.82E-07	2.59E-06	7.71E-04	1.28E-02	2.65E-06	7.94E-04	1.31E-02	2.58E-06
1	BULK12	11	checkerboard	P	1.13E-06	-1.65E-07	1.97E-06	7.68E-04	1.28E-02	2.13E-06	7.93E-04	1.30E-02	2.05E-06
2	BULK12	18	checkerboard	P	1.54E-06	2.73E-07	2.39E-06	7.70E-04	1.28E-02	2.29E-06	7.94E-04	1.31E-02	2.49E-06
3	BULK12	28	checkerboard	P	1.61E-06	1.34E-07	2.08E-06	7.70E-04	1.28E-02	2.17E-06	7.94E-04	1.31E-02	2.18E-06
4	BULK12	47	checkerboard	P	1.46E-06	1.69E-07	2.33E-06	7.69E-04	1.28E-02	2.38E-06	7.93E-04	1.30E-02	2.30E-06
5	BULK12	67	checkerboard	P	1.55E-06	1.47E-07	2.55E-06	7.69E-04	1.28E-02	2.53E-06	7.94E-04	1.31E-02	2.57E-06
6	BULK12	99	checkerboard	P	1.30E-06	4.60E-08	2.32E-06	7.69E-04	1.28E-02	2.64E-06	7.93E-04	1.30E-02	2.51E-06
6bis	BULK12	99	checkerboard	P	1.23E-06	-1.20E-08	2.44E-06	7.69E-04	1.28E-02	2.38E-06	7.94E-04	1.31E-02	2.55E-06
7	BULK12	111	checkerboard	P	1.42E-06	1.13E-07	2.52E-06	7.69E-04	1.28E-02	2.55E-06	7.94E-04	1.31E-02	2.47E-06
8	BULK12	160	checkerboard	P	1.01E-06	-1.20E-07	2.26E-06	7.68E-04	1.28E-02	1.94E-06	7.92E-04	1.31E-02	1.92E-06
9	BULK12	189	checkerboard	P	7.47E-07	-3.54E-07	1.90E-06	7.66E-04	1.28E-02	1.93E-06	7.90E-04	1.30E-02	1.97E-06
10	BULK12	226	checkerboard	P	3.57E-07	-1.01E-06	1.47E-06	7.67E-04	1.28E-02	1.76E-06	7.91E-04	1.31E-02	1.76E-06
11	BULK12	266	checkerboard	P	6.28E-07	-6.10E-07	1.80E-06	7.66E-04	1.28E-02	2.07E-06	7.90E-04	1.30E-02	1.97E-06
12	BULK12	311	checkerboard	P	7.62E-07	-3.58E-07	2.25E-06	7.67E-04	1.28E-02	2.08E-06	7.92E-04	1.31E-02	2.11E-06
ann	BULK12	annealing*	checkerboard	P	1.57E-06	5.00E-09	2.11E-06	7.67E-04	1.28E-02	2.36E-06	7.91E-04	1.30E-02	2.41E-06

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK12	0	rev checkerboard	P	2.21E-06	2.80E-07	9.33E-07	7.72E-04	1.28E-02	8.67E-07	7.95E-04	1.30E-02	8.11E-07
1	BULK12	11	rev checkerboard	P	1.33E-06	-2.18E-07	2.95E-07	7.69E-04	1.28E-02	3.78E-07	7.93E-04	1.30E-02	5.03E-07
2	BULK12	18	rev checkerboard	P	1.74E-06	3.48E-07	7.55E-07	7.71E-04	1.28E-02	1.03E-06	7.95E-04	1.30E-02	9.92E-07
3	BULK12	28	rev checkerboard	P	2.03E-06	4.07E-07	1.06E-06	7.71E-04	1.28E-02	9.55E-07	7.95E-04	1.30E-02	1.10E-06
4	BULK12	47	rev checkerboard	P	1.62E-06	2.53E-07	4.91E-07	7.69E-04	1.28E-02	7.36E-07	7.93E-04	1.30E-02	7.51E-07
5	BULK12	67	rev checkerboard	P	1.86E-06	1.39E-07	7.19E-07	7.70E-04	1.28E-02	7.33E-07	7.94E-04	1.30E-02	9.12E-07
6	BULK12	99	rev checkerboard	P	1.79E-06	2.42E-07	7.95E-07	7.70E-04	1.28E-02	8.29E-07	7.94E-04	1.30E-02	8.56E-07
6bis	BULK12	99	rev checkerboard	P	1.53E-06	2.55E-07	7.22E-07	7.70E-04	1.28E-02	6.97E-07	7.94E-04	1.30E-02	7.67E-07
7	BULK12	111	rev checkerboard	P	1.68E-06	2.24E-07	6.75E-07	7.70E-04	1.28E-02	8.00E-07	7.94E-04	1.31E-02	7.99E-07
8	BULK12	160	rev checkerboard	P	1.13E-06	-5.80E-08	5.37E-07	7.69E-04	1.28E-02	9.90E-08	7.93E-04	1.31E-02	4.61E-07
9	BULK12	189	rev checkerboard	P	1.25E-06	-1.35E-07	4.10E-07	7.67E-04	1.28E-02	5.62E-07	7.91E-04	1.30E-02	6.28E-07
10	BULK12	226	rev checkerboard	P	8.35E-07	-4.61E-07	3.44E-07	7.68E-04	1.28E-02	5.90E-08	7.92E-04	1.30E-02	-4.78E-07
11	BULK12	266	rev checkerboard	P	1.21E-06	-3.56E-07	1.80E-07	7.66E-04	1.28E-02	4.46E-07	7.91E-04	1.30E-02	5.77E-07
12	BULK12	311	rev checkerboard	P	1.44E-06	-6.70E-08	4.78E-07	7.68E-04	1.28E-02	6.65E-07	7.92E-04	1.30E-02	7.46E-07
ann	BULK12	annealing*	rev checkerboard	P	1.33E-06	-2.80E-08	7.22E-07	7.68E-04	1.28E-02	9.01E-07	7.92E-04	1.30E-02	7.40E-07

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK12	0	all 1	P	1.77E-06	2.84E-07	1.08E-06	1.96E-06	1.37E-02	1.03E-06	2.14E-06	1.54E-02	9.96E-07
1	BULK12	11	all 1	P	1.76E-06	2.30E-08	4.86E-07	1.74E-06	1.37E-02	5.53E-07	1.80E-06	1.54E-02	5.81E-07
2	BULK12	18	all 1	P	2.24E-06	5.32E-07	1.02E-06	1.86E-06	1.37E-02	1.02E-06	2.05E-06	1.54E-02	1.00E-06
3	BULK12	28	all 1	P	2.09E-06	3.61E-07	1.04E-06	2.22E-06	1.37E-02	1.08E-06	2.07E-06	1.54E-02	1.05E-06
4	BULK12	47	all 1	P	1.90E-06	1.74E-07	6.66E-07	1.73E-06	1.37E-02	8.08E-07	2.05E-06	1.54E-02	7.99E-07
5	BULK12	67	all 1	P	2.04E-06	3.69E-07	8.27E-07	2.30E-06	1.37E-02	1.01E-06	1.99E-06	1.54E-02	1.05E-06
6	BULK12	99	all 1	P	2.04E-06	2.64E-07	7.96E-07	1.88E-06	1.37E-02	7.96E-07	1.90E-06	1.54E-02	1.02E-06
6bis	BULK12	99	all 1	P	1.77E-06	1.16E-07	5.79E-07	1.72E-06	1.37E-02	9.29E-07	1.91E-06	1.54E-02	9.25E-07
7	BULK12	111	all 1	P	1.74E-06	2.81E-07	8.83E-07	2.07E-06	1.37E-02	7.26E-07	1.74E-06	1.54E-02	9.47E-07
8	BULK12	160	all 1	P	1.55E-06	-1.91E-07	2.11E-07	9.60E-07	1.38E-02	7.10E-07	1.13E-06	1.55E-02	4.46E-07
9	BULK12	189	all 1	P	1.67E-06	5.90E-08	6.04E-07	1.51E-06	1.37E-02	6.88E-07	1.65E-06	1.54E-02	6.97E-07
10	BULK12	226	all 1	P	5.88E-07	-7.45E-07	1.22E-07	8.57E-07	1.37E-02	-2.32E-07	1.03E-06	1.54E-02	2.56E-07
11	BULK12	266	all 1	P	1.42E-06	-5.50E-08	5.52E-07	1.73E-06	1.37E-02	8.42E-07	1.53E-06	1.54E-02	7.17E-07
12	BULK12	311	all 1	P	1.57E-06	2.24E-07	6.66E-07	1.41E-06	1.37E-02	5.90E-07	1.52E-06	1.54E-02	5.94E-07
ann	BULK12	annealing*	all 1	P	1.73E-06	1.11E-07	8.48E-07	1.69E-06	1.37E-02	9.90E-07	1.84E-06	1.54E-02	1.21E-06

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK13	0	all 0	P	1.79E-06	1.90E-05	1.57E-06	3.50E-05	1.03E-02	1.41E-06	3.34E-05	1.10E-02	1.37E-06
6bis	BULK13	0	all 0	P	1.95E-06	1.92E-05	1.75E-06	3.46E-05	1.03E-02	1.63E-06	3.30E-05	1.10E-02	1.53E-06
7	BULK13	12	all 0	P	2.07E-06	1.91E-05	2.17E-06	3.43E-05	1.03E-02	2.00E-06	3.29E-05	1.10E-02	1.78E-06
8	BULK13	61	all 0	P	1.23E-06	1.74E-05	4.22E-06	3.35E-05	1.03E-02	3.96E-06	3.24E-05	1.10E-02	3.91E-06
9	BULK13	90	all 0	P	2.74E-07	1.62E-05	1.02E-05	3.20E-05	1.03E-02	9.86E-06	3.07E-05	1.10E-02	9.69E-06
10	BULK13	126	all 0	P	8.74E-07	1.59E-05	1.88E-04	3.29E-05	1.03E-02	1.84E-04	3.16E-05	1.10E-02	1.83E-04
11	BULK13	167	all 0	P	1.26E-06	1.55E-05	2.83E-04	3.25E-05	1.03E-02	2.79E-04	3.10E-05	1.09E-02	2.78E-04
12	BULK13	211	all 0	P	1.04E-06	1.66E-05	9.48E-04	3.28E-05	1.02E-02	9.38E-04	3.14E-05	1.09E-02	9.36E-04
13	BULK13	273	all 0	P	1.59E-06	1.74E-05	8.93E-04	3.24E-05	1.02E-02	8.93E-04	3.11E-05	1.09E-02	8.95E-04
14	BULK13	301	all 0	P	1.46E-06	1.99E-05	1.19E-03	3.34E-05	1.02E-02	1.19E-03	3.21E-05	1.09E-02	1.19E-03
ann	BULK13	annealing*	all 0	P	7.38E-07	1.43E-05	6.10E-04	3.20E-05	1.02E-02	6.06E-04	3.08E-05	1.09E-02	6.04E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK13	0	checkerboard	P	1.68E-06	1.93E-05	4.92E-06	7.76E-04	1.28E-02	5.21E-06	8.04E-04	1.31E-02	5.09E-06
6bis	BULK13	0	checkerboard	P	1.60E-06	1.92E-05	4.74E-06	7.74E-04	1.28E-02	4.98E-06	8.03E-04	1.31E-02	5.24E-06
7	BULK13	12	checkerboard	P	1.64E-06	1.87E-05	5.55E-06	7.74E-04	1.28E-02	5.89E-06	8.03E-04	1.31E-02	5.89E-06
8	BULK13	61	checkerboard	P	8.94E-07	1.71E-05	7.74E-06	7.72E-04	1.28E-02	8.15E-06	8.01E-04	1.31E-02	8.31E-06
9	BULK13	90	checkerboard	P	2.59E-07	1.58E-05	1.38E-05	7.69E-04	1.27E-02	1.39E-05	7.99E-04	1.30E-02	1.41E-05
10	BULK13	126	checkerboard	P	4.74E-07	1.56E-05	1.90E-04	7.71E-04	1.27E-02	1.86E-04	8.00E-04	1.30E-02	1.85E-04
11	BULK13	167	checkerboard	P	8.45E-07	1.52E-05	2.85E-04	7.70E-04	1.27E-02	2.82E-04	7.99E-04	1.30E-02	2.80E-04
12	BULK13	211	checkerboard	P	7.28E-07	1.67E-05	9.48E-04	7.71E-04	1.27E-02	9.37E-04	8.01E-04	1.30E-02	9.32E-04
13	BULK13	273	checkerboard	P	1.61E-06	1.76E-05	9.10E-04	7.71E-04	1.27E-02	9.05E-04	8.00E-04	1.29E-02	9.04E-04
14	BULK13	301	checkerboard	P	2.30E-06	2.05E-05	1.21E-03	7.73E-04	1.27E-02	1.20E-03	8.02E-04	1.30E-02	1.20E-03
ann	BULK13	annealing*	checkerboard	P	2.24E-06	1.41E-05	6.20E-04	7.72E-04	1.27E-02	6.13E-04	8.01E-04	1.29E-02	6.10E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK13	0	rev checkerboard	P	1.91E-06	1.92E-05	1.27E-06	7.77E-04	1.28E-02	1.14E-06	8.05E-04	1.31E-02	1.26E-06
6bis	BULK13	0	rev checkerboard	P	2.13E-06	1.92E-05	1.22E-06	7.75E-04	1.28E-02	8.94E-07	8.03E-04	1.31E-02	1.08E-06
7	BULK13	12	rev checkerboard	P	1.88E-06	1.89E-05	1.39E-06	7.75E-04	1.28E-02	1.34E-06	8.03E-04	1.31E-02	1.36E-06
8	BULK13	61	rev checkerboard	P	1.32E-06	1.75E-05	3.45E-06	7.74E-04	1.28E-02	3.35E-06	8.02E-04	1.31E-02	3.45E-06
9	BULK13	90	rev checkerboard	P	9.69E-07	1.63E-05	9.77E-06	7.71E-04	1.27E-02	9.84E-06	8.00E-04	1.30E-02	9.87E-06
10	BULK13	126	rev checkerboard	P	1.11E-06	1.58E-05	2.02E-04	7.72E-04	1.27E-02	1.97E-04	8.01E-04	1.30E-02	1.94E-04
11	BULK13	167	rev checkerboard	P	1.15E-06	1.53E-05	2.98E-04	7.71E-04	1.27E-02	2.92E-04	8.00E-04	1.30E-02	2.89E-04
12	BULK13	211	rev checkerboard	P	1.37E-06	1.64E-05	1.01E-03	7.72E-04	1.27E-02	9.91E-04	8.01E-04	1.30E-02	9.79E-04
13	BULK13	273	rev checkerboard	P	1.79E-06	1.75E-05	9.50E-04	7.72E-04	1.27E-02	9.37E-04	8.01E-04	1.29E-02	9.31E-04
14	BULK13	301	rev checkerboard	P	2.43E-06	2.06E-05	1.25E-03	7.74E-04	1.27E-02	1.23E-03	8.02E-04	1.30E-02	1.23E-03
ann	BULK13	annealing*	rev checkerboard	P	2.38E-06	1.48E-05	6.55E-04	7.73E-04	1.27E-02	6.42E-04	8.01E-04	1.29E-02	6.33E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	BULK13	0	all 1	P	2.00E-06	1.94E-05	4.44E-06	1.75E-06	1.39E-02	4.28E-06	1.66E-06	1.56E-02	4.38E-06
6bis	BULK13	0	all 1	P	2.12E-06	1.93E-05	4.53E-06	2.05E-06	1.38E-02	4.54E-06	1.92E-06	1.56E-02	4.41E-06
7	BULK13	12	all 1	P	1.94E-06	1.89E-05	4.78E-06	1.84E-06	1.38E-02	4.92E-06	1.82E-06	1.56E-02	4.83E-06
8	BULK13	61	all 1	P	1.46E-06	1.74E-05	7.42E-06	1.45E-06	1.38E-02	7.54E-06	1.75E-06	1.56E-02	7.40E-06
9	BULK13	90	all 1	P	1.24E-06	1.65E-05	1.40E-05	1.36E-06	1.37E-02	1.38E-05	1.41E-06	1.55E-02	1.38E-05
10	BULK13	126	all 1	P	1.22E-06	1.59E-05	2.01E-04	1.53E-06	1.37E-02	1.98E-04	1.67E-06	1.55E-02	1.97E-04
11	BULK13	167	all 1	P	1.56E-06	1.54E-05	3.03E-04	1.42E-06	1.37E-02	2.99E-04	1.58E-06	1.54E-02	2.97E-04
12	BULK13	211	all 1	P	1.80E-06	1.71E-05	1.01E-03	1.84E-06	1.37E-02	9.95E-04	1.82E-06	1.55E-02	9.90E-04
13	BULK13	273	all 1	P	2.34E-06	1.78E-05	9.63E-04	2.31E-06	1.37E-02	9.55E-04	2.64E-06	1.54E-02	9.51E-04
14	BULK13	301	all 1	P	3.59E-06	2.11E-05	1.26E-03	3.35E-06	1.37E-02	1.25E-03	3.62E-06	1.54E-02	1.25E-03
ann	BULK13	annealing*	all 1	P	4.34E-06	1.52E-05	6.47E-04	4.30E-06	1.37E-02	6.39E-04	4.09E-06	1.54E-02	6.33E-04

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6bis	BULK14	0	all 0	P	1.83E-06	4.06E-07	2.10E-06	3.08E-05	1.04E-02	2.33E-06	2.99E-05	1.10E-02	1.99E-06
7	BULK14	12	all 0	P	1.93E-06	2.60E-07	2.88E-06	3.09E-05	1.03E-02	2.78E-06	2.98E-05	1.10E-02	2.63E-06
8	BULK14	61	all 0	P	1.33E-06	2.40E-08	4.14E-06	3.00E-05	1.03E-02	4.13E-06	2.89E-05	1.10E-02	3.75E-06
9	BULK14	90	all 0	P	7.26E-07	-1.98E-07	7.76E-06	2.89E-05	1.03E-02	7.43E-06	2.77E-05	1.10E-02	7.60E-06
10	BULK14	126	all 0	P	2.54E-07	-3.88E-07	1.11E-04	2.90E-05	1.03E-02	1.10E-04	2.78E-05	1.10E-02	1.09E-04
11	BULK14	167	all 0	P	1.03E-07	-2.99E-07	2.06E-04	2.89E-05	1.03E-02	1.99E-04	2.73E-05	1.10E-02	1.95E-04
12	BULK14	211	all 0	P	1.17E-06	1.30E-06	5.68E-04	2.92E-05	1.03E-02	5.66E-04	2.77E-05	1.10E-02	5.67E-04
13	BULK14	273	all 0	P	1.74E-06	2.29E-06	5.64E-04	2.91E-05	1.03E-02	5.66E-04	2.79E-05	1.09E-02	5.69E-04
14	BULK14	301	all 0	P	1.68E-06	4.03E-06	7.56E-04	2.98E-05	1.03E-02	7.57E-04	2.87E-05	1.09E-02	7.59E-04
ann	BULK14	annealing*	all 0	P	1.48E-06	5.27E-07	4.22E-04	2.92E-05	1.03E-02	4.21E-04	2.82E-05	1.09E-02	4.21E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6bis	BULK14	0	checkerboard	P	1.51E-06	1.30E-07	2.08E-06	7.71E-04	1.28E-02	2.25E-06	8.02E-04	1.31E-02	2.32E-06
7	BULK14	12	checkerboard	P	1.58E-06	7.50E-08	2.74E-06	7.71E-04	1.28E-02	2.59E-06	8.02E-04	1.31E-02	2.88E-06
8	BULK14	61	checkerboard	P	6.83E-07	-4.74E-07	3.98E-06	7.69E-04	1.28E-02	4.02E-06	8.00E-04	1.30E-02	4.34E-06
9	BULK14	90	checkerboard	P	4.09E-07	-4.19E-07	7.79E-06	7.66E-04	1.27E-02	7.81E-06	7.98E-04	1.30E-02	8.00E-06
10	BULK14	126	checkerboard	P	1.21E-07	-6.46E-07	1.11E-04	7.67E-04	1.27E-02	1.09E-04	7.99E-04	1.30E-02	1.08E-04
11	BULK14	167	checkerboard	P	-2.49E-07	-9.51E-07	1.95E-04	7.66E-04	1.27E-02	1.91E-04	7.97E-04	1.30E-02	1.89E-04
12	BULK14	211	checkerboard	P	6.55E-07	1.28E-06	5.73E-04	7.68E-04	1.27E-02	5.70E-04	8.00E-04	1.30E-02	5.69E-04
13	BULK14	273	checkerboard	P	1.65E-06	2.45E-06	5.75E-04	7.68E-04	1.27E-02	5.75E-04	7.99E-04	1.29E-02	5.76E-04
14	BULK14	301	checkerboard	P	2.45E-06	4.28E-06	7.65E-04	7.69E-04	1.27E-02	7.63E-04	8.00E-04	1.30E-02	7.63E-04
ann	BULK14	annealing*	checkerboard	P	2.96E-06	7.10E-07	4.33E-04	7.69E-04	1.27E-02	4.30E-04	8.00E-04	1.29E-02	4.28E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6bis	BULK14	0	rev checkerboard	P	1.85E-06	3.25E-07	4.40E-06	7.71E-04	1.28E-02	4.28E-06	8.02E-04	1.31E-02	4.37E-06
7	BULK14	12	rev checkerboard	P	1.76E-06	2.44E-07	4.95E-06	7.71E-04	1.28E-02	5.09E-06	8.03E-04	1.31E-02	5.31E-06
8	BULK14	61	rev checkerboard	P	1.15E-06	-2.90E-07	6.90E-06	7.69E-04	1.28E-02	6.80E-06	8.01E-04	1.30E-02	6.95E-06
9	BULK14	90	rev checkerboard	P	1.04E-06	-2.18E-07	1.07E-05	7.68E-04	1.27E-02	1.07E-05	7.99E-04	1.30E-02	1.08E-05
10	BULK14	126	rev checkerboard	P	9.91E-07	-2.82E-07	1.24E-04	7.69E-04	1.27E-02	1.21E-04	8.00E-04	1.30E-02	1.19E-04
11	BULK14	167	rev checkerboard	P	3.10E-08	-7.37E-07	2.05E-04	7.67E-04	1.27E-02	2.01E-04	7.98E-04	1.30E-02	1.98E-04
12	BULK14	211	rev checkerboard	P	1.23E-06	1.14E-06	6.27E-04	7.69E-04	1.27E-02	6.15E-04	8.00E-04	1.30E-02	6.08E-04
13	BULK14	273	rev checkerboard	P	2.27E-06	2.52E-06	6.19E-04	7.69E-04	1.27E-02	6.11E-04	8.00E-04	1.29E-02	6.08E-04
14	BULK14	301	rev checkerboard	P	2.36E-06	4.08E-06	8.10E-04	7.70E-04	1.27E-02	7.99E-04	8.01E-04	1.29E-02	7.95E-04
ann	BULK14	annealing*	rev checkerboard	P	3.06E-06	4.50E-07	4.63E-04	7.70E-04	1.27E-02	4.55E-04	8.01E-04	1.29E-02	4.51E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6bis	BULK14	0	all 1	P	1.86E-06	4.88E-07	4.50E-06	1.92E-06	1.38E-02	4.42E-06	1.75E-06	1.56E-02	4.50E-06
7	BULK14	12	all 1	P	1.78E-06	2.24E-07	5.29E-06	1.73E-06	1.38E-02	5.13E-06	1.98E-06	1.55E-02	5.26E-06
8	BULK14	61	all 1	P	1.27E-06	-1.97E-07	7.19E-06	1.28E-06	1.38E-02	7.24E-06	1.59E-06	1.55E-02	7.16E-06
9	BULK14	90	all 1	P	1.49E-06	-7.60E-08	1.10E-05	1.28E-06	1.37E-02	1.10E-05	1.66E-06	1.54E-02	1.10E-05
10	BULK14	126	all 1	P	1.12E-06	-3.65E-07	1.22E-04	9.24E-07	1.37E-02	1.20E-04	1.06E-06	1.54E-02	1.19E-04
11	BULK14	167	all 1	P	6.34E-07	-4.99E-07	2.03E-04	3.12E-07	1.37E-02	1.99E-04	6.35E-07	1.54E-02	1.97E-04
12	BULK14	211	all 1	P	1.97E-06	1.56E-06	6.23E-04	1.88E-06	1.37E-02	6.15E-04	1.93E-06	1.54E-02	6.10E-04
13	BULK14	273	all 1	P	2.67E-06	2.92E-06	6.20E-04	2.84E-06	1.36E-02	6.15E-04	2.72E-06	1.54E-02	6.14E-04
14	BULK14	301	all 1	P	3.67E-06	4.54E-06	8.12E-04	3.61E-06	1.37E-02	8.05E-04	3.61E-06	1.54E-02	8.04E-04
ann	BULK14	annealing*	all 1	P	4.75E-06	9.42E-07	4.59E-04	4.70E-06	1.36E-02	4.54E-04	4.41E-06	1.54E-02	4.51E-04

run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6bis	BULK15	0	all 0	P	1.38E-06	3.05E-07	3.10E-08	3.30E-05	1.05E-02	-9.90E-08	3.16E-05	1.11E-02	-2.07E-07
7	BULK15	12	all 0	P	2.10E-06	5.61E-07	4.39E-07	3.34E-05	1.05E-02	1.08E-07	3.20E-05	1.11E-02	1.06E-07
8	BULK15	61	all 0	P	1.49E-06	9.00E-08	9.30E-06	3.26E-05	1.04E-02	9.02E-06	3.11E-05	1.11E-02	8.74E-06
9	BULK15	90	all 0	P	1.00E-06	1.60E-07	2.65E-05	3.16E-05	1.04E-02	2.57E-05	3.02E-05	1.11E-02	2.54E-05
10	BULK15	126	all 0	P	5.73E-07	-2.89E-07	3.22E-04	3.12E-05	1.04E-02	3.18E-04	3.02E-05	1.11E-02	3.16E-04
11	BULK15	167	all 0	P	1.01E-06	-2.95E-07	4.48E-04	3.09E-05	1.04E-02	4.43E-04	2.98E-05	1.11E-02	4.41E-04
12	BULK15	211	all 0	P	1.39E-06	1.15E-06	1.12E-03	3.23E-05	1.04E-02	1.11E-03	3.09E-05	1.11E-02	1.11E-03
13	BULK15	273	all 0	P	1.63E-06	1.32E-06	1.04E-03	3.14E-05	1.04E-02	1.04E-03	2.99E-05	1.10E-02	1.05E-03
14	BULK15	301	all 0	P	1.27E-06	1.96E-06	1.33E-03	3.20E-05	1.04E-02	1.33E-03	3.07E-05	1.10E-02	1.33E-03
ann	BULK15	annealing*	all 0	P	1.99E-06	9.94E-07	6.96E-04	3.20E-05	1.04E-02	6.93E-04	3.04E-05	1.10E-02	6.92E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6bis	BULK15	0	checkerboard	P	1.09E-06	0.00E+00	9.50E-08	7.67E-04	1.29E-02	3.22E-07	7.99E-04	1.32E-02	3.39E-07
7	BULK15	12	checkerboard	P	1.78E-06	7.20E-08	4.88E-07	7.68E-04	1.29E-02	5.97E-07	7.99E-04	1.31E-02	4.39E-07
8	BULK15	61	checkerboard	P	9.81E-07	-3.56E-07	9.48E-06	7.66E-04	1.29E-02	8.98E-06	7.97E-04	1.31E-02	8.90E-06
9	BULK15	90	checkerboard	P	7.54E-07	-3.44E-07	2.58E-05	7.64E-04	1.28E-02	2.54E-05	7.95E-04	1.31E-02	2.54E-05
10	BULK15	126	checkerboard	P	6.06E-07	-4.57E-07	3.22E-04	7.65E-04	1.28E-02	3.16E-04	7.96E-04	1.31E-02	3.14E-04
11	BULK15	167	checkerboard	P	6.83E-07	-4.18E-07	4.44E-04	7.63E-04	1.28E-02	4.40E-04	7.95E-04	1.30E-02	4.38E-04
12	BULK15	211	checkerboard	P	1.54E-06	8.18E-07	1.13E-03	7.66E-04	1.28E-02	1.12E-03	7.97E-04	1.30E-02	1.11E-03
13	BULK15	273	checkerboard	P	4.67E-06	9.37E-07	1.07E-03	7.67E-04	1.28E-02	1.06E-03	7.99E-04	1.30E-02	1.06E-03
14	BULK15	301	checkerboard	P	6.82E-06	1.35E-06	1.35E-03	7.72E-04	1.28E-02	1.35E-03	8.03E-04	1.30E-02	1.34E-03
ann	BULK15	annealing*	checkerboard	P	9.34E-06	7.63E-07	7.08E-04	7.73E-04	1.28E-02	7.02E-04	8.05E-04	1.30E-02	7.00E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6bis	BULK15	0	rev checkerboard	P	1.53E-06	8.90E-08	2.09E-07	7.68E-04	1.29E-02	8.60E-08	7.99E-04	1.32E-02	3.78E-07
7	BULK15	12	rev checkerboard	P	1.79E-06	1.59E-07	3.57E-07	7.69E-04	1.29E-02	5.88E-07	8.00E-04	1.31E-02	5.72E-07
8	BULK15	61	rev checkerboard	P	1.22E-06	-4.72E-07	1.03E-05	7.67E-04	1.29E-02	9.90E-06	7.98E-04	1.31E-02	1.01E-05
9	BULK15	90	rev checkerboard	P	1.23E-06	7.70E-08	2.76E-05	7.65E-04	1.28E-02	2.72E-05	7.96E-04	1.31E-02	2.69E-05
10	BULK15	126	rev checkerboard	P	8.03E-07	-6.20E-07	3.52E-04	7.66E-04	1.28E-02	3.43E-04	7.97E-04	1.31E-02	3.39E-04
11	BULK15	167	rev checkerboard	P	1.20E-06	-3.20E-08	4.72E-04	7.64E-04	1.28E-02	4.62E-04	7.96E-04	1.30E-02	4.56E-04
12	BULK15	211	rev checkerboard	P	1.92E-06	9.82E-07	1.21E-03	7.67E-04	1.28E-02	1.18E-03	7.98E-04	1.30E-02	1.17E-03
13	BULK15	273	rev checkerboard	P	5.57E-06	1.50E-06	1.13E-03	7.69E-04	1.28E-02	1.11E-03	8.00E-04	1.30E-02	1.10E-03
14	BULK15	301	rev checkerboard	P	8.77E-06	2.06E-06	1.42E-03	7.73E-04	1.28E-02	1.40E-03	8.04E-04	1.30E-02	1.39E-03
ann	BULK15	annealing*	rev checkerboard	P	1.29E-05	7.96E-07	7.53E-04	7.75E-04	1.28E-02	7.40E-04	8.06E-04	1.30E-02	7.34E-04

Run	DeviceID	dose(krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6bis	BULK15	0	all 1	P	1.90E-06	3.53E-07	5.81E-07	1.80E-06	1.39E-02	5.89E-07	1.83E-06	1.56E-02	6.01E-07
7	BULK15	12	all 1	P	1.83E-06	3.56E-07	8.85E-07	1.88E-06	1.38E-02	7.86E-07	1.96E-06	1.55E-02	7.38E-07
8	BULK15	61	all 1	P	1.47E-06	2.60E-08	1.06E-05	1.07E-06	1.38E-02	1.02E-05	1.36E-06	1.55E-02	1.00E-05
9	BULK15	90	all 1	P	1.73E-06	1.77E-07	2.79E-05	1.60E-06	1.38E-02	2.75E-05	1.58E-06	1.54E-02	2.74E-05
10	BULK15	126	all 1	P	9.50E-07	-2.22E-07	3.47E-04	1.13E-06	1.37E-02	3.39E-04	1.13E-06	1.54E-02	3.37E-04
11	BULK15	167	all 1	P	1.26E-06	5.20E-08	4.70E-04	1.52E-06	1.37E-02	4.64E-04	1.58E-06	1.54E-02	4.61E-04
12	BULK15	211	all 1	P	2.74E-06	1.14E-06	1.20E-03	2.84E-06	1.37E-02	1.18E-03	2.86E-06	1.54E-02	1.18E-03
13	BULK15	273	all 1	P	9.36E-06	1.41E-06	1.13E-03	9.22E-06	1.37E-02	1.12E-03	9.37E-06	1.54E-02	1.12E-03
14	BULK15	301	all 1	P	1.48E-05	1.90E-06	1.42E-03	1.50E-05	1.37E-02	1.40E-03	1.49E-05	1.54E-02	1.40E-03
ann	BULK15	annealing*	all 1	P	2.09E-05	9.86E-07	7.45E-04	2.09E-05	1.37E-02	7.37E-04	2.13E-05	1.54E-02	7.33E-04

5.3 Appendix 3: Electrical measurements on SOI devices

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI04 control	0	all 0	P	2.15E-06	1.40E-05	5.46E-06	6.31E-05	1.01E-02	4.78E-06	6.16E-05	1.06E-02	4.68E-06
7	SOI04 control	12	all 0	P	2.23E-06	1.43E-05	5.30E-06	6.29E-05	1.01E-02	4.81E-06	6.10E-05	1.07E-02	4.54E-06
8	SOI04 control	61	all 0	P	6.13E-07	1.34E-05	4.57E-06	6.14E-05	1.01E-02	3.87E-06	6.00E-05	1.07E-02	3.73E-06
9	SOI04 control	90	all 0	P	1.23E-06	1.39E-05	4.77E-06	6.10E-05	1.01E-02	4.29E-06	5.93E-05	1.07E-02	3.88E-06
10	SOI04 control	126	all 0	P	9.64E-07	1.36E-05	4.79E-06	6.15E-05	1.01E-02	3.78E-06	5.98E-05	1.07E-02	3.67E-06
11	SOI04 control	167	all 0	P	7.24E-07	1.35E-05	4.81E-06	6.13E-05	1.01E-02	3.98E-06	5.98E-05	1.07E-02	3.71E-06
12	SOI04 control	211	all 0	P	1.73E-06	1.42E-05	5.39E-06	6.31E-05	1.01E-02	4.71E-06	6.18E-05	1.07E-02	4.42E-06
13	SOI04 control	273	all 0	P	1.64E-06	1.39E-05	5.27E-06	6.17E-05	1.01E-02	4.44E-06	6.01E-05	1.07E-02	4.31E-06
14	SOI04 control	301	all 0	P	1.10E-06	1.36E-05	4.77E-06	6.22E-05	1.01E-02	4.23E-06	6.06E-05	1.07E-02	4.14E-06
anneal	SOI04 control	annealing	all 0	P	7.99E-07	1.33E-05	4.88E-06	6.08E-05	1.01E-02	3.93E-06	5.96E-05	1.07E-02	3.44E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI04 control	0	checkerboard	P	1.61E-06	1.38E-05	8.52E-06	7.93E-04	1.15E-02	8.39E-06	8.02E-04	1.13E-02	8.63E-06
7	SOI04 control	12	checkerboard	P	1.75E-06	1.39E-05	8.57E-06	7.89E-04	1.18E-02	8.52E-06	7.79E-04	1.16E-02	8.63E-06
8	SOI04 control	61	checkerboard	P	3.27E-07	1.30E-05	7.70E-06	7.87E-04	1.18E-02	7.64E-06	7.77E-04	1.17E-02	7.64E-06
9	SOI04 control	90	checkerboard	P	7.98E-07	1.34E-05	7.90E-06	7.83E-04	1.18E-02	8.09E-06	7.74E-04	1.16E-02	8.25E-06
10	SOI04 control	126	checkerboard	P	2.86E-07	1.32E-05	7.82E-06	7.85E-04	1.18E-02	7.76E-06	7.76E-04	1.16E-02	7.74E-06
11	SOI04 control	167	checkerboard	P	4.95E-07	1.29E-05	7.69E-06	7.84E-04	1.17E-02	7.80E-06	7.77E-04	1.15E-02	7.59E-06
12	SOI04 control	211	checkerboard	P	1.13E-06	1.38E-05	8.71E-06	7.90E-04	1.17E-02	8.66E-06	7.81E-04	1.15E-02	8.69E-06
13	SOI04 control	273	checkerboard	P	1.14E-06	1.35E-05	8.24E-06	7.85E-04	1.18E-02	8.15E-06	7.74E-04	1.17E-02	8.04E-06
14	SOI04 control	301	checkerboard	P	8.17E-07	1.33E-05	7.89E-06	7.86E-04	1.18E-02	8.18E-06	7.77E-04	1.15E-02	7.80E-06
anneal	SOI04 control	annealing	checkerboard	P	2.45E-07	1.29E-05	7.88E-06	7.86E-04	1.18E-02	8.11E-06	7.76E-04	1.16E-02	7.96E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI04 control	0	rev checkerboard	P	1.68E-06	1.41E-05	1.01E-05	8.11E-04	1.14E-02	1.04E-05	8.19E-04	1.12E-02	1.07E-05
7	SOI04 control	12	rev checkerboard	P	1.99E-06	1.40E-05	1.00E-05	8.04E-04	1.14E-02	1.06E-05	8.07E-04	1.12E-02	1.08E-05
8	SOI04 control	61	rev checkerboard	P	7.65E-07	1.32E-05	9.47E-06	8.02E-04	1.15E-02	9.98E-06	7.99E-04	1.13E-02	1.03E-05
9	SOI04 control	90	rev checkerboard	P	1.60E-06	1.37E-05	9.73E-06	7.97E-04	1.14E-02	1.05E-05	8.00E-04	1.12E-02	1.04E-05
10	SOI04 control	126	rev checkerboard	P	7.04E-07	1.35E-05	9.65E-06	8.01E-04	1.14E-02	1.00E-05	8.10E-04	1.12E-02	1.03E-05
11	SOI04 control	167	rev checkerboard	P	6.28E-07	1.32E-05	9.33E-06	8.02E-04	1.14E-02	9.86E-06	8.09E-04	1.12E-02	1.02E-05
12	SOI04 control	211	rev checkerboard	P	1.83E-06	1.42E-05	1.03E-05	8.09E-04	1.14E-02	1.11E-05	8.16E-04	1.12E-02	1.11E-05
13	SOI04 control	273	rev checkerboard	P	1.43E-06	1.37E-05	9.99E-06	7.93E-04	1.16E-02	1.05E-05	7.86E-04	1.13E-02	1.04E-05
14	SOI04 control	301	rev checkerboard	P	1.19E-06	1.34E-05	9.47E-06	8.06E-04	1.14E-02	1.02E-05	8.12E-04	1.12E-02	1.04E-05
anneal	SOI04 control	annealing	rev checkerboard	P	8.42E-07	1.33E-05	9.36E-06	8.00E-04	1.15E-02	1.00E-05	8.06E-04	1.12E-02	1.03E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI04 control	0	all 1	P	1.90E-06	1.40E-05	1.41E-05	4.75E-06	1.09E-02	1.43E-05	4.35E-06	1.17E-02	1.42E-05
7	SOI04 control	12	all 1	P	1.84E-06	1.41E-05	1.41E-05	3.59E-06	1.09E-02	1.44E-05	3.39E-06	1.17E-02	1.44E-05
8	SOI04 control	61	all 1	P	1.15E-06	1.34E-05	1.35E-05	2.95E-06	1.09E-02	1.42E-05	2.86E-06	1.18E-02	1.38E-05
9	SOI04 control	90	all 1	P	1.58E-06	1.38E-05	1.38E-05	2.88E-06	1.09E-02	1.41E-05	2.83E-06	1.17E-02	1.42E-05
10	SOI04 control	126	all 1	P	1.28E-06	1.32E-05	1.34E-05	2.98E-06	1.09E-02	1.37E-05	2.62E-06	1.17E-02	1.36E-05
11	SOI04 control	167	all 1	P	1.53E-06	1.34E-05	1.37E-05	3.14E-06	1.09E-02	1.36E-05	2.76E-06	1.17E-02	1.36E-05
12	SOI04 control	211	all 1	P	2.02E-06	1.41E-05	1.44E-05	4.52E-06	1.09E-02	1.47E-05	4.51E-06	1.18E-02	1.46E-05
13	SOI04 control	273	all 1	P	1.30E-06	1.35E-05	1.38E-05	2.42E-06	1.09E-02	1.40E-05	2.72E-06	1.18E-02	1.44E-05
14	SOI04 control	301	all 1	P	1.23E-06	1.33E-05	1.35E-05	3.47E-06	1.09E-02	1.40E-05	3.43E-06	1.17E-02	1.40E-05
anneal	SOI04 control	annealing*	all 1	P	1.47E-06	1.32E-05	1.37E-05	3.32E-06	1.09E-02	1.40E-05	3.19E-06	1.17E-02	1.40E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI05	0	all 0	P	-1.28E-06	4.85E-06	8.60E-08	7.17E-05	1.00E-02	5.40E-08	7.07E-05	1.05E-02	1.74E-07
1	SOI05	11	all 0	P	6.37E-07	5.07E-06	1.01E-06	7.88E-05	1.02E-02	1.09E-06	7.68E-05	1.09E-02	1.08E-06
2	SOI05	18	all 0	P	1.73E-06	6.66E-06	2.05E-06	8.09E-05	1.04E-02	2.13E-06	7.92E-05	1.10E-02	2.12E-06
3	SOI05	28	all 0	P	-1.21E-06	5.03E-06	5.72E-07	7.85E-05	1.04E-02	9.72E-07	7.73E-05	1.12E-02	1.04E-06
4	SOI05	47	all 0	P	1.75E-06	5.67E-06	1.99E-06	8.26E-05	1.04E-02	2.09E-06	8.13E-05	1.12E-02	2.12E-06
5	SOI05	67	all 0	P	1.75E-06	5.55E-06	2.28E-06	8.34E-05	1.04E-02	2.52E-06	8.27E-05	1.11E-02	2.26E-06
6	SOI05	99	all 0	P	2.33E-07	4.23E-06	1.80E-06	8.15E-05	1.04E-02	2.23E-06	7.99E-05	1.12E-02	2.26E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI05	0	checkerboard	P	-3.32E-07	5.37E-06	8.25E-07	8.11E-04	1.16E-02	1.17E-06	7.98E-04	1.15E-02	1.40E-06
1	SOI05	11	checkerboard	P	6.34E-07	5.23E-06	1.74E-06	8.07E-04	1.22E-02	2.30E-06	7.95E-04	1.22E-02	2.79E-06
2	SOI05	18	checkerboard	P	2.01E-06	6.37E-06	2.55E-06	8.16E-04	1.23E-02	3.20E-06	7.96E-04	1.24E-02	3.45E-06
3	SOI05	28	checkerboard	P	1.32E-06	5.66E-06	1.70E-06	8.15E-04	1.24E-02	2.89E-06	8.00E-04	1.25E-02	3.29E-06
4	SOI05	47	checkerboard	P	5.71E-06	5.44E-06	2.47E-06	8.24E-04	1.23E-02	3.42E-06	8.19E-04	1.24E-02	3.71E-06
5	SOI05	67	checkerboard	P	9.22E-06	5.09E-06	2.85E-06	8.31E-04	1.23E-02	4.30E-06	8.29E-04	1.24E-02	4.54E-06
6	SOI05	99	checkerboard	P	1.19E-05	4.56E-06	2.94E-06	8.38E-04	1.22E-02	4.85E-06	8.42E-04	1.23E-02	4.66E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI05	0	rev checkerboard	P	7.77E-07	5.82E-06	2.38E-06	8.36E-04	1.16E-02	2.72E-06	8.27E-04	1.14E-02	3.32E-06
1	SOI05	11	rev checkerboard	P	1.31E-06	5.34E-06	3.51E-06	8.20E-04	1.22E-02	4.33E-06	8.00E-04	1.22E-02	4.31E-06
2	SOI05	18	rev checkerboard	P	2.25E-06	6.38E-06	4.20E-06	8.20E-04	1.23E-02	5.03E-06	7.98E-04	1.24E-02	5.35E-06
3	SOI05	28	rev checkerboard	P	2.99E-06	5.79E-06	4.13E-06	8.18E-04	1.24E-02	4.92E-06	8.01E-04	1.25E-02	5.21E-06
4	SOI05	47	rev checkerboard	P	6.48E-06	5.28E-06	4.17E-06	8.23E-04	1.23E-02	5.10E-06	8.19E-04	1.24E-02	5.27E-06
5	SOI05	67	rev checkerboard	P	1.03E-05	4.96E-06	4.65E-06	8.32E-04	1.23E-02	5.62E-06	8.29E-04	1.24E-02	5.78E-06
6	SOI05	99	rev checkerboard	P	1.45E-05	4.22E-06	4.91E-06	8.39E-04	1.22E-02	6.89E-06	8.41E-04	1.23E-02	6.60E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI05	0	all 1	P	1.51E-06	6.26E-06	3.26E-06	4.24E-06	1.10E-02	3.58E-06	4.45E-06	1.17E-02	3.59E-06
1	SOI05	11	all 1	P	1.58E-06	5.93E-06	4.55E-06	3.03E-06	1.24E-02	4.58E-06	2.61E-06	1.35E-02	4.69E-06
2	SOI05	18	all 1	P	1.71E-06	6.39E-06	5.19E-06	2.63E-06	1.28E-02	5.70E-06	2.40E-06	1.38E-02	5.32E-06
3	SOI05	28	all 1	P	1.45E-06	6.38E-06	5.38E-06	2.12E-06	1.29E-02	5.69E-06	2.18E-06	1.40E-02	5.44E-06
4	SOI05	47	all 1	P	1.96E-06	5.36E-06	5.17E-06	2.10E-06	1.24E-02	5.65E-06	2.32E-06	1.37E-02	5.25E-06
5	SOI05	67	all 1	P	2.10E-06	5.08E-06	5.46E-06	1.79E-06	1.24E-02	6.20E-06	2.33E-06	1.36E-02	5.80E-06
6	SOI05	99	all 1	P	2.70E-06	4.67E-06	7.04E-06	2.34E-06	1.22E-02	8.82E-06	3.49E-06	1.36E-02	7.02E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI06	0	all 0	P	1.79E-06	4.57E-07	1.20E-05	7.00E-05	1.01E-02	1.16E-05	6.78E-05	1.07E-02	1.15E-05
1	SOI06	11	all 0	P	1.58E-06	2.01E-07	1.16E-05	6.93E-05	1.03E-02	1.12E-05	6.78E-05	1.09E-02	1.14E-05
2	SOI06	18	all 0	P	2.09E-06	1.30E-06	1.22E-05	7.15E-05	1.04E-02	1.17E-05	6.98E-05	1.10E-02	1.18E-05
3	SOI06	28	all 0	P	1.68E-06	1.46E-06	1.22E-05	7.32E-05	1.04E-02	1.21E-05	7.11E-05	1.11E-02	1.19E-05
4	SOI06	47	all 0	P	1.87E-06	1.31E-06	1.19E-05	7.75E-05	1.04E-02	1.17E-05	7.57E-05	1.11E-02	1.16E-05
5	SOI06	67	all 0	P	1.68E-06	1.22E-06	1.21E-05	7.79E-05	1.04E-02	1.19E-05	7.67E-05	1.11E-02	1.22E-05
6	SOI06	99	all 0	P	1.30E-06	1.15E-06	1.27E-05	7.89E-05	1.04E-02	1.28E-05	7.68E-05	1.11E-02	1.29E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI06	0	checkerboard	P	1.67E-06	2.98E-07	1.17E-05	7.97E-04	1.18E-02	1.19E-05	7.87E-04	1.17E-02	1.16E-05
1	SOI06	11	checkerboard	P	1.51E-06	-2.40E-08	1.21E-05	7.92E-04	1.23E-02	1.20E-05	7.84E-04	1.23E-02	1.21E-05
2	SOI06	18	checkerboard	P	1.87E-06	7.96E-07	1.23E-05	7.98E-04	1.24E-02	1.28E-05	7.85E-04	1.25E-02	1.29E-05
3	SOI06	28	checkerboard	P	2.63E-06	1.15E-06	1.28E-05	8.02E-04	1.26E-02	1.32E-05	7.90E-04	1.27E-02	1.31E-05
4	SOI06	47	checkerboard	P	4.72E-06	9.39E-07	1.20E-05	8.11E-04	1.24E-02	1.28E-05	8.03E-04	1.25E-02	1.28E-05
5	SOI06	67	checkerboard	P	7.61E-06	7.35E-07	1.22E-05	8.22E-04	1.23E-02	1.36E-05	8.14E-04	1.25E-02	1.31E-05
6	SOI06	99	checkerboard	P	1.24E-05	1.00E-06	1.30E-05	8.31E-04	1.22E-02	1.45E-05	8.31E-04	1.24E-02	1.45E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI06	0	rev checkerboard	P	1.90E-06	5.88E-07	3.23E-06	8.07E-04	1.18E-02	3.48E-06	7.96E-04	1.17E-02	3.69E-06
1	SOI06	11	rev checkerboard	P	1.50E-06	2.40E-08	3.66E-06	7.97E-04	1.23E-02	4.15E-06	7.88E-04	1.23E-02	4.18E-06
2	SOI06	18	rev checkerboard	P	2.00E-06	8.97E-07	4.57E-06	8.00E-04	1.24E-02	5.09E-06	7.86E-04	1.25E-02	5.01E-06
3	SOI06	28	rev checkerboard	P	2.89E-06	9.46E-07	4.39E-06	8.02E-04	1.26E-02	4.94E-06	7.91E-04	1.27E-02	5.07E-06
4	SOI06	47	rev checkerboard	P	5.21E-06	7.28E-07	4.14E-06	8.11E-04	1.24E-02	5.06E-06	8.03E-04	1.25E-02	5.02E-06
5	SOI06	67	rev checkerboard	P	8.43E-06	9.34E-07	4.79E-06	8.22E-04	1.23E-02	5.49E-06	8.15E-04	1.25E-02	5.46E-06
6	SOI06	99	rev checkerboard	P	1.29E-05	8.20E-07	5.52E-06	8.31E-04	1.22E-02	7.31E-06	8.32E-04	1.24E-02	7.15E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI06	0	all 1	P	2.38E-06	7.42E-07	3.99E-06	3.22E-06	1.15E-02	3.95E-06	3.12E-06	1.25E-02	3.79E-06
1	SOI06	11	all 1	P	1.39E-06	1.11E-07	4.42E-06	1.94E-06	1.26E-02	4.81E-06	2.00E-06	1.39E-02	4.69E-06
2	SOI06	18	all 1	P	2.09E-06	1.18E-06	5.08E-06	1.96E-06	1.29E-02	5.33E-06	2.25E-06	1.42E-02	4.96E-06
3	SOI06	28	all 1	P	1.97E-06	1.09E-06	5.37E-06	2.04E-06	1.31E-02	5.67E-06	2.01E-06	1.44E-02	5.55E-06
4	SOI06	47	all 1	P	1.72E-06	4.60E-07	4.74E-06	1.92E-06	1.28E-02	5.30E-06	2.15E-06	1.41E-02	5.18E-06
5	SOI06	67	all 1	P	2.00E-06	8.02E-07	5.17E-06	1.72E-06	1.27E-02	5.91E-06	2.33E-06	1.40E-02	5.21E-06
6	SOI06	99	all 1	P	2.45E-06	1.16E-06	6.60E-06	2.05E-06	1.24E-02	9.02E-06	3.23E-06	1.37E-02	7.13E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI07	0	all 0	P	2.07E-06	8.39E-06	7.75E-06	6.44E-05	1.01E-02	7.68E-06	6.22E-05	1.07E-02	7.45E-06
1	SOI07	11	all 0	P	1.64E-06	7.50E-06	6.48E-06	6.46E-05	1.02E-02	6.51E-06	6.25E-05	1.09E-02	6.44E-06
2	SOI07	18	all 0	P	1.80E-06	8.05E-06	6.85E-06	6.60E-05	1.04E-02	6.94E-06	6.39E-05	1.10E-02	6.74E-06
3	SOI07	28	all 0	P	2.04E-06	8.38E-06	6.93E-06	6.69E-05	1.04E-02	6.66E-06	6.50E-05	1.12E-02	6.72E-06
4	SOI07	47	all 0	P	1.93E-06	7.88E-06	6.54E-06	6.95E-05	1.04E-02	6.45E-06	6.81E-05	1.12E-02	6.39E-06
5	SOI07	67	all 0	P	1.67E-06	7.87E-06	6.78E-06	7.07E-05	1.04E-02	6.64E-06	6.93E-05	1.12E-02	6.70E-06
6	SOI07	99	all 0	P	1.81E-06	8.08E-06	7.82E-06	7.18E-05	1.04E-02	8.22E-06	7.03E-05	1.11E-02	8.21E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI07	0	checkerboard	P	1.93E-06	8.60E-06	7.52E-06	7.93E-04	1.19E-02	7.61E-06	7.82E-04	1.18E-02	7.59E-06
1	SOI07	11	checkerboard	P	1.22E-06	7.38E-06	6.91E-06	7.88E-04	1.23E-02	7.09E-06	7.84E-04	1.24E-02	7.19E-06
2	SOI07	18	checkerboard	P	1.69E-06	8.08E-06	7.26E-06	7.92E-04	1.25E-02	7.61E-06	7.81E-04	1.26E-02	7.25E-06
3	SOI07	28	checkerboard	P	2.34E-06	8.10E-06	7.30E-06	7.97E-04	1.26E-02	7.60E-06	7.86E-04	1.27E-02	7.75E-06
4	SOI07	47	checkerboard	P	3.86E-06	7.57E-06	7.15E-06	8.06E-04	1.25E-02	7.45E-06	7.96E-04	1.26E-02	7.52E-06
5	SOI07	67	checkerboard	P	6.68E-06	7.60E-06	7.21E-06	8.17E-04	1.25E-02	7.99E-06	8.07E-04	1.26E-02	7.66E-06
6	SOI07	99	checkerboard	P	1.08E-05	8.07E-06	8.78E-06	8.29E-04	1.24E-02	1.17E-05	8.23E-04	1.25E-02	9.56E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI07	0	rev checkerboard	P	2.43E-06	8.51E-06	6.80E-06	8.03E-04	1.18E-02	6.72E-06	7.90E-04	1.18E-02	6.71E-06
1	SOI07	11	rev checkerboard	P	1.53E-06	7.33E-06	6.55E-06	7.94E-04	1.23E-02	6.80E-06	7.88E-04	1.24E-02	7.21E-06
2	SOI07	18	rev checkerboard	P	1.92E-06	7.88E-06	6.72E-06	7.94E-04	1.25E-02	7.05E-06	7.83E-04	1.26E-02	7.00E-06
3	SOI07	28	rev checkerboard	P	3.04E-06	8.16E-06	7.10E-06	7.98E-04	1.26E-02	7.13E-06	7.87E-04	1.27E-02	7.15E-06
4	SOI07	47	rev checkerboard	P	4.78E-06	7.74E-06	6.67E-06	8.05E-04	1.25E-02	7.07E-06	7.97E-04	1.26E-02	7.06E-06
5	SOI07	67	rev checkerboard	P	8.20E-06	7.66E-06	6.88E-06	8.17E-04	1.25E-02	7.57E-06	8.07E-04	1.26E-02	7.47E-06
6	SOI07	99	rev checkerboard	P	1.32E-05	8.07E-06	8.64E-06	8.29E-04	1.24E-02	1.08E-05	8.23E-04	1.25E-02	9.13E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI07	0	all 1	P	2.03E-06	8.65E-06	6.77E-06	3.22E-06	1.16E-02	6.77E-06	2.99E-06	1.26E-02	6.67E-06
1	SOI07	11	all 1	P	2.00E-06	7.84E-06	7.10E-06	2.20E-06	1.27E-02	7.05E-06	2.10E-06	1.39E-02	6.90E-06
2	SOI07	18	all 1	P	1.59E-06	8.20E-06	7.34E-06	1.72E-06	1.30E-02	7.32E-06	2.09E-06	1.41E-02	7.31E-06
3	SOI07	28	all 1	P	1.88E-06	8.49E-06	7.73E-06	1.92E-06	1.32E-02	7.59E-06	2.33E-06	1.43E-02	7.54E-06
4	SOI07	47	all 1	P	1.90E-06	7.84E-06	7.24E-06	2.04E-06	1.30E-02	7.46E-06	2.08E-06	1.41E-02	7.22E-06
5	SOI07	67	all 1	P	2.09E-06	7.97E-06	7.81E-06	1.85E-06	1.29E-02	8.46E-06	2.15E-06	1.40E-02	7.65E-06
6	SOI07	99	all 1	P	2.52E-06	8.75E-06	1.07E-05	2.46E-06	1.27E-02	1.44E-05	2.51E-06	1.38E-02	9.26E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI09	0	all 0	P	2.20E-06	4.12E-06	2.01E-05	6.93E-05	1.00E-02	1.89E-05	6.72E-05	1.06E-02	1.84E-05
1	SOI09	11	all 0	P	1.97E-06	3.38E-06	1.95E-05	6.95E-05	1.02E-02	1.93E-05	6.78E-05	1.09E-02	1.90E-05
2	SOI09	18	all 0	P	1.40E-06	3.78E-06	1.98E-05	7.13E-05	1.03E-02	1.97E-05	6.88E-05	1.10E-02	1.99E-05
3	SOI09	28	all 0	P	1.61E-06	4.02E-06	2.01E-05	7.32E-05	1.04E-02	2.02E-05	7.13E-05	1.11E-02	2.00E-05
4	SOI09	47	all 0	P	2.05E-06	3.78E-06	1.98E-05	7.60E-05	1.04E-02	1.97E-05	7.47E-05	1.11E-02	1.95E-05
5	SOI09	67	all 0	P	1.94E-06	3.56E-06	1.94E-05	7.70E-05	1.03E-02	1.94E-05	7.58E-05	1.11E-02	1.93E-05
6	SOI09	99	all 0	P	1.69E-06	3.20E-06	1.87E-05	7.76E-05	1.03E-02	1.90E-05	7.57E-05	1.11E-02	1.89E-05
6b	SOI09	99	all 0	P	1.13E-06	3.12E-06	1.81E-05	7.70E-05	1.03E-02	1.85E-05	7.54E-05	1.10E-02	1.84E-05
7	SOI09	111	all 0	P	-2.51E-07	2.28E-06	1.70E-05	7.54E-05	1.03E-02	1.78E-05	7.40E-05	1.10E-02	1.79E-05
8	SOI09	160	all 0	P	-3.34E-07	1.23E-05	1.09E-04	7.54E-05	1.03E-02	1.24E-04	7.37E-05	1.10E-02	1.20E-04
9	SOI09	189	all 0	P	2.85E-07	5.16E-06	4.23E-05	7.63E-05	1.03E-02	4.71E-05	7.44E-05	1.10E-02	4.64E-05
10	SOI09	226	all 0	P	-2.60E-08	2.42E-05	1.65E-04	7.72E-05	1.03E-02	1.91E-04	7.49E-05	1.10E-02	1.86E-04
11	SOI09	266	all 0	P	9.57E-07	2.91E-05	1.49E-04	7.66E-05	1.03E-02	1.73E-04	7.48E-05	1.10E-02	1.70E-04
12	SOI09	311	all 0	P	-4.81E-07	8.47E-05	3.05E-04	7.76E-05	1.03E-02	3.59E-04	7.57E-05	1.10E-02	3.54E-04
anneal	SOI09	annealing	all 0	P	1.26E-06	3.73E-05	1.19E-04	8.05E-05	1.01E-02	1.37E-04	7.82E-05	1.08E-02	1.35E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI09	0	checkerboard	P	1.61E-06	3.93E-06	2.16E-05	8.00E-04	1.16E-02	2.18E-05	7.87E-04	1.16E-02	2.17E-05
1	SOI09	11	checkerboard	P	9.25E-07	2.82E-06	2.14E-05	7.94E-04	1.22E-02	2.20E-05	7.83E-04	1.23E-02	2.18E-05
2	SOI09	18	checkerboard	P	1.84E-06	3.69E-06	2.20E-05	7.99E-04	1.24E-02	2.27E-05	7.83E-04	1.25E-02	2.25E-05
3	SOI09	28	checkerboard	P	2.89E-06	3.87E-06	2.19E-05	8.04E-04	1.25E-02	2.28E-05	7.89E-04	1.26E-02	2.26E-05
4	SOI09	47	checkerboard	P	5.86E-06	3.45E-06	2.12E-05	8.15E-04	1.24E-02	2.24E-05	8.01E-04	1.24E-02	2.28E-05
5	SOI09	67	checkerboard	P	9.04E-06	2.85E-06	2.07E-05	8.26E-04	1.23E-02	2.20E-05	8.12E-04	1.24E-02	2.22E-05
6	SOI09	99	checkerboard	P	1.37E-05	2.93E-06	1.99E-05	8.36E-04	1.22E-02	2.19E-05	8.28E-04	1.23E-02	2.16E-05
6b	SOI09	99	checkerboard	P	1.25E-05	2.65E-06	1.94E-05	8.35E-04	1.22E-02	2.12E-05	8.29E-04	1.23E-02	2.11E-05
7	SOI09	111	checkerboard	P	1.77E-05	2.40E-06	1.94E-05	8.50E-04	1.22E-02	2.27E-05	8.45E-04	1.23E-02	2.18E-05
8	SOI09	160	checkerboard	P	3.66E-05	1.93E-05	1.70E-04	8.98E-04	1.22E-02	2.64E-04	8.85E-04	1.23E-02	1.70E-04
9	SOI09	189	checkerboard	P	3.61E-05	7.23E-06	6.27E-05	8.93E-04	1.20E-02	9.03E-05	8.91E-04	1.21E-02	6.49E-05
10	SOI09	226	checkerboard	P	4.52E-05	4.20E-05	2.66E-04	9.15E-04	1.21E-02	4.16E-04	9.08E-04	1.21E-02	2.64E-04
11	SOI09	266	checkerboard	P	5.08E-05	5.21E-05	2.47E-04	9.23E-04	1.20E-02	3.83E-04	9.17E-04	1.21E-02	2.45E-04
12	SOI09	311	checkerboard	P	5.98E-05	1.49E-04	5.15E-04	9.44E-04	1.21E-02	8.27E-04	9.36E-04	1.21E-02	5.08E-04
anneal	SOI09	annealing	checkerboard	P	6.07E-05	5.95E-05	1.84E-04	9.48E-04	1.18E-02	2.79E-04	9.39E-04	1.19E-02	1.88E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI09	0	rev checkerboard	P	2.16E-06	3.86E-06	8.61E-06	8.11E-04	1.16E-02	9.01E-06	7.96E-04	1.15E-02	9.37E-06
1	SOI09	11	rev checkerboard	P	1.22E-06	2.93E-06	1.05E-05	7.99E-04	1.22E-02	1.11E-05	7.86E-04	1.23E-02	1.10E-05
2	SOI09	18	rev checkerboard	P	2.03E-06	3.79E-06	1.13E-05	8.01E-04	1.24E-02	1.22E-05	7.84E-04	1.25E-02	1.22E-05
3	SOI09	28	rev checkerboard	P	3.59E-06	3.89E-06	1.18E-05	8.05E-04	1.25E-02	1.27E-05	7.89E-04	1.26E-02	1.25E-05
4	SOI09	47	rev checkerboard	P	6.36E-06	3.47E-06	1.14E-05	8.15E-04	1.24E-02	1.27E-05	8.02E-04	1.24E-02	1.26E-05
5	SOI09	67	rev checkerboard	P	1.01E-05	2.76E-06	1.15E-05	8.26E-04	1.23E-02	1.29E-05	8.12E-04	1.24E-02	1.28E-05
6	SOI09	99	rev checkerboard	P	1.52E-05	2.91E-06	1.17E-05	8.36E-04	1.22E-02	1.36E-05	8.28E-04	1.23E-02	1.33E-05
6b	SOI09	99	rev checkerboard	P	1.48E-05	2.60E-06	1.15E-05	8.38E-04	1.22E-02	1.35E-05	8.30E-04	1.23E-02	1.32E-05
7	SOI09	111	rev checkerboard	P	1.98E-05	2.91E-06	1.23E-05	8.51E-04	1.22E-02	1.55E-05	8.46E-04	1.23E-02	1.43E-05
8	SOI09	160	rev checkerboard	P	3.99E-05	1.57E-05	1.69E-04	8.99E-04	1.22E-02	2.64E-04	8.86E-04	1.23E-02	1.68E-04
9	SOI09	189	rev checkerboard	P	3.92E-05	6.80E-06	5.87E-05	8.95E-04	1.20E-02	8.61E-05	8.91E-04	1.21E-02	6.03E-05
10	SOI09	226	rev checkerboard	P	4.85E-05	3.72E-05	2.64E-04	9.17E-04	1.21E-02	4.11E-04	9.10E-04	1.21E-02	2.61E-04
11	SOI09	266	rev checkerboard	P	5.54E-05	4.73E-05	2.47E-04	9.23E-04	1.20E-02	3.81E-04	9.16E-04	1.21E-02	2.42E-04
12	SOI09	311	rev checkerboard	P	6.55E-05	1.39E-04	5.24E-04	9.45E-04	1.21E-02	8.23E-04	9.37E-04	1.21E-02	5.08E-04
anneal	SOI09	annealing	rev checkerboard	P	6.93E-05	6.05E-05	1.92E-04	9.50E-04	1.18E-02	2.77E-04	9.41E-04	1.18E-02	1.87E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI09	0	all 1	P	2.31E-06	4.14E-06	1.24E-05	3.64E-06	1.12E-02	1.22E-05	3.54E-06	1.20E-02	1.24E-05
1	SOI09	11	all 1	P	1.28E-06	3.10E-06	1.28E-05	1.72E-06	1.27E-02	1.27E-05	1.73E-06	1.39E-02	1.25E-05
2	SOI09	18	all 1	P	1.94E-06	3.83E-06	1.33E-05	1.63E-06	1.29E-02	1.31E-05	2.07E-06	1.42E-02	1.31E-05
3	SOI09	28	all 1	P	2.12E-06	3.71E-06	1.33E-05	2.15E-06	1.30E-02	1.34E-05	2.09E-06	1.44E-02	1.32E-05
4	SOI09	47	all 1	P	2.23E-06	3.27E-06	1.31E-05	2.26E-06	1.28E-02	1.32E-05	2.84E-06	1.40E-02	1.29E-05
5	SOI09	67	all 1	P	2.46E-06	3.03E-06	1.26E-05	2.05E-06	1.27E-02	1.31E-05	2.86E-06	1.39E-02	1.26E-05
6	SOI09	99	all 1	P	3.32E-06	2.99E-06	1.27E-05	2.27E-06	1.25E-02	1.43E-05	3.95E-06	1.37E-02	1.28E-05
6b	SOI09	99	all 1	P	3.01E-06	2.87E-06	1.24E-05	2.00E-06	1.24E-02	1.36E-05	3.75E-06	1.36E-02	1.24E-05
7	SOI09	111	all 1	P	3.18E-06	3.16E-06	1.45E-05	2.33E-06	1.24E-02	1.85E-05	4.52E-06	1.36E-02	1.45E-05
8	SOI09	160	all 1	P	5.54E-06	2.74E-05	2.67E-04	3.99E-06	1.26E-02	4.67E-04	9.05E-06	1.37E-02	2.35E-04
9	SOI09	189	all 1	P	5.59E-06	1.10E-05	9.28E-05	3.96E-06	1.22E-02	1.58E-04	9.00E-06	1.33E-02	8.53E-05
10	SOI09	226	all 1	P	8.36E-06	6.73E-05	4.15E-04	6.83E-06	1.23E-02	7.30E-04	1.25E-05	1.34E-02	3.64E-04
11	SOI09	266	all 1	P	1.09E-05	8.58E-05	3.84E-04	9.13E-06	1.22E-02	6.77E-04	1.61E-05	1.33E-02	3.38E-04
12	SOI09	311	all 1	P	1.65E-05	2.38E-04	7.92E-04	1.64E-05	1.24E-02	1.41E-03	2.30E-05	1.34E-02	6.81E-04
anneal	SOI09	annealing*	all 1	P	1.72E-05	1.01E-04	2.79E-04	1.57E-05	1.18E-02	4.72E-04	2.30E-05	1.28E-02	2.46E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI10	0	all 0	P	-1.14E-06	-8.29E-07	1.94E-06	5.26E-05	1.02E-02	2.02E-06	5.11E-05	1.08E-02	2.05E-06
1	SOI10	11	all 0	P	1.50E-06	1.46E-07	3.92E-06	5.48E-05	1.00E-02	3.26E-06	5.25E-05	1.06E-02	3.27E-06
2	SOI10	18	all 0	P	1.62E-06	4.92E-07	3.90E-06	5.52E-05	1.02E-02	4.21E-06	5.40E-05	1.09E-02	4.17E-06
3	SOI10	28	all 0	P	1.92E-06	8.85E-07	4.19E-06	5.61E-05	1.03E-02	4.35E-06	5.43E-05	1.10E-02	4.20E-06
4	SOI10	47	all 0	P	1.63E-06	1.05E-06	3.95E-06	5.78E-05	1.03E-02	3.77E-06	5.61E-05	1.10E-02	3.72E-06
5	SOI10	67	all 0	P	2.08E-06	1.34E-06	4.51E-06	6.03E-05	1.03E-02	4.50E-06	5.88E-05	1.10E-02	4.65E-06
6	SOI10	99	all 0	P	2.00E-06	1.56E-06	2.82E-06	6.33E-05	1.03E-02	3.00E-06	6.15E-05	1.10E-02	2.86E-06
6b	SOI10	99	all 0	P	1.86E-06	1.46E-06	5.55E-06	6.32E-05	1.03E-02	5.93E-06	6.15E-05	1.09E-02	5.72E-06
7	SOI10	111	all 0	P	1.81E-06	2.02E-06	8.51E-06	6.26E-05	1.02E-02	9.11E-06	6.12E-05	1.09E-02	9.16E-06
8	SOI10	160	all 0	P	4.40E-08	2.89E-05	1.76E-04	6.14E-05	1.03E-02	1.97E-04	5.96E-05	1.10E-02	1.94E-04
9	SOI10	189	all 0	P	7.22E-07	1.30E-05	6.80E-05	6.31E-05	1.02E-02	7.53E-05	6.12E-05	1.09E-02	7.44E-05
10	SOI10	226	all 0	P	1.70E-06	5.83E-05	2.71E-04	6.49E-05	1.02E-02	3.06E-04	6.27E-05	1.09E-02	3.02E-04
11	SOI10	266	all 0	P	3.08E-06	6.80E-05	2.58E-04	6.60E-05	1.02E-02	2.89E-04	6.39E-05	1.09E-02	2.87E-04
12	SOI10	311	all 0	P	1.07E-05	1.72E-04	5.09E-04	7.68E-05	1.03E-02	5.77E-04	7.46E-05	1.09E-02	5.71E-04
anneal	SOI10	annealing	all 0	P	8.11E-06	1.11E-04	2.19E-04	7.54E-05	1.01E-02	2.46E-04	7.37E-05	1.08E-02	2.45E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI10	0	checkerboard	P	-3.10E-08	-3.89E-07	1.73E-06	7.82E-04	1.23E-02	1.93E-06	7.86E-04	1.23E-02	2.03E-06
1	SOI10	11	checkerboard	P	5.44E-07	-3.27E-07	3.16E-06	7.78E-04	1.19E-02	3.31E-06	7.79E-04	1.19E-02	3.26E-06
2	SOI10	18	checkerboard	P	1.40E-06	4.41E-07	3.72E-06	7.79E-04	1.23E-02	4.12E-06	7.73E-04	1.24E-02	3.86E-06
3	SOI10	28	checkerboard	P	1.76E-06	9.54E-07	4.05E-06	7.79E-04	1.24E-02	4.33E-06	7.71E-04	1.25E-02	4.20E-06
4	SOI10	47	checkerboard	P	1.96E-06	7.36E-07	3.60E-06	7.83E-04	1.24E-02	4.20E-06	7.76E-04	1.25E-02	3.96E-06
5	SOI10	67	checkerboard	P	3.76E-06	7.46E-07	4.03E-06	7.90E-04	1.25E-02	4.68E-06	7.84E-04	1.25E-02	4.71E-06
6	SOI10	99	checkerboard	P	6.39E-06	1.15E-06	3.76E-06	8.02E-04	1.24E-02	5.50E-06	8.00E-04	1.24E-02	4.43E-06
6b	SOI10	99	checkerboard	P	5.84E-06	1.10E-06	6.22E-06	7.99E-04	1.23E-02	7.85E-06	7.94E-04	1.23E-02	6.90E-06
7	SOI10	111	checkerboard	P	9.80E-06	2.17E-06	1.15E-05	8.11E-04	1.23E-02	1.51E-05	8.05E-04	1.23E-02	1.17E-05
8	SOI10	160	checkerboard	P	2.29E-05	5.11E-05	2.82E-04	8.51E-04	1.24E-02	4.05E-04	8.39E-04	1.24E-02	2.53E-04
9	SOI10	189	checkerboard	P	2.34E-05	2.27E-05	1.10E-04	8.49E-04	1.21E-02	1.52E-04	8.44E-04	1.21E-02	1.01E-04
10	SOI10	226	checkerboard	P	3.38E-05	1.03E-04	4.43E-04	8.74E-04	1.22E-02	6.35E-04	8.64E-04	1.22E-02	3.99E-04
11	SOI10	266	checkerboard	P	4.06E-05	1.22E-04	4.21E-04	8.87E-04	1.22E-02	6.02E-04	8.77E-04	1.21E-02	3.82E-04
12	SOI10	311	checkerboard	P	6.42E-05	3.04E-04	8.27E-04	9.34E-04	1.24E-02	1.21E-03	9.10E-04	1.22E-02	7.47E-04
anneal	SOI10	annealing	checkerboard	P	6.86E-05	1.99E-04	3.52E-04	9.47E-04	1.20E-02	5.16E-04	9.23E-04	1.19E-02	3.38E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI10	0	rev checkerboard	P	9.06E-07	1.65E-07	3.84E-06	7.84E-04	1.22E-02	3.76E-06	7.87E-04	1.23E-02	4.16E-06
1	SOI10	11	rev checkerboard	P	1.18E-06	-1.21E-07	3.72E-06	7.80E-04	1.19E-02	3.98E-06	7.81E-04	1.19E-02	3.84E-06
2	SOI10	18	rev checkerboard	P	1.52E-06	3.31E-07	4.02E-06	7.79E-04	1.23E-02	4.37E-06	7.74E-04	1.24E-02	4.68E-06
3	SOI10	28	rev checkerboard	P	1.67E-06	7.36E-07	4.22E-06	7.79E-04	1.24E-02	4.68E-06	7.72E-04	1.25E-02	4.68E-06
4	SOI10	47	rev checkerboard	P	2.43E-06	8.80E-07	4.01E-06	7.82E-04	1.24E-02	4.44E-06	7.76E-04	1.25E-02	4.44E-06
5	SOI10	67	rev checkerboard	P	3.82E-06	6.65E-07	4.35E-06	7.90E-04	1.24E-02	4.99E-06	7.85E-04	1.25E-02	5.03E-06
6	SOI10	99	rev checkerboard	P	6.45E-06	1.04E-06	3.58E-06	8.02E-04	1.24E-02	5.48E-06	8.00E-04	1.24E-02	4.20E-06
6b	SOI10	99	rev checkerboard	P	6.35E-06	1.34E-06	6.51E-06	8.00E-04	1.23E-02	8.25E-06	7.95E-04	1.23E-02	7.41E-06
7	SOI10	111	rev checkerboard	P	9.91E-06	2.30E-06	1.16E-05	8.10E-04	1.23E-02	1.59E-05	8.06E-04	1.23E-02	1.25E-05
8	SOI10	160	rev checkerboard	P	2.38E-05	4.11E-05	2.64E-04	8.51E-04	1.24E-02	4.20E-04	8.40E-04	1.24E-02	2.61E-04
9	SOI10	189	rev checkerboard	P	2.33E-05	1.83E-05	9.80E-05	8.49E-04	1.21E-02	1.56E-04	8.45E-04	1.21E-02	1.04E-04
10	SOI10	226	rev checkerboard	P	3.33E-05	8.39E-05	3.99E-04	8.74E-04	1.22E-02	6.48E-04	8.64E-04	1.22E-02	4.05E-04
11	SOI10	266	rev checkerboard	P	4.08E-05	9.92E-05	3.78E-04	8.87E-04	1.22E-02	6.12E-04	8.77E-04	1.21E-02	3.87E-04
12	SOI10	311	rev checkerboard	P	6.28E-05	2.54E-04	7.52E-04	9.34E-04	1.24E-02	1.23E-03	9.11E-04	1.22E-02	7.57E-04
anneal	SOI10	annealing	rev checkerboard	P	6.61E-05	1.70E-04	3.22E-04	9.47E-04	1.20E-02	5.20E-04	9.24E-04	1.19E-02	3.40E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI10	0	all 1	P	1.34E-06	2.78E-07	3.73E-06	1.84E-06	1.28E-02	3.88E-06	1.96E-06	1.42E-02	4.22E-06
1	SOI10	11	all 1	P	9.54E-07	-9.80E-08	3.48E-06	1.39E-06	1.23E-02	3.79E-06	1.29E-06	1.34E-02	3.70E-06
2	SOI10	18	all 1	P	1.82E-06	6.47E-07	4.40E-06	2.11E-06	1.26E-02	4.12E-06	1.73E-06	1.40E-02	3.89E-06
3	SOI10	28	all 1	P	1.96E-06	1.09E-06	4.18E-06	1.77E-06	1.28E-02	4.03E-06	1.83E-06	1.42E-02	4.00E-06
4	SOI10	47	all 1	P	2.06E-06	9.01E-07	4.06E-06	1.94E-06	1.30E-02	4.10E-06	1.95E-06	1.42E-02	3.91E-06
5	SOI10	67	all 1	P	1.84E-06	6.44E-07	4.36E-06	1.63E-06	1.29E-02	4.90E-06	1.73E-06	1.42E-02	4.21E-06
6	SOI10	99	all 1	P	1.98E-06	1.58E-06	6.17E-06	2.08E-06	1.31E-02	1.16E-05	2.41E-06	1.40E-02	4.54E-06
6b	SOI10	99	all 1	P	2.38E-06	1.77E-06	8.17E-06	2.57E-06	1.28E-02	1.15E-05	2.17E-06	1.39E-02	7.04E-06
7	SOI10	111	all 1	P	2.58E-06	3.01E-06	1.66E-05	2.54E-06	1.28E-02	2.67E-05	2.86E-06	1.39E-02	1.32E-05
8	SOI10	160	all 1	P	4.08E-06	7.67E-05	4.10E-04	5.63E-06	1.31E-02	7.36E-04	4.92E-06	1.40E-02	2.94E-04
9	SOI10	189	all 1	P	3.68E-06	3.37E-05	1.57E-04	4.70E-06	1.27E-02	2.88E-04	5.12E-06	1.34E-02	1.23E-04
10	SOI10	226	all 1	P	1.04E-05	1.51E-04	6.17E-04	1.58E-05	1.30E-02	1.12E-03	1.04E-05	1.35E-02	4.59E-04
11	SOI10	266	all 1	P	1.70E-05	1.81E-04	5.80E-04	2.68E-05	1.29E-02	1.05E-03	1.61E-05	1.34E-02	4.41E-04
12	SOI10	311	all 1	P	4.50E-05	4.49E-04	1.12E-03	7.53E-05	1.33E-02	2.04E-03	4.23E-05	1.36E-02	8.49E-04
anneal	SOI10	annealing*	all 1	P	4.75E-05	3.04E-04	4.80E-04	8.47E-05	1.26E-02	8.74E-04	4.75E-05	1.31E-02	4.03E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI11	0	all 0	P	1.53E-06	1.30E-07	6.44E-06	6.20E-05	1.02E-02	6.11E-06	5.99E-05	1.08E-02	5.74E-06
1	SOI11	11	all 0	P	1.27E-06	-1.02E-07	5.59E-06	6.10E-05	1.02E-02	5.36E-06	5.86E-05	1.08E-02	5.41E-06
2	SOI11	18	all 0	P	1.95E-06	4.56E-07	6.29E-06	6.18E-05	1.03E-02	6.01E-06	5.99E-05	1.09E-02	5.80E-06
3	SOI11	28	all 0	P	1.69E-06	1.19E-06	6.22E-06	6.29E-05	1.04E-02	5.99E-06	6.17E-05	1.10E-02	6.22E-06
4	SOI11	47	all 0	P	1.64E-06	1.02E-06	5.67E-06	6.70E-05	1.03E-02	5.63E-06	6.58E-05	1.10E-02	5.86E-06
5	SOI11	67	all 0	P	1.78E-06	9.03E-07	5.91E-06	6.95E-05	1.03E-02	5.72E-06	6.77E-05	1.10E-02	5.75E-06
6	SOI11	99	all 0	P	1.72E-06	1.43E-06	7.19E-06	7.07E-05	1.03E-02	7.04E-06	6.91E-05	1.10E-02	6.94E-06
6b	SOI11	99	all 0	P	2.12E-06	1.62E-06	7.30E-06	7.12E-05	1.03E-02	7.21E-06	6.97E-05	1.10E-02	7.18E-06
7	SOI11	111	all 0	P	2.21E-06	2.51E-06	1.05E-05	7.06E-05	1.03E-02	1.05E-05	6.87E-05	1.10E-02	1.04E-05
8	SOI11	160	all 0	P	1.22E-06	4.06E-05	1.47E-04	6.71E-05	1.03E-02	1.46E-04	6.52E-05	1.11E-02	1.45E-04
9	SOI11	189	all 0	P	1.18E-06	1.82E-05	6.59E-05	6.85E-05	1.02E-02	6.56E-05	6.66E-05	1.09E-02	6.54E-05
10	SOI11	226	all 0	P	2.51E-06	8.00E-05	2.39E-04	7.08E-05	1.03E-02	2.38E-04	6.83E-05	1.10E-02	2.37E-04
11	SOI11	266	all 0	P	4.22E-06	9.07E-05	2.27E-04	7.23E-05	1.03E-02	2.27E-04	7.00E-05	1.10E-02	2.26E-04
12	SOI11	311	all 0	P	1.41E-05	2.12E-04	4.03E-04	8.33E-05	1.03E-02	4.08E-04	8.13E-05	1.10E-02	4.07E-04
anneal	SOI11	annealing	all 0	P	1.11E-05	1.43E-04	1.99E-04	8.32E-05	1.02E-02	2.38E-04	8.09E-05	1.09E-02	2.37E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI11	0	checkerboard	P	1.57E-06	3.34E-07	1.22E-06	7.89E-04	1.20E-02	1.33E-06	7.83E-04	1.20E-02	1.30E-06
1	SOI11	11	checkerboard	P	8.22E-07	-3.13E-07	1.09E-06	7.83E-04	1.21E-02	1.17E-06	7.78E-04	1.22E-02	1.40E-06
2	SOI11	18	checkerboard	P	1.88E-06	6.17E-07	1.99E-06	7.85E-04	1.23E-02	2.06E-06	7.74E-04	1.25E-02	2.10E-06
3	SOI11	28	checkerboard	P	2.21E-06	6.97E-07	1.63E-06	7.89E-04	1.24E-02	1.85E-06	7.74E-04	1.26E-02	1.95E-06
4	SOI11	47	checkerboard	P	2.72E-06	7.04E-07	1.51E-06	7.93E-04	1.23E-02	1.79E-06	7.82E-04	1.24E-02	1.91E-06
5	SOI11	67	checkerboard	P	3.87E-06	4.51E-07	1.67E-06	8.00E-04	1.23E-02	2.33E-06	7.91E-04	1.24E-02	2.57E-06
6	SOI11	99	checkerboard	P	6.40E-06	1.04E-06	3.31E-06	8.05E-04	1.22E-02	3.85E-06	8.05E-04	1.23E-02	3.97E-06
6b	SOI11	99	checkerboard	P	6.82E-06	1.16E-06	3.37E-06	8.05E-04	1.21E-02	4.01E-06	8.06E-04	1.23E-02	4.08E-06
7	SOI11	111	checkerboard	P	1.21E-05	2.17E-06	6.91E-06	8.19E-04	1.21E-02	7.62E-06	8.17E-04	1.23E-02	7.67E-06
8	SOI11	160	checkerboard	P	3.42E-05	4.19E-05	1.49E-04	8.68E-04	1.22E-02	1.48E-04	8.65E-04	1.24E-02	1.46E-04
9	SOI11	189	checkerboard	P	3.61E-05	1.85E-05	6.45E-05	8.69E-04	1.21E-02	6.50E-05	8.73E-04	1.22E-02	6.49E-05
10	SOI11	226	checkerboard	P	4.78E-05	8.06E-05	2.43E-04	8.90E-04	1.21E-02	2.42E-04	8.94E-04	1.22E-02	2.41E-04
11	SOI11	266	checkerboard	P	5.48E-05	9.15E-05	2.33E-04	8.99E-04	1.21E-02	2.34E-04	9.06E-04	1.22E-02	2.33E-04
12	SOI11	311	checkerboard	P	7.47E-05	2.15E-04	4.21E-04	9.29E-04	1.21E-02	4.25E-04	9.36E-04	1.22E-02	4.22E-04
anneal	SOI11	annealing	checkerboard	P	6.67E-05	1.43E-04	2.03E-04	9.25E-04	1.20E-02	2.13E-04	9.33E-04	1.20E-02	2.13E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI11	0	rev checkerboard	P	1.76E-06	1.86E-07	9.73E-06	7.94E-04	1.20E-02	9.90E-06	7.85E-04	1.20E-02	1.00E-05
1	SOI11	11	rev checkerboard	P	1.24E-06	-3.23E-07	9.46E-06	7.87E-04	1.21E-02	9.77E-06	7.81E-04	1.22E-02	9.91E-06
2	SOI11	18	rev checkerboard	P	1.92E-06	4.97E-07	1.00E-05	7.87E-04	1.23E-02	1.01E-05	7.74E-04	1.25E-02	1.02E-05
3	SOI11	28	rev checkerboard	P	1.99E-06	6.91E-07	9.88E-06	7.88E-04	1.24E-02	1.00E-05	7.75E-04	1.26E-02	1.03E-05
4	SOI11	47	rev checkerboard	P	2.54E-06	5.41E-07	9.45E-06	7.93E-04	1.23E-02	9.98E-06	7.83E-04	1.24E-02	1.01E-05
5	SOI11	67	rev checkerboard	P	4.34E-06	8.35E-07	1.01E-05	8.00E-04	1.23E-02	1.02E-05	7.92E-04	1.24E-02	1.03E-05
6	SOI11	99	rev checkerboard	P	6.94E-06	1.07E-06	1.08E-05	8.05E-04	1.22E-02	1.13E-05	8.05E-04	1.23E-02	1.15E-05
6b	SOI11	99	rev checkerboard	P	7.11E-06	1.38E-06	1.09E-05	8.06E-04	1.21E-02	1.17E-05	8.06E-04	1.23E-02	1.17E-05
7	SOI11	111	rev checkerboard	P	1.25E-05	2.23E-06	1.45E-05	8.19E-04	1.21E-02	1.51E-05	8.18E-04	1.23E-02	1.52E-05
8	SOI11	160	rev checkerboard	P	3.49E-05	3.96E-05	1.66E-04	8.69E-04	1.22E-02	1.63E-04	8.66E-04	1.24E-02	1.60E-04
9	SOI11	189	rev checkerboard	P	3.59E-05	1.78E-05	7.39E-05	8.69E-04	1.21E-02	7.40E-05	8.73E-04	1.22E-02	7.36E-05
10	SOI11	226	rev checkerboard	P	4.76E-05	7.85E-05	2.62E-04	8.90E-04	1.21E-02	2.60E-04	8.94E-04	1.22E-02	2.56E-04
11	SOI11	266	rev checkerboard	P	5.46E-05	9.04E-05	2.49E-04	9.00E-04	1.21E-02	2.48E-04	9.07E-04	1.22E-02	2.46E-04
12	SOI11	311	rev checkerboard	P	7.44E-05	2.16E-04	4.48E-04	9.30E-04	1.21E-02	4.49E-04	9.37E-04	1.22E-02	4.43E-04
anneal	SOI11	annealing	rev checkerboard	P	6.92E-05	1.42E-04	2.13E-04	9.26E-04	1.20E-02	2.23E-04	9.34E-04	1.20E-02	2.22E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI11	0	all 1	P	2.26E-06	6.46E-07	5.24E-06	2.58E-06	1.23E-02	5.30E-06	2.33E-06	1.35E-02	4.91E-06
1	SOI11	11	all 1	P	1.66E-06	2.19E-07	5.21E-06	1.79E-06	1.25E-02	5.00E-06	1.76E-06	1.38E-02	5.17E-06
2	SOI11	18	all 1	P	1.87E-06	6.66E-07	5.67E-06	2.14E-06	1.26E-02	5.90E-06	2.13E-06	1.41E-02	5.53E-06
3	SOI11	28	all 1	P	1.88E-06	5.44E-07	5.39E-06	1.91E-06	1.27E-02	5.64E-06	1.88E-06	1.42E-02	5.37E-06
4	SOI11	47	all 1	P	1.86E-06	4.96E-07	5.62E-06	2.19E-06	1.25E-02	5.38E-06	2.34E-06	1.39E-02	5.57E-06
5	SOI11	67	all 1	P	1.78E-06	6.12E-07	5.50E-06	1.70E-06	1.24E-02	5.70E-06	1.89E-06	1.38E-02	5.75E-06
6	SOI11	99	all 1	P	1.90E-06	8.72E-07	7.13E-06	1.97E-06	1.22E-02	7.29E-06	2.48E-06	1.36E-02	6.99E-06
6b	SOI11	99	all 1	P	2.16E-06	1.10E-06	7.06E-06	2.16E-06	1.21E-02	7.10E-06	2.23E-06	1.35E-02	7.34E-06
7	SOI11	111	all 1	P	2.32E-06	2.00E-06	1.06E-05	2.43E-06	1.22E-02	1.07E-05	2.80E-06	1.36E-02	1.06E-05
8	SOI11	160	all 1	P	2.94E-06	4.12E-05	1.59E-04	2.93E-06	1.24E-02	1.57E-04	5.30E-06	1.38E-02	1.54E-04
9	SOI11	189	all 1	P	2.95E-06	1.82E-05	6.96E-05	2.50E-06	1.20E-02	6.93E-05	5.48E-06	1.34E-02	6.92E-05
10	SOI11	226	all 1	P	7.57E-06	7.98E-05	2.53E-04	7.07E-06	1.21E-02	2.52E-04	1.13E-05	1.34E-02	2.48E-04
11	SOI11	266	all 1	P	1.15E-05	9.10E-05	2.38E-04	1.10E-05	1.21E-02	2.39E-04	1.64E-05	1.33E-02	2.37E-04
12	SOI11	311	all 1	P	2.92E-05	2.17E-04	4.33E-04	2.84E-05	1.22E-02	4.33E-04	3.57E-05	1.34E-02	4.29E-04
anneal	SOI11	annealing*	all 1	P	2.23E-05	1.43E-04	2.06E-04	2.12E-05	1.19E-02	2.13E-04	2.90E-05	1.31E-02	2.12E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI12	0	all 0	P	1.84E-06	2.97E-06	1.49E-05	7.09E-05	9.86E-03	1.43E-05	6.96E-05	1.04E-02	1.40E-05
1	SOI12	11	all 0	P	1.86E-06	2.77E-06	1.39E-05	8.10E-05	1.02E-02	1.37E-05	8.07E-05	1.08E-02	1.36E-05
2	SOI12	18	all 0	P	1.77E-06	3.45E-06	1.42E-05	8.08E-05	1.03E-02	1.43E-05	8.01E-05	1.09E-02	1.45E-05
3	SOI12	28	all 0	P	1.65E-06	3.59E-06	1.41E-05	8.04E-05	1.03E-02	1.42E-05	8.08E-05	1.10E-02	1.40E-05
4	SOI12	47	all 0	P	1.71E-06	3.19E-06	1.35E-05	7.93E-05	1.03E-02	1.37E-05	7.92E-05	1.10E-02	1.39E-05
5	SOI12	67	all 0	P	1.71E-06	3.07E-06	1.35E-05	7.97E-05	1.03E-02	1.38E-05	7.92E-05	1.10E-02	1.35E-05
6	SOI12	99	all 0	P	1.56E-06	3.09E-06	1.32E-05	7.95E-05	1.03E-02	1.36E-05	7.76E-05	1.10E-02	1.36E-05
6b	SOI12	99	all 0	P	1.44E-06	2.92E-06	1.28E-05	7.88E-05	1.03E-02	1.33E-05	7.74E-05	1.10E-02	1.31E-05
7	SOI12	111	all 0	P	2.25E-06	3.50E-06	1.36E-05	8.06E-05	1.03E-02	1.41E-05	7.83E-05	1.10E-02	1.40E-05
8	SOI12	160	all 0	P	1.01E-06	4.09E-06	1.68E-05	7.78E-05	1.02E-02	1.86E-05	7.50E-05	1.10E-02	1.84E-05
9	SOI12	189	all 0	P	1.31E-06	3.57E-06	1.45E-05	7.83E-05	1.02E-02	1.63E-05	7.58E-05	1.10E-02	1.62E-05
10	SOI12	226	all 0	P	-9.45E-07	5.81E-06	2.04E-05	7.61E-05	1.02E-02	2.47E-05	7.39E-05	1.09E-02	2.46E-05
11	SOI12	266	all 0	P	1.50E-06	8.95E-06	2.45E-05	7.78E-05	1.02E-02	2.93E-05	7.51E-05	1.09E-02	2.88E-05
12	SOI12	311	all 0	P	2.27E-06	1.81E-05	3.48E-05	7.89E-05	1.02E-02	4.31E-05	7.65E-05	1.09E-02	4.27E-05
anneal	SOI12	annealing	all 0	P	2.12E-06	2.55E-05	3.42E-05	7.90E-05	1.01E-02	4.25E-05	7.67E-05	1.08E-02	4.20E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI12	0	checkerboard	P	1.78E-06	2.82E-06	7.49E-06	8.07E-04	1.13E-02	8.04E-06	8.02E-04	1.11E-02	7.77E-06
1	SOI12	11	checkerboard	P	1.37E-06	2.68E-06	7.88E-06	8.28E-04	1.18E-02	8.85E-06	8.32E-04	1.18E-02	8.97E-06
2	SOI12	18	checkerboard	P	2.60E-06	3.34E-06	8.33E-06	8.30E-04	1.20E-02	9.45E-06	8.26E-04	1.20E-02	9.46E-06
3	SOI12	28	checkerboard	P	3.78E-06	3.47E-06	8.58E-06	8.26E-04	1.21E-02	9.69E-06	8.25E-04	1.21E-02	9.82E-06
4	SOI12	47	checkerboard	P	7.10E-06	2.74E-06	8.48E-06	8.28E-04	1.20E-02	9.72E-06	8.30E-04	1.21E-02	9.59E-06
5	SOI12	67	checkerboard	P	1.08E-05	2.70E-06	8.69E-06	8.36E-04	1.20E-02	1.00E-05	8.38E-04	1.20E-02	1.00E-05
6	SOI12	99	checkerboard	P	1.59E-05	2.58E-06	8.64E-06	8.45E-04	1.19E-02	1.08E-05	8.49E-04	1.20E-02	1.06E-05
6b	SOI12	99	checkerboard	P	1.52E-05	2.55E-06	8.54E-06	8.44E-04	1.19E-02	1.06E-05	8.49E-04	1.20E-02	1.04E-05
7	SOI12	111	checkerboard	P	1.72E-05	3.13E-06	9.40E-06	8.49E-04	1.19E-02	1.16E-05	8.52E-04	1.20E-02	1.13E-05
8	SOI12	160	checkerboard	P	2.62E-05	3.74E-06	1.45E-05	8.69E-04	1.19E-02	2.06E-05	8.69E-04	1.20E-02	1.62E-05
9	SOI12	189	checkerboard	P	2.48E-05	3.53E-06	1.21E-05	8.63E-04	1.18E-02	1.71E-05	8.65E-04	1.19E-02	1.45E-05
10	SOI12	226	checkerboard	P	3.12E-05	6.96E-06	2.09E-05	8.81E-04	1.18E-02	3.23E-05	8.80E-04	1.19E-02	2.40E-05
11	SOI12	266	checkerboard	P	3.70E-05	1.03E-05	2.47E-05	8.90E-04	1.18E-02	3.75E-05	8.89E-04	1.19E-02	2.80E-05
12	SOI12	311	checkerboard	P	4.58E-05	2.24E-05	3.88E-05	9.11E-04	1.18E-02	5.97E-05	9.09E-04	1.18E-02	4.34E-05
anneal	SOI12	annealing	checkerboard	P	5.11E-05	3.11E-05	3.69E-05	9.18E-04	1.17E-02	5.54E-05	9.19E-04	1.17E-02	4.30E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI12	0	rev checkerboard	P	1.68E-06	2.83E-06	1.26E-05	8.31E-04	1.12E-02	1.30E-05	8.22E-04	1.09E-02	1.33E-05
1	SOI12	11	rev checkerboard	P	1.69E-06	2.91E-06	1.20E-05	8.53E-04	1.18E-02	1.28E-05	8.41E-04	1.18E-02	1.27E-05
2	SOI12	18	rev checkerboard	P	2.78E-06	3.37E-06	1.20E-05	8.32E-04	1.20E-02	1.28E-05	8.27E-04	1.20E-02	1.31E-05
3	SOI12	28	rev checkerboard	P	4.42E-06	3.32E-06	1.17E-05	8.29E-04	1.21E-02	1.24E-05	8.24E-04	1.21E-02	1.25E-05
4	SOI12	47	rev checkerboard	P	7.48E-06	3.15E-06	1.15E-05	8.28E-04	1.20E-02	1.22E-05	8.30E-04	1.21E-02	1.26E-05
5	SOI12	67	rev checkerboard	P	1.15E-05	2.80E-06	1.11E-05	8.36E-04	1.20E-02	1.21E-05	8.38E-04	1.20E-02	1.23E-05
6	SOI12	99	rev checkerboard	P	1.70E-05	2.79E-06	1.13E-05	8.45E-04	1.19E-02	1.31E-05	8.50E-04	1.20E-02	1.29E-05
6b	SOI12	99	rev checkerboard	P	1.62E-05	2.97E-06	1.12E-05	8.45E-04	1.19E-02	1.31E-05	8.50E-04	1.20E-02	1.29E-05
7	SOI12	111	rev checkerboard	P	1.86E-05	3.27E-06	1.20E-05	8.49E-04	1.19E-02	1.40E-05	8.53E-04	1.20E-02	1.35E-05
8	SOI12	160	rev checkerboard	P	2.76E-05	4.11E-06	1.67E-05	8.70E-04	1.19E-02	2.30E-05	8.70E-04	1.20E-02	1.88E-05
9	SOI12	189	rev checkerboard	P	2.63E-05	3.85E-06	1.47E-05	8.63E-04	1.18E-02	1.98E-05	8.65E-04	1.19E-02	1.72E-05
10	SOI12	226	rev checkerboard	P	3.36E-05	7.31E-06	2.31E-05	8.81E-04	1.18E-02	3.52E-05	8.82E-04	1.19E-02	2.68E-05
11	SOI12	266	rev checkerboard	P	3.91E-05	1.02E-05	2.69E-05	8.90E-04	1.18E-02	4.03E-05	8.89E-04	1.19E-02	3.05E-05
12	SOI12	311	rev checkerboard	P	4.88E-05	2.12E-05	3.98E-05	9.11E-04	1.18E-02	6.25E-05	9.10E-04	1.18E-02	4.60E-05
anneal	SOI12	annealing	rev checkerboard	P	5.48E-05	2.96E-05	3.83E-05	9.18E-04	1.17E-02	5.78E-05	9.20E-04	1.17E-02	4.57E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI12	0	all 1	P	1.96E-06	2.87E-06	5.95E-06	5.49E-06	1.04E-02	6.15E-06	5.51E-06	1.10E-02	6.22E-06
1	SOI12	11	all 1	P	1.49E-06	2.83E-06	5.87E-06	5.51E-06	1.17E-02	6.14E-06	4.67E-06	1.27E-02	5.94E-06
2	SOI12	18	all 1	P	2.14E-06	3.54E-06	6.03E-06	3.48E-06	1.19E-02	6.14E-06	3.59E-06	1.30E-02	6.34E-06
3	SOI12	28	all 1	P	1.81E-06	3.05E-06	6.06E-06	2.59E-06	1.20E-02	6.21E-06	2.86E-06	1.31E-02	6.29E-06
4	SOI12	47	all 1	P	2.30E-06	2.89E-06	6.06E-06	2.22E-06	1.19E-02	6.44E-06	2.61E-06	1.31E-02	6.26E-06
5	SOI12	67	all 1	P	2.23E-06	2.78E-06	6.10E-06	2.03E-06	1.18E-02	6.46E-06	2.76E-06	1.30E-02	6.30E-06
6	SOI12	99	all 1	P	3.04E-06	2.65E-06	6.83E-06	2.47E-06	1.17E-02	8.01E-06	4.03E-06	1.30E-02	7.29E-06
6b	SOI12	99	all 1	P	3.42E-06	2.96E-06	7.11E-06	2.70E-06	1.17E-02	8.30E-06	3.95E-06	1.30E-02	7.36E-06
7	SOI12	111	all 1	P	3.71E-06	3.40E-06	7.89E-06	3.02E-06	1.17E-02	9.39E-06	4.18E-06	1.29E-02	8.04E-06
8	SOI12	160	all 1	P	4.28E-06	4.29E-06	1.43E-05	2.14E-06	1.17E-02	2.26E-05	5.15E-06	1.29E-02	1.38E-05
9	SOI12	189	all 1	P	4.18E-06	4.22E-06	1.28E-05	2.72E-06	1.16E-02	1.82E-05	5.49E-06	1.28E-02	1.26E-05
10	SOI12	226	all 1	P	5.06E-06	8.97E-06	2.41E-05	3.18E-06	1.16E-02	3.93E-05	6.58E-06	1.28E-02	2.28E-05
11	SOI12	266	all 1	P	6.54E-06	1.22E-05	2.82E-05	4.08E-06	1.16E-02	4.52E-05	8.30E-06	1.27E-02	2.65E-05
12	SOI12	311	all 1	P	9.35E-06	2.66E-05	4.49E-05	7.07E-06	1.16E-02	7.40E-05	1.18E-05	1.27E-02	4.25E-05
anneal	SOI12	annealing*	all 1	P	9.82E-06	3.75E-05	4.25E-05	6.74E-06	1.13E-02	6.62E-05	1.35E-05	1.24E-02	4.34E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI13	0	all 0	P	1.55E-06	2.22E-07	2.72E-06	6.27E-05	1.04E-02	1.84E-06	6.04E-05	1.10E-02	1.67E-06
1	SOI13	11	all 0	P	1.49E-06	3.49E-07	1.90E-06	6.52E-05	1.01E-02	1.84E-06	6.34E-05	1.07E-02	1.83E-06
2	SOI13	18	all 0	P	1.66E-06	2.33E-07	2.26E-06	6.54E-05	1.04E-02	2.46E-06	6.38E-05	1.10E-02	2.36E-06
3	SOI13	28	all 0	P	1.81E-06	6.48E-07	2.55E-06	6.61E-05	1.04E-02	2.72E-06	6.43E-05	1.11E-02	2.60E-06
4	SOI13	47	all 0	P	1.75E-06	8.74E-07	2.59E-06	6.89E-05	1.04E-02	2.38E-06	6.74E-05	1.11E-02	2.35E-06
5	SOI13	67	all 0	P	1.78E-06	1.28E-06	2.86E-06	7.03E-05	1.04E-02	2.83E-06	6.91E-05	1.11E-02	2.88E-06
6	SOI13	99	all 0	P	1.93E-06	2.11E-06	4.89E-06	7.22E-05	1.04E-02	4.81E-06	7.07E-05	1.11E-02	4.66E-06
6b	SOI13	99	all 0	P	2.10E-06	2.17E-06	4.76E-06	7.29E-05	1.03E-02	4.90E-06	7.11E-05	1.10E-02	4.73E-06
7	SOI13	111	all 0	P	2.56E-06	2.88E-06	5.93E-06	7.41E-05	1.03E-02	6.30E-06	7.24E-05	1.10E-02	6.00E-06
8	SOI13	160	all 0	P	1.03E-06	1.06E-05	1.78E-05	7.18E-05	1.04E-02	1.94E-05	6.93E-05	1.11E-02	1.90E-05
9	SOI13	189	all 0	P	2.26E-07	8.08E-06	1.35E-05	7.28E-05	1.03E-02	1.45E-05	7.06E-05	1.10E-02	1.43E-05
10	SOI13	226	all 0	P	1.45E-06	2.38E-05	3.10E-05	7.35E-05	1.03E-02	3.38E-05	7.13E-05	1.10E-02	3.32E-05
11	SOI13	266	all 0	P	6.40E-07	3.01E-05	3.53E-05	7.23E-05	1.03E-02	3.83E-05	7.03E-05	1.10E-02	3.80E-05
12	SOI13	311	all 0	P	5.48E-06	6.50E-05	5.87E-05	7.80E-05	1.03E-02	6.36E-05	7.60E-05	1.10E-02	6.34E-05
anneal	SOI13	annealing	all 0	P	4.54E-06	8.59E-05	6.07E-05	7.72E-05	1.03E-02	6.52E-05	7.42E-05	1.10E-02	6.43E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI13	0	checkerboard	P	1.42E-06	-2.37E-07	5.50E-06	7.93E-04	1.25E-02	5.50E-06	7.95E-04	1.26E-02	5.76E-06
1	SOI13	11	checkerboard	P	1.23E-06	-7.10E-08	5.36E-06	7.92E-04	1.19E-02	5.63E-06	7.87E-04	1.18E-02	5.54E-06
2	SOI13	18	checkerboard	P	1.57E-06	2.05E-07	5.45E-06	7.94E-04	1.25E-02	5.75E-06	7.83E-04	1.25E-02	5.84E-06
3	SOI13	28	checkerboard	P	1.72E-06	5.36E-07	5.58E-06	7.92E-04	1.26E-02	5.69E-06	7.79E-04	1.27E-02	5.98E-06
4	SOI13	47	checkerboard	P	1.76E-06	6.44E-07	5.51E-06	7.93E-04	1.25E-02	5.66E-06	7.81E-04	1.26E-02	5.65E-06
5	SOI13	67	checkerboard	P	2.36E-06	8.93E-07	5.90E-06	7.98E-04	1.25E-02	6.34E-06	7.86E-04	1.26E-02	6.40E-06
6	SOI13	99	checkerboard	P	3.97E-06	1.75E-06	8.47E-06	8.03E-04	1.24E-02	9.71E-06	7.94E-04	1.25E-02	8.45E-06
6b	SOI13	99	checkerboard	P	4.25E-06	2.04E-06	8.33E-06	8.04E-04	1.24E-02	9.48E-06	7.95E-04	1.24E-02	8.26E-06
7	SOI13	111	checkerboard	P	5.22E-06	2.85E-06	9.83E-06	8.06E-04	1.23E-02	1.15E-05	8.00E-04	1.24E-02	9.85E-06
8	SOI13	160	checkerboard	P	8.60E-06	1.37E-05	2.60E-05	8.18E-04	1.25E-02	3.50E-05	8.07E-04	1.25E-02	2.37E-05
9	SOI13	189	checkerboard	P	7.26E-06	1.04E-05	2.03E-05	8.13E-04	1.22E-02	2.64E-05	8.13E-04	1.22E-02	1.92E-05
10	SOI13	226	checkerboard	P	1.32E-05	3.18E-05	4.28E-05	8.29E-04	1.23E-02	5.89E-05	8.22E-04	1.23E-02	3.91E-05
11	SOI13	266	checkerboard	P	1.64E-05	4.23E-05	4.94E-05	8.37E-04	1.23E-02	6.74E-05	8.28E-04	1.22E-02	4.44E-05
12	SOI13	311	checkerboard	P	3.09E-05	9.45E-05	8.18E-05	8.70E-04	1.24E-02	1.13E-04	8.47E-04	1.23E-02	7.22E-05
anneal	SOI13	annealing	checkerboard	P	3.69E-05	1.32E-04	8.63E-05	8.81E-04	1.23E-02	1.13E-04	8.57E-04	1.22E-02	7.27E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI13	0	rev checkerboard	P	1.93E-06	2.38E-07	1.23E-06	7.96E-04	1.25E-02	1.45E-06	7.97E-04	1.26E-02	1.18E-06
1	SOI13	11	rev checkerboard	P	1.46E-06	9.00E-09	1.46E-06	7.99E-04	1.19E-02	1.55E-06	7.91E-04	1.18E-02	1.70E-06
2	SOI13	18	rev checkerboard	P	1.85E-06	2.16E-07	2.02E-06	7.95E-04	1.25E-02	2.31E-06	7.85E-04	1.25E-02	2.09E-06
3	SOI13	28	rev checkerboard	P	1.89E-06	7.38E-07	1.83E-06	7.92E-04	1.26E-02	2.00E-06	7.79E-04	1.27E-02	2.15E-06
4	SOI13	47	rev checkerboard	P	1.88E-06	7.28E-07	1.98E-06	7.94E-04	1.25E-02	2.34E-06	7.81E-04	1.26E-02	2.20E-06
5	SOI13	67	rev checkerboard	P	2.75E-06	7.80E-07	2.77E-06	7.98E-04	1.25E-02	3.20E-06	7.87E-04	1.26E-02	2.82E-06
6	SOI13	99	rev checkerboard	P	4.34E-06	2.03E-06	5.44E-06	8.03E-04	1.24E-02	6.96E-06	7.95E-04	1.25E-02	5.35E-06
6b	SOI13	99	rev checkerboard	P	4.33E-06	1.83E-06	5.25E-06	8.04E-04	1.24E-02	6.46E-06	7.96E-04	1.24E-02	5.17E-06
7	SOI13	111	rev checkerboard	P	5.46E-06	3.05E-06	6.76E-06	8.06E-04	1.23E-02	8.69E-06	8.01E-04	1.24E-02	6.75E-06
8	SOI13	160	rev checkerboard	P	9.56E-06	1.44E-05	2.44E-05	8.18E-04	1.25E-02	3.20E-05	8.08E-04	1.24E-02	2.10E-05
9	SOI13	189	rev checkerboard	P	8.40E-06	1.08E-05	1.79E-05	8.13E-04	1.22E-02	2.42E-05	8.14E-04	1.22E-02	1.66E-05
10	SOI13	226	rev checkerboard	P	1.50E-05	3.33E-05	4.21E-05	8.30E-04	1.23E-02	5.63E-05	8.23E-04	1.23E-02	3.67E-05
11	SOI13	266	rev checkerboard	P	1.85E-05	4.32E-05	4.79E-05	8.38E-04	1.23E-02	6.51E-05	8.29E-04	1.22E-02	4.23E-05
12	SOI13	311	rev checkerboard	P	3.30E-05	9.48E-05	7.97E-05	8.70E-04	1.24E-02	1.11E-04	8.48E-04	1.23E-02	6.97E-05
anneal	SOI13	annealing	rev checkerboard	P	3.63E-05	1.17E-04	7.64E-05	8.81E-04	1.23E-02	1.10E-04	8.58E-04	1.22E-02	7.00E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI13	0	all 1	P	1.93E-06	3.13E-07	5.35E-06	2.11E-06	1.32E-02	5.14E-06	2.12E-06	1.46E-02	5.01E-06
1	SOI13	11	all 1	P	1.62E-06	2.53E-07	4.99E-06	2.11E-06	1.22E-02	4.98E-06	1.91E-06	1.33E-02	4.90E-06
2	SOI13	18	all 1	P	2.09E-06	6.42E-07	5.46E-06	2.03E-06	1.30E-02	5.66E-06	2.42E-06	1.43E-02	5.48E-06
3	SOI13	28	all 1	P	1.87E-06	8.30E-07	5.09E-06	1.88E-06	1.30E-02	5.30E-06	1.97E-06	1.45E-02	5.33E-06
4	SOI13	47	all 1	P	1.83E-06	4.38E-07	4.90E-06	1.84E-06	1.29E-02	5.29E-06	1.90E-06	1.42E-02	5.07E-06
5	SOI13	67	all 1	P	1.65E-06	7.11E-07	5.84E-06	1.82E-06	1.30E-02	6.52E-06	1.84E-06	1.42E-02	5.66E-06
6	SOI13	99	all 1	P	2.04E-06	2.33E-06	9.93E-06	1.89E-06	1.29E-02	1.25E-05	1.87E-06	1.40E-02	8.09E-06
6b	SOI13	99	all 1	P	2.07E-06	2.48E-06	9.38E-06	1.87E-06	1.29E-02	1.19E-05	1.72E-06	1.39E-02	7.78E-06
7	SOI13	111	all 1	P	2.62E-06	3.73E-06	1.17E-05	2.57E-06	1.28E-02	1.53E-05	2.57E-06	1.37E-02	9.34E-06
8	SOI13	160	all 1	P	3.30E-06	2.08E-05	3.54E-05	3.44E-06	1.30E-02	5.44E-05	2.64E-06	1.39E-02	2.43E-05
9	SOI13	189	all 1	P	2.47E-06	1.61E-05	2.81E-05	2.74E-06	1.25E-02	4.13E-05	2.29E-06	1.35E-02	1.97E-05
10	SOI13	226	all 1	P	6.24E-06	4.82E-05	5.87E-05	8.48E-06	1.28E-02	9.17E-05	4.69E-06	1.35E-02	4.03E-05
11	SOI13	266	all 1	P	8.86E-06	6.37E-05	6.71E-05	1.28E-05	1.28E-02	1.05E-04	6.52E-06	1.35E-02	4.59E-05
12	SOI13	311	all 1	P	2.43E-05	1.41E-04	1.10E-04	3.76E-05	1.31E-02	1.78E-04	1.82E-05	1.36E-02	7.43E-05
anneal	SOI13	annealing*	all 1	P	2.27E-05	1.91E-04	1.12E-04	3.65E-05	1.28E-02	1.77E-04	1.66E-05	1.34E-02	7.62E-05

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI14 control	0	all 0	P	1.74E-06	3.46E-06	2.54E-06	7.10E-05	1.00E-02	2.19E-06	6.93E-05	1.05E-02	1.65E-06
1	SOI14 control	11	all 0	P	1.63E-06	3.25E-06	1.53E-06	6.95E-05	1.00E-02	1.63E-06	6.77E-05	1.05E-02	1.37E-06
2	SOI14 control	18	all 0	P	2.01E-06	3.41E-06	2.53E-06	7.04E-05	1.00E-02	2.04E-06	6.88E-05	1.05E-02	1.89E-06
3	SOI14 control	28	all 0	P	1.88E-06	3.53E-06	2.33E-06	7.03E-05	1.00E-02	2.09E-06	6.88E-05	1.06E-02	1.80E-06
4	SOI14 control	47	all 0	P	1.73E-06	3.38E-06	2.17E-06	6.94E-05	1.00E-02	1.77E-06	6.79E-05	1.05E-02	1.69E-06
5	SOI14 control	67	all 0	P	1.83E-06	3.42E-06	2.03E-06	7.03E-05	1.00E-02	1.62E-06	6.87E-05	1.05E-02	1.53E-06
6	SOI14 control	99	all 0	P	1.82E-06	3.44E-06	2.41E-06	7.02E-05	1.00E-02	1.96E-06	6.84E-05	1.05E-02	2.05E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI14 control	0	checkerboard	P	1.50E-06	3.20E-06	1.86E-06	8.09E-04	1.16E-02	1.77E-06	8.03E-04	1.15E-02	1.82E-06
1	SOI14 control	11	checkerboard	P	9.32E-07	2.84E-06	1.28E-06	8.08E-04	1.16E-02	1.67E-06	8.00E-04	1.15E-02	1.58E-06
2	SOI14 control	18	checkerboard	P	1.77E-06	3.40E-06	2.13E-06	8.08E-04	1.16E-02	2.10E-06	8.00E-04	1.15E-02	1.93E-06
3	SOI14 control	28	checkerboard	P	1.59E-06	3.30E-06	1.73E-06	8.10E-04	1.16E-02	2.31E-06	8.03E-04	1.15E-02	2.15E-06
4	SOI14 control	47	checkerboard	P	1.47E-06	3.12E-06	1.76E-06	8.06E-04	1.16E-02	1.93E-06	7.98E-04	1.15E-02	2.02E-06
5	SOI14 control	67	checkerboard	P	1.03E-06	3.01E-06	1.49E-06	8.13E-04	1.16E-02	1.75E-06	8.04E-04	1.15E-02	1.86E-06
6	SOI14 control	99	checkerboard	P	1.58E-06	3.40E-06	1.98E-06	8.07E-04	1.16E-02	2.23E-06	8.00E-04	1.15E-02	1.93E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI14 control	0	rev checkerboard	P	1.73E-06	2.57E-06	5.03E-06	8.34E-04	1.15E-02	5.12E-06	8.36E-04	1.14E-02	5.49E-06
1	SOI14 control	11	rev checkerboard	P	1.54E-06	2.26E-06	4.76E-06	8.28E-04	1.15E-02	5.15E-06	8.23E-04	1.14E-02	5.04E-06
2	SOI14 control	18	rev checkerboard	P	1.69E-06	2.48E-06	5.03E-06	8.26E-04	1.16E-02	5.50E-06	8.26E-04	1.14E-02	5.53E-06
3	SOI14 control	28	rev checkerboard	P	2.08E-06	2.70E-06	5.21E-06	8.31E-04	1.15E-02	5.29E-06	8.27E-04	1.14E-02	5.39E-06
4	SOI14 control	47	rev checkerboard	P	1.68E-06	2.13E-06	4.85E-06	8.23E-04	1.16E-02	5.32E-06	8.20E-04	1.14E-02	5.05E-06
5	SOI14 control	67	rev checkerboard	P	1.56E-06	2.09E-06	4.67E-06	8.37E-04	1.15E-02	5.21E-06	8.35E-04	1.14E-02	4.98E-06
6	SOI14 control	99	rev checkerboard	P	1.67E-06	2.52E-06	5.10E-06	8.27E-04	1.15E-02	5.16E-06	8.21E-04	1.14E-02	5.24E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
prerad	SOI14 control	0	all 1	P	1.90E-06	2.45E-06	5.09E-06	5.10E-06	1.09E-02	5.03E-06	4.77E-06	1.16E-02	5.04E-06
1	SOI14 control	11	all 1	P	1.66E-06	2.34E-06	4.84E-06	4.24E-06	1.10E-02	4.99E-06	3.96E-06	1.17E-02	4.96E-06
2	SOI14 control	18	all 1	P	2.23E-06	2.65E-06	5.30E-06	4.82E-06	1.10E-02	5.36E-06	4.79E-06	1.17E-02	5.45E-06
3	SOI14 control	28	all 1	P	1.78E-06	2.67E-06	5.03E-06	4.47E-06	1.10E-02	5.18E-06	4.38E-06	1.17E-02	5.22E-06
4	SOI14 control	47	all 1	P	1.66E-06	2.52E-06	5.15E-06	4.09E-06	1.10E-02	5.02E-06	4.10E-06	1.17E-02	5.17E-06
5	SOI14 control	67	all 1	P	1.45E-06	2.30E-06	4.77E-06	4.73E-06	1.09E-02	4.69E-06	4.60E-06	1.16E-02	4.96E-06
6	SOI14 control	99	all 1	P	1.71E-06	2.42E-06	4.88E-06	4.36E-06	1.10E-02	4.99E-06	4.38E-06	1.17E-02	5.21E-06

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI14	0	all 0	P	1.70E-06	3.56E-06	2.47E-06	7.03E-05	1.00E-02	2.20E-06	6.90E-05	1.05E-02	2.09E-06
7	SOI14	12	all 0	P	2.25E-06	3.87E-06	2.82E-06	7.51E-05	1.03E-02	2.92E-06	7.29E-05	1.09E-02	2.89E-06
8	SOI14	61	all 0	P	1.00E-06	6.33E-06	1.29E-05	6.64E-05	1.06E-02	2.04E-05	6.44E-05	1.14E-02	1.97E-05
9	SOI14	90	all 0	P	1.33E-06	5.75E-06	1.31E-05	7.46E-05	1.04E-02	2.13E-05	7.32E-05	1.11E-02	2.13E-05
10	SOI14	126	all 0	P	1.39E-06	2.95E-05	1.58E-04	7.52E-05	1.04E-02	2.74E-04	7.32E-05	1.11E-02	2.68E-04
11	SOI14	167	all 0	P	1.04E-07	3.69E-05	1.61E-04	7.57E-05	1.04E-02	2.73E-04	7.36E-05	1.11E-02	2.67E-04
12	SOI14	211	all 0	P	2.70E-06	1.30E-04	3.72E-04	8.06E-05	1.04E-02	6.26E-04	7.85E-05	1.11E-02	6.17E-04
13	SOI14	273	all 0	P	5.96E-06	1.47E-04	2.83E-04	8.57E-05	1.04E-02	4.65E-04	8.31E-05	1.11E-02	4.55E-04
14	SOI14	301	all 0	P	9.93E-06	2.24E-04	3.57E-04	9.48E-05	1.05E-02	5.83E-04	9.23E-05	1.12E-02	5.74E-04
anneal	SOI14	annealing	all 0	P	4.75E-06	5.81E-05	1.22E-04	8.60E-05	1.02E-02	1.83E-04	8.32E-05	1.09E-02	1.80E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI14	0	checkerboard	P	1.75E-06	3.23E-06	2.04E-06	8.08E-04	1.16E-02	2.03E-06	8.02E-04	1.15E-02	1.93E-06
7	SOI14	12	checkerboard	P	2.26E-06	3.82E-06	3.10E-06	8.01E-04	1.23E-02	3.67E-06	7.94E-04	1.23E-02	3.58E-06
8	SOI14	61	checkerboard	P	1.64E-05	5.89E-06	1.53E-05	8.49E-04	1.26E-02	3.18E-05	8.37E-04	1.28E-02	2.20E-05
9	SOI14	90	checkerboard	P	2.01E-05	5.70E-06	1.69E-05	8.62E-04	1.23E-02	3.59E-05	8.58E-04	1.24E-02	2.40E-05
10	SOI14	126	checkerboard	P	2.84E-05	3.51E-05	1.99E-04	8.87E-04	1.23E-02	4.45E-04	8.86E-04	1.24E-02	2.89E-04
11	SOI14	167	checkerboard	P	3.46E-05	4.58E-05	2.05E-04	9.00E-04	1.22E-02	4.49E-04	9.03E-04	1.23E-02	2.90E-04
12	SOI14	211	checkerboard	P	4.82E-05	1.63E-04	4.86E-04	9.30E-04	1.23E-02	1.05E-03	9.30E-04	1.23E-02	6.80E-04
13	SOI14	273	checkerboard	P	6.11E-05	1.83E-04	3.69E-04	9.55E-04	1.23E-02	7.89E-04	9.51E-04	1.23E-02	5.09E-04
14	SOI14	301	checkerboard	P	7.16E-05	2.76E-04	4.68E-04	9.81E-04	1.24E-02	1.01E-03	9.74E-04	1.24E-02	6.47E-04
anneal	SOI14	annealing	checkerboard	P	5.62E-05	7.01E-05	1.53E-04	9.53E-04	1.20E-02	3.00E-04	9.49E-04	1.20E-02	2.00E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI14	0	rev checkerboard	P	1.75E-06	2.42E-06	5.02E-06	8.36E-04	1.15E-02	5.21E-06	8.34E-04	1.14E-02	5.24E-06
7	SOI14	12	rev checkerboard	P	2.31E-06	3.29E-06	5.02E-06	8.10E-04	1.23E-02	5.45E-06	7.99E-04	1.23E-02	5.50E-06
8	SOI14	61	rev checkerboard	P	1.62E-05	3.50E-06	1.52E-05	8.50E-04	1.26E-02	3.24E-05	8.38E-04	1.28E-02	2.18E-05
9	SOI14	90	rev checkerboard	P	1.86E-05	3.72E-06	1.55E-05	8.63E-04	1.23E-02	3.58E-05	8.59E-04	1.24E-02	2.36E-05
10	SOI14	126	rev checkerboard	P	2.65E-05	3.04E-05	2.08E-04	8.88E-04	1.23E-02	4.64E-04	8.86E-04	1.23E-02	3.01E-04
11	SOI14	167	rev checkerboard	P	3.19E-05	4.13E-05	2.12E-04	9.01E-04	1.22E-02	4.66E-04	9.03E-04	1.23E-02	2.99E-04
12	SOI14	211	rev checkerboard	P	4.38E-05	1.58E-04	5.12E-04	9.31E-04	1.23E-02	1.08E-03	9.30E-04	1.23E-02	6.95E-04
13	SOI14	273	rev checkerboard	P	5.67E-05	1.82E-04	3.89E-04	9.55E-04	1.23E-02	8.08E-04	9.52E-04	1.23E-02	5.22E-04
14	SOI14	301	rev checkerboard	P	6.90E-05	2.82E-04	4.99E-04	9.82E-04	1.24E-02	1.03E-03	9.75E-04	1.24E-02	6.59E-04
anneal	SOI14	annealing	rev checkerboard	P	5.58E-05	6.82E-05	1.56E-04	9.54E-04	1.19E-02	2.98E-04	9.50E-04	1.20E-02	2.00E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI14	0	all 1	P	1.78E-06	2.64E-06	5.18E-06	4.93E-06	1.09E-02	5.17E-06	5.00E-06	1.16E-02	5.09E-06
7	SOI14	12	all 1	P	2.48E-06	3.09E-06	5.53E-06	3.32E-06	1.25E-02	5.20E-06	2.96E-06	1.36E-02	5.40E-06
8	SOI14	61	all 1	P	1.65E-06	4.06E-06	1.89E-05	1.43E-06	1.30E-02	4.31E-05	2.39E-06	1.45E-02	2.29E-05
9	SOI14	90	all 1	P	1.88E-06	3.95E-06	2.11E-05	1.89E-06	1.25E-02	5.01E-05	3.41E-06	1.36E-02	2.54E-05
10	SOI14	126	all 1	P	3.19E-06	4.01E-05	2.59E-04	3.50E-06	1.25E-02	6.17E-04	5.88E-06	1.36E-02	3.15E-04
11	SOI14	167	all 1	P	4.45E-06	5.55E-05	2.66E-04	6.22E-06	1.23E-02	6.25E-04	8.71E-06	1.35E-02	3.14E-04
12	SOI14	211	all 1	P	1.25E-05	2.06E-04	6.22E-04	1.88E-05	1.25E-02	1.39E-03	1.93E-05	1.36E-02	7.12E-04
13	SOI14	273	all 1	P	2.19E-05	2.36E-04	4.61E-04	3.61E-05	1.25E-02	1.04E-03	3.13E-05	1.35E-02	5.23E-04
14	SOI14	301	all 1	P	3.37E-05	3.60E-04	5.85E-04	5.82E-05	1.26E-02	1.30E-03	4.59E-05	1.36E-02	6.54E-04
anneal	SOI14	annealing*	all 1	P	1.60E-05	8.94E-05	1.89E-04	2.77E-05	1.19E-02	3.85E-04	2.34E-05	1.30E-02	2.04E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI15	0	all 0	P	1.93E-06	3.07E-07	3.57E-06	5.47E-05	1.02E-02	3.42E-06	5.29E-05	1.08E-02	2.97E-06
7	SOI15	12	all 0	P	2.32E-06	7.19E-07	4.07E-06	5.56E-05	1.02E-02	4.13E-06	5.34E-05	1.08E-02	3.70E-06
8	SOI15	61	all 0	P	1.09E-06	1.15E-05	2.34E-05	5.30E-05	1.05E-02	2.65E-05	5.13E-05	1.12E-02	2.60E-05
9	SOI15	90	all 0	P	1.41E-06	5.98E-06	2.51E-05	5.60E-05	1.04E-02	2.95E-05	5.44E-05	1.11E-02	2.93E-05
10	SOI15	126	all 0	P	1.03E-06	6.84E-05	2.24E-04	5.81E-05	1.05E-02	2.75E-04	5.63E-05	1.12E-02	2.71E-04
11	SOI15	167	all 0	P	1.74E-06	7.50E-05	2.33E-04	6.04E-05	1.04E-02	2.86E-04	5.86E-05	1.11E-02	2.82E-04
12	SOI15	211	all 0	P	6.15E-06	2.30E-04	5.11E-04	6.94E-05	1.04E-02	6.23E-04	6.75E-05	1.12E-02	6.18E-04
13	SOI15	273	all 0	P	1.80E-05	2.57E-04	4.16E-04	8.45E-05	1.04E-02	5.04E-04	8.24E-05	1.11E-02	5.00E-04
14	SOI15	301	all 0	P	3.41E-05	3.87E-04	5.25E-04	1.06E-04	1.05E-02	6.33E-04	1.04E-04	1.12E-02	6.27E-04
anneal	SOI15	annealing	all 0	P	1.26E-05	1.37E-04	2.17E-04	7.90E-05	1.02E-02	2.56E-04	7.67E-05	1.09E-02	2.53E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI15	0	checkerboard	P	1.36E-06	6.10E-08	3.65E-06	7.80E-04	1.22E-02	3.55E-06	7.84E-04	1.23E-02	3.44E-06
7	SOI15	12	checkerboard	P	1.94E-06	5.70E-07	4.57E-06	7.79E-04	1.21E-02	4.85E-06	7.79E-04	1.21E-02	4.87E-06
8	SOI15	61	checkerboard	P	3.24E-06	1.32E-05	2.93E-05	7.91E-04	1.27E-02	4.37E-05	7.86E-04	1.29E-02	2.79E-05
9	SOI15	90	checkerboard	P	8.27E-06	7.38E-06	3.20E-05	8.05E-04	1.26E-02	4.86E-05	7.96E-04	1.26E-02	3.12E-05
10	SOI15	126	checkerboard	P	1.51E-05	9.15E-05	3.01E-04	8.31E-04	1.27E-02	4.95E-04	8.19E-04	1.27E-02	2.85E-04
11	SOI15	167	checkerboard	P	2.16E-05	1.03E-04	3.13E-04	8.47E-04	1.26E-02	5.16E-04	8.33E-04	1.25E-02	2.96E-04
12	SOI15	211	checkerboard	P	3.71E-05	3.10E-04	6.84E-04	8.88E-04	1.28E-02	1.14E-03	8.64E-04	1.26E-02	6.46E-04
13	SOI15	273	checkerboard	P	6.09E-05	3.49E-04	5.48E-04	9.37E-04	1.28E-02	9.25E-04	8.96E-04	1.25E-02	5.24E-04
14	SOI15	301	checkerboard	P	8.92E-05	5.17E-04	6.86E-04	9.95E-04	1.30E-02	1.17E-03	9.34E-04	1.26E-02	6.56E-04
anneal	SOI15	annealing	checkerboard	P	5.42E-05	1.80E-04	2.70E-04	9.28E-04	1.24E-02	4.37E-04	8.93E-04	1.22E-02	2.65E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI15	0	rev checkerboard	P	1.46E-06	1.06E-07	7.65E-06	7.84E-04	1.22E-02	7.51E-06	7.86E-04	1.23E-02	7.62E-06
7	SOI15	12	rev checkerboard	P	2.20E-06	5.98E-07	1.01E-05	7.81E-04	1.21E-02	1.06E-05	7.80E-04	1.21E-02	1.04E-05
8	SOI15	61	rev checkerboard	P	4.02E-06	1.18E-05	3.77E-05	7.91E-04	1.27E-02	5.24E-05	7.86E-04	1.29E-02	3.60E-05
9	SOI15	90	rev checkerboard	P	8.54E-06	6.68E-06	3.84E-05	8.06E-04	1.26E-02	5.66E-05	7.97E-04	1.26E-02	3.80E-05
10	SOI15	126	rev checkerboard	P	1.61E-05	8.51E-05	3.18E-04	8.32E-04	1.27E-02	5.26E-04	8.20E-04	1.27E-02	3.05E-04
11	SOI15	167	rev checkerboard	P	2.20E-05	9.85E-05	3.31E-04	8.47E-04	1.26E-02	5.42E-04	8.33E-04	1.25E-02	3.14E-04
12	SOI15	211	rev checkerboard	P	4.07E-05	3.20E-04	7.54E-04	8.89E-04	1.28E-02	1.19E-03	8.66E-04	1.26E-02	6.77E-04
13	SOI15	273	rev checkerboard	P	6.82E-05	3.78E-04	6.19E-04	9.37E-04	1.28E-02	9.59E-04	8.97E-04	1.25E-02	5.46E-04
14	SOI15	301	rev checkerboard	P	1.03E-04	5.81E-04	7.88E-04	9.95E-04	1.30E-02	1.20E-03	9.34E-04	1.26E-02	6.78E-04
anneal	SOI15	annealing	rev checkerboard	P	6.35E-05	2.04E-04	3.09E-04	9.28E-04	1.24E-02	4.44E-04	8.93E-04	1.22E-02	2.73E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI15	0	all 1	P	1.90E-06	3.99E-07	7.99E-06	1.93E-06	1.28E-02	8.00E-06	1.86E-06	1.41E-02	8.06E-06
7	SOI15	12	all 1	P	2.23E-06	5.13E-07	1.11E-05	2.31E-06	1.26E-02	1.12E-05	2.17E-06	1.37E-02	1.09E-05
8	SOI15	61	all 1	P	1.28E-06	1.50E-05	4.60E-05	1.35E-06	1.32E-02	7.42E-05	1.38E-06	1.47E-02	3.60E-05
9	SOI15	90	all 1	P	1.78E-06	9.50E-06	4.88E-05	1.87E-06	1.31E-02	8.14E-05	2.14E-06	1.43E-02	3.87E-05
10	SOI15	126	all 1	P	2.84E-06	1.19E-04	4.12E-04	4.42E-06	1.34E-02	7.65E-04	3.90E-06	1.45E-02	3.04E-04
11	SOI15	167	all 1	P	5.75E-06	1.38E-04	4.24E-04	9.27E-06	1.33E-02	7.91E-04	6.92E-06	1.41E-02	3.13E-04
12	SOI15	211	all 1	P	2.27E-05	4.28E-04	9.32E-04	3.98E-05	1.37E-02	1.70E-03	2.14E-05	1.41E-02	6.68E-04
13	SOI15	273	all 1	P	5.20E-05	5.02E-04	7.49E-04	9.34E-05	1.37E-02	1.35E-03	4.53E-05	1.39E-02	5.36E-04
14	SOI15	301	all 1	P	9.41E-05	7.53E-04	9.42E-04	1.66E-04	1.41E-02	1.70E-03	7.87E-05	1.40E-02	6.69E-04
anneal	SOI15	annealing*	all 1	P	3.99E-05	2.60E-04	3.59E-04	7.51E-05	1.30E-02	6.15E-04	3.27E-05	1.34E-02	2.72E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI16	0	all 0	P	2.03E-06	5.16E-06	4.14E-06	5.81E-05	1.04E-02	3.70E-06	5.59E-05	1.10E-02	3.39E-06
7	SOI16	12	all 0	P	2.39E-06	4.84E-06	4.71E-06	5.96E-05	1.01E-02	4.38E-06	5.74E-05	1.07E-02	4.37E-06
8	SOI16	61	all 0	P	1.08E-06	1.36E-05	2.20E-05	5.71E-05	1.05E-02	2.52E-05	5.55E-05	1.11E-02	2.49E-05
9	SOI16	90	all 0	P	9.39E-07	8.13E-06	2.32E-05	5.97E-05	1.04E-02	2.71E-05	5.82E-05	1.10E-02	2.69E-05
10	SOI16	126	all 0	P	1.86E-06	5.70E-05	1.93E-04	6.24E-05	1.05E-02	2.44E-04	6.00E-05	1.12E-02	2.38E-04
11	SOI16	167	all 0	P	1.81E-06	6.19E-05	1.97E-04	6.48E-05	1.04E-02	2.55E-04	6.27E-05	1.11E-02	2.50E-04
12	SOI16	211	all 0	P	7.79E-06	1.90E-04	4.27E-04	7.59E-05	1.05E-02	5.66E-04	7.37E-05	1.12E-02	5.54E-04
13	SOI16	273	all 0	P	1.94E-05	2.17E-04	3.57E-04	9.34E-05	1.05E-02	4.72E-04	9.09E-05	1.12E-02	4.64E-04
14	SOI16	301	all 0	P	3.62E-05	3.28E-04	4.51E-04	1.20E-04	1.06E-02	5.98E-04	1.17E-04	1.13E-02	5.86E-04
anneal	SOI16	annealing	all 0	P	1.21E-05	1.20E-04	1.94E-04	8.51E-05	1.03E-02	2.49E-04	8.25E-05	1.10E-02	2.44E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI16	0	checkerboard	P	1.46E-06	4.91E-06	3.67E-06	7.83E-04	1.25E-02	3.67E-06	7.93E-04	1.26E-02	3.51E-06
7	SOI16	12	checkerboard	P	1.80E-06	4.68E-06	4.57E-06	7.81E-04	1.20E-02	4.62E-06	7.84E-04	1.20E-02	4.76E-06
8	SOI16	61	checkerboard	P	1.35E-06	1.48E-05	2.53E-05	7.85E-04	1.27E-02	3.50E-05	7.85E-04	1.28E-02	2.91E-05
9	SOI16	90	checkerboard	P	2.69E-06	8.77E-06	2.73E-05	7.92E-04	1.25E-02	3.92E-05	7.89E-04	1.26E-02	3.32E-05
10	SOI16	126	checkerboard	P	6.78E-06	6.83E-05	2.37E-04	8.12E-04	1.27E-02	3.85E-04	8.09E-04	1.28E-02	2.93E-04
11	SOI16	167	checkerboard	P	1.08E-05	7.67E-05	2.47E-04	8.27E-04	1.26E-02	4.10E-04	8.22E-04	1.26E-02	3.09E-04
12	SOI16	211	checkerboard	P	2.54E-05	2.39E-04	5.44E-04	8.69E-04	1.28E-02	9.38E-04	8.58E-04	1.28E-02	6.80E-04
13	SOI16	273	checkerboard	P	4.93E-05	2.77E-04	4.50E-04	9.20E-04	1.28E-02	7.85E-04	8.99E-04	1.27E-02	5.61E-04
14	SOI16	301	checkerboard	P	8.00E-05	4.17E-04	5.67E-04	9.85E-04	1.30E-02	1.00E-03	9.45E-04	1.28E-02	7.02E-04
anneal	SOI16	annealing	checkerboard	P	4.11E-05	1.55E-04	2.39E-04	9.06E-04	1.24E-02	3.85E-04	8.91E-04	1.23E-02	2.94E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI16	0	rev checkerboard	P	1.64E-06	5.27E-06	2.37E-06	7.85E-04	1.25E-02	2.33E-06	7.94E-04	1.26E-02	2.34E-06
7	SOI16	12	rev checkerboard	P	2.05E-06	4.95E-06	3.44E-06	7.83E-04	1.20E-02	3.62E-06	7.85E-04	1.20E-02	3.83E-06
8	SOI16	61	rev checkerboard	P	1.92E-06	1.49E-05	2.71E-05	7.86E-04	1.27E-02	3.52E-05	7.86E-04	1.28E-02	2.91E-05
9	SOI16	90	rev checkerboard	P	3.37E-06	9.13E-06	2.89E-05	7.92E-04	1.25E-02	3.99E-05	7.90E-04	1.26E-02	3.36E-05
10	SOI16	126	rev checkerboard	P	7.20E-06	7.06E-05	2.65E-04	8.12E-04	1.27E-02	3.99E-04	8.09E-04	1.28E-02	3.03E-04
11	SOI16	167	rev checkerboard	P	1.19E-05	8.19E-05	2.76E-04	8.27E-04	1.26E-02	4.24E-04	8.23E-04	1.26E-02	3.19E-04
12	SOI16	211	rev checkerboard	P	2.81E-05	2.67E-04	6.19E-04	8.69E-04	1.28E-02	9.56E-04	8.59E-04	1.28E-02	6.96E-04
13	SOI16	273	rev checkerboard	P	5.54E-05	3.19E-04	5.16E-04	9.22E-04	1.28E-02	7.98E-04	8.97E-04	1.27E-02	5.71E-04
14	SOI16	301	rev checkerboard	P	9.11E-05	4.91E-04	6.57E-04	9.85E-04	1.30E-02	1.02E-03	9.45E-04	1.28E-02	7.17E-04
anneal	SOI16	annealing	rev checkerboard	P	4.50E-05	1.65E-04	2.55E-04	9.08E-04	1.24E-02	3.85E-04	8.90E-04	1.23E-02	2.95E-04

Run	DeviceID	Dose (krad-Si)	Test pattern	Functional	Idd (A)	Idd2 (A)	IddCore (A)	Idd_W (A)	Idd2_W (A)	IddCore_W (A)	Idd_R (A)	Idd2_R (A)	IddCore_R (A)
6b	SOI16	0	all 1	P	1.80E-06	5.19E-06	2.92E-06	2.01E-06	1.32E-02	2.80E-06	1.89E-06	1.47E-02	3.08E-06
7	SOI16	12	all 1	P	2.51E-06	5.06E-06	3.83E-06	2.26E-06	1.24E-02	3.76E-06	2.23E-06	1.35E-02	3.58E-06
8	SOI16	61	all 1	P	1.39E-06	1.80E-05	3.35E-05	1.14E-06	1.32E-02	5.18E-05	1.31E-06	1.47E-02	3.30E-05
9	SOI16	90	all 1	P	1.73E-06	1.11E-05	3.65E-05	1.64E-06	1.31E-02	5.82E-05	1.99E-06	1.45E-02	3.95E-05
10	SOI16	126	all 1	P	2.08E-06	9.25E-05	3.28E-04	3.49E-06	1.34E-02	5.78E-04	3.07E-06	1.47E-02	3.47E-04
11	SOI16	167	all 1	P	4.96E-06	1.09E-04	3.40E-04	8.19E-06	1.33E-02	6.09E-04	6.38E-06	1.44E-02	3.66E-04
12	SOI16	211	all 1	P	2.21E-05	3.48E-04	7.55E-04	4.07E-05	1.37E-02	1.35E-03	2.79E-05	1.46E-02	7.93E-04
13	SOI16	273	all 1	P	5.57E-05	4.17E-04	6.20E-04	1.03E-04	1.37E-02	1.11E-03	6.74E-05	1.45E-02	6.46E-04
14	SOI16	301	all 1	P	1.02E-04	6.31E-04	7.80E-04	1.85E-04	1.40E-02	1.38E-03	1.14E-04	1.46E-02	7.98E-04
anneal	SOI16	annealing*	all 1	P	3.97E-05	2.25E-04	3.13E-04	7.61E-05	1.30E-02	5.28E-04	5.35E-05	1.39E-02	3.49E-04